-MILITARY SPECIFICATION -

'CONTROL, REMOTE, M71
LAND MINE SYSTEM

This specification is approved for use within U.S. Army Armaments Munitions and Chemical Command, and is available for use by all Departments and Agencies of the Department of Defense.

1. SCOPE

1.1 Scope. This specification establishes the Quality Assurance provisions for the manufacture, inspection, test and packaging of the Remote Control Unit (Rcu).

2. APPLICABLE DOCUMENTS

2.1 Government documents.

2.1.1 specifications and standards. Unless otherwise specified, the following specifications and standards of issue listed in that issue of the Department of Defense Index of Specifications and Standards (DoDISS) specified in the solicitation form part of this specification to the extent 'specified herein.

SPECIFICATIONS

MILITARY

MIL-C-816   –   Capacitors, Variable, *ceramic, Diel* Styles CV35 and CV36.

MIL-C-3098   Crystal Units, Quartz, General Specification for

Beneficial comments (recommendations, additions, deletions) and any pertinent data which may be of use in improving this document should be addressed to: Commander, U.S. Army Armament, Munitions and Chemical Command, Attn: AMSMC-QA, Dover, New Jersey 07801-5001 by using the self-addressed Standardization Document Improvement Proposal (DD Form 1426) appearing at the end of this document or by letter.

AMSC N/A   FSC 1290
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MIL-R-5757   ~.-   Relays, Electromagnetic, G e n e r a l
Specification for

MIL-S-19500   -   Semiconductor Device, General Specification
For.

MIL-S-19500/116 -   Semiconductor Device, Diode, Silicon,
Switching Types 1N914, 1N4148, 1N4531
TX1N914, TX1N4148, and TX1N4531.

MIL-S-19500/255 -   Semiconductor Device, Transistor NPN
Silicon, Switching Types 2N2221, 2N92
2N2222, and 2N2222A, Jan, Jantx, Jantxv
and Jans.   221A.

MIL-S-19500/2i3 -   Semiconductor Device, Transistor, PNP
Silicon, Switching Types 2N69Aa and
24453, Jan, Jantx, and Jantxv,

MIL-S-19500/290 -   Semiconductor device, Transistor, PNP
Silicon Switching Types 2N2904, 2N2904A,
2N2905, and 2N2905A, Jan, Jantx, Jantxv,
and Jans.

MIL-S-19500/291 -   Semiconductor Device, Transistor, PSNP
Silicon Switching Types 2N2906, 2N2906A,
2N2907, and 2N2907A, Jan, Jantx, Jantxv,
and Jans.

MIL-s-19500/317 -   Semiconductor Device, Transistor, NPN,
Silicon Switching Types 2N2369A, 2N3227,
2N4449, Jan, Jantx and Jans.

MIL-S-19500/356 -   Semiconductor Device, Diode, Silicon,
Voltage Regulator Types 1N4954 through
1N4996, 1N5968 and 1N5969 Jan, Jantx
Jantxv , and Jans

MIL-S-19500/427 -   Semiconductor Device, Diode, Silicon,
Power Rectifier, Types 1N5614, 1N5618,
1N5620, 1N5622, Jan, Jantx, Jantxv and
Jans .

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MIL-s-19500/437 - semiconductor Device, Diode, silicon, Low Noise Voltage- Regulator 1N5518B thru 1N5546B and TX1N5518B thru TX1N5546B.

MIL-s-19500/441 - Semiconductor Device, Transistor, PNP Silicon, Power Types 2N3740, 2N3741, **Nontx, Tx and Txv.**

MIL-s-19500/444 - **Semiconductor Device, Diode, Silicon, Switching Types lN5711, TX1N5711.**

MIL-s-19500/445 - **Semiconductor Device, Diode, silicon, Switching Types 1N5712, TX1N5712.**

M1L-M-38510 - **Microcircuits, General Specification For.**

MIL-M-38510/12 - **Microcircuits, Digital, TTL, Monostable, Multvibrators, Monolithic Silicon.**

MIL-M-38510/173 - **Microcircuits, Digital, CMOS Decoders, Encoder, and Decoders/Demultiplexers, Monolithic Silicon, positive Logic.**

MIL-M-38510/300 - **Microcircuits, Digital, Low Power Schottky TTL , Nand Gates, Monolithic Silicon.**

MIL-c-39001/5 - **Capacitor, Fixed, Mica Dielectric, Established Reliability Styles CMR04 to 08.**

MIL-c-39003/l - **Capacitor, Fixed, Electrolytic (Solid Electrolyte), Tantalum, (polarized, Sintered Slug), Established Reliability, Style CSR 13.**

MIL-C-39006/9 - **Capacitor, Fixed, Electrolytic (Nonsolid Electrolyte), Tantalum, (Polarized, Sintered Slug), 85 Degrees C (Voltage Derated to 125 Degrees C), Established Reliability, Style CIR65.**

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MIL-R-39007/8 -	Resistor, Fixed,- Wire-Wound (Power-Type) Established Reliability Style RwR80.
MIL-R-39008/l -	Resistor, Fixed, Composition (Insulated), Established Reliability, Style RCR07,
MIL-R-39008/2	Resistor, Fixed, Composition (Insulated), Established Reliability, Style RCR20.
MIL-R-39008/3	Resistor, Fixed, Composition (Insulated), Established Reliability, Style RCR32.
MIL-R-39008/5	Resistor, Fixed, Composition (Insulated), Established Reliability, Style RCR42.
MIL-C-39014/1	Capacitor, Fixed, Ceramic Dielectric, (General Purpose), Established Reliability, Style CKR05.
MIL-C-39014/2	Capacitor, Fixed, Ceramic Dielectric, (General Purpose), Established Reliability Style CKR06.
MIL-C-39014/22	Capacitor, Fixed, Ceramic Dielectric. (General Purpose), Established Reliability Style CKR22, CKR23, and CKR24.
MIL-C-39016/9	Relay, Electromagnetic, Established Reliability, DPDS; Low Level to 1.0 Ampere.
MIL-R-39017/l	Resistor, Fixed, Film (Insulated) Established Reliability, Style RLR07.
MIL-S-46844	Solder Bath Soldering of Printed Wiring Assemblies
MIL-S-45743	Soldering, Manual Type, High Reliability, Electrical and Electronic Equipment
MIL-A-48078	Ammunition, Standard Quality Assurance Provisions, General Specification for
MIL-C-48655	Core, Toroid .

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MIL-P-35149	-	Post, Bindin-gi..RleCtriCal (Insulated and Uninsulated) , 'General Specification for
MIL-O-55310	-	Oscillators, Crystal General Specification for
MIL-C-55681	-	Capacitors, Chip, Multiple Layer, Fixed, Unencapsulated, Ceramic Dielectric, Established Reliability, General Specification for
MIL-C-55681/5	-	Capacitor, Chip, Multiple Layer, Fixed unencapsulated, Ceramic, Dielectric, Established Reliability, Styles CDR21 to CDR25 (High Frequency).
MIL-R-83401/2	-	Resistor Networks, Fixed, Film, style RZ020, 16 Pin Dip.

STANDARDS

MILITARY

MIL-STD-105	-	Sampling Procedures and Tables for Inspection by Attributes
MIL-STD-202	-	Test Methods for Electronic and Electrical Component Parts.
MIL-STD-331	-	Fuze and Fuze Components, Environmental and Performance Test For
MIL-STD-454	-	Standard General Requirement for Electronic Equipment
MIL-STD-750	-	Test Methods for Semiconductor Devices
MIL-sTD-883	-	Test Methods and Procedures for Micro-electronics
MIL-STD-1169	-	Packaging, Packing and Marking for Shipment of Inert Ammunition Components
DOD-STD-1686	-	Electrostatic Discharge Control Program for Protection of Electrical and Electronic Parts, Assemblies and

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Equipment

Handbooks

DOD-HD BK-263 - EDC Handbook for Protection of Electrical
and Electronics Parts, Assemblies and
Equipment.

2.1.2 Other government documents drawings and Publications. The
following government documents, drawings, and publications form a
part of this specification to the extent specified herein.

DRAWINGS

U*S. ARMAMENT RESEARCH, DEVELOPMENT AND ENGINEERING
CENTER (ARDEC)

PRODUCT AND PACKAGING DRAWINGS

9332870 - Control, Remote, Land Mine M71

CODE OF FEDERAL REGULATION

Title 49 - Transportation, Parts 100-199

. (Copies of specifications, standards, drawings and publications
required by manufacturers in connection with specific acquisition
functions should be obtained for the contracting activity or as
directed by the Contracting Officer).

2.2 Order of precedence. In the event of a conflict between the
text of this specification and the references cited herein, the text
of this specification shall take precedence.

3. REQUIREMENTS

3.1 Materials. Materials shall be in accordance with the ___
applicable drawings, specification and, standards.

3.2 Components and assemblies. The components and assemblies
shall comply with -all requirements specified on Drawing 9332870 and
associated drawings and with all requirements specified in applicable
specifications and standards.

3.3 Physical characteristics.

3.3.1 Envelope and dimensions. The envelope and dimensions of
the Remote Control Unit shall conform to the requirements of Drawing
9332870.

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3.4 Environmental conditions.

3.4.1 Transportation vibration. The electronics assembly shall show no evidence of internal or external damage that will affect the intended functions following Transportation Vibration Test No. 119, Procedure 2 of MIL-STD-331.

3.4.2 Temperature range. The Remote Control Unit shall perform as required herein and in Drawing 933026 over the temperature range, after one (1) hour conditioning at temperature.

    a. **Cold -35 (+0/-5)** degrees F

    b. Hot **+145 (+5) degrees F**

    c. Ambient 70 (+10/-10) degrees F

3.4.3 Shock. The electronic assembly shall perform as required after impact environments that provide mechanical shock of TBD G's peak **wit** a duration of TBD ms minimum, **TBD ms maximum.**

3.5 Soldering. All soldered electrical connections shall comply with MIL-S-46844, and MIL-S-45743.

3.5.1 Solderability Electronic assembly parts **that are to be soldered shall comply with the solderability requirements of MIL-S-45743 or as otherwise specified.**

3.6 Remote Control Unit Performance characteristics . This section describes the performance characteristics of the Remote Control Unit (RCU), assembly number 9332873.

3.6.1 RCU power off current. With the voltage at Pi-RED (+14.4 VDC) with respect to P1-BLK (COMMON) set to 13 + 0.5 volts (Nominal Battery Voltage), the unit power Switch off, the current flowing into Pi-RED shall be 2.0 milliamperes maximum when tested per 4.5.2.1

3.6.2 RCU standby current . With the voltage (Pi-RED with respect to P1-BLK) set to 13 + 0.5 volts, the unit power switch on and displays blank, the current flowing into PI-RED shall be 100 milliamperes maximum when tested per 4.5.2.2

3.6.3 Keyboard lights. All the keyboard keys shall be backlit when the unit power switch is on when tested per 4.5.2.3

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3.6.4 <ins>-Low "battery voltage</ins>. The RCU shall flash the "BAT LOW" LED when the battery voltage is at or below the low voltage threshold. The low voltage -threshold shall be 11.0 volts max. and 10.3 volts minimum when tested per 4.5.2.24

3.6.5 <ins>-RGU transmitting current</ins>. With the battery voltage (Pl-RED with respect to P1-BLK) set to 13 + 0.5 volts and the RCU transmitting into a 50 +5% ohm resistive load, the current flowing into PI-RED shall be 2.6 amperes maximum when tested per 4,5.2.25

3.6.6 <ins>Transmitting Power</ins>. With a battery voltage of $13 + 0.1$ its, the RF-Power -into a 50 + 5% ohm resistive load at the ANTENNA, while transmitting, shall be 10 watts minimum when tested per 4.5.2.26

3.6.7 <ins>Tuning (load matching) capability.</ins> The RCU shall produce 10 watts minimum into the 50 ohm real component of each of the complex loads listed in the table below with a battery voltage of 13 + 0.1 volts when tested per 4.5.2.27

LOAD	LOAD)_IMPllDANCE
A	50 - j169
B	50 + j152
c	83 + j88
D	316- j169
E	79 + j183

3.6.8 <ins>Transmitter cutoff voltage</ins>. The RCU shall not transmit an RF signal when the battery voltage is at or below the cutoff threshold of 10 + 0.5 volts when tested per 4.5.2.28

3.6.9 <ins>Data retention time</ins>. Data stored in the RCU memory shall be retained for at least 5 minutes with the battery disconnected from the unit when tested per 4.5.2.29

3.6.10 <ins>Initial Power app lication</ins>. When battery power is first applied or until a valid STORE code has been established, the RCU shall display INVALID with the STORE code select switch is off when tested per 4.5.2.4

3.6.11 <ins>STORE code entry mode</ins>. The RCU allows a five digit STORE code to be entered via the front panel keyboard where STORE code digits are chosen from the set of integers 1 thru 8 inclusive. Turn the store code select switch on, turn the power switch on and then turn the store code switch off. The RCU shall display five dashes (-----) as the STORE CODE prompt. Key in the five digit STORE code. The RCU shall display the "key-in" digits when tested per 4.5.2.5, then turn the unit power switch off.

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3.6.12 STORE mode.

3.6.12.1 Power on prompt. When a valid STORE code has been established and the store code select switch is off, the RCU shall display "ON", after the unit power switch is turned on when tested per 4.5.2.6. .

3.6.12.2 Invalid STORE code entry. The RCU shall display "Invalid" 16 + 1.0 seconds after the unit power switch is turned on if an incorrect or incomplete STORE code or no entry is keyed in on the keyboard within the first 15 seconds after the unit power switch has been turned on when tested per 4,5.2.7

3 .6.12.3 No Previous SEND code selected. The RCU shall display four dashes (----) 16 + 1.0 seconds after the unit power switch is turned on if a SEND code has not been previously selected and the correct STORE code has been keyed in within the first 15 seconds after the unit power switch has been turned on when tested per 4.5.2.8

3.6.13 SEND code selection. The RCU permits a four digit SEND code to be selected, from pseudo-randomly generated candidate codes, via the front panel keyboard. The RCU shall display "AUTO" when the AUTO key is pressed and the RCU is in the STORE mode; then the RCU shall display a four digit SEND code when the TRANSFER key is pressed sequentially following the AUTO key when tested per 4.5.2.10. Repeating this sequence will select a different SEND code.

3.6 .13.1 Previous SEND code selected. The RCU shall display the previously selected SEND code 16 + 1.0 seconds after the unit power switch is turned on if a SEND code has been previously selected and the correct STORE code has been keyed in within the first 15 seconds after the unit power switch has been turned on when tested per 4.5.2.11

3.6.14 Transfer capability. The RCU shall have the capability of transferring the Remote Copy Data (RCD) code from RCU to RCU via the Magnetic Coupling Device (MCD) coil. The receiving and transferring of data is accomplished when both RCUS are in the STORE mode, and the MCD transfer coils are aligned.

3.6.14.1 RCD code transfer.

3.6.14.1.1 Transfer output prompt. The RCU shall display "COPY[a] when the COPY key is pressed and the RCU is in the STORE mode when tested per 4.5.2.12.

3.6.14.1.2 Data sending display. When the TRANSFER key is pressed sequentially following the COPY key while in the STORE mode, the RCU shall display "SENDING" when tested per 4.5.2.12

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3.6.14.1.3 <u>Data output sequence</u>. When the load of Figure la is placed on the RCU MCD coil as specified, an RCD pulse sequence shall be generated at the output of the load as specified in Figure 2 in response to a COPY command when tested per 4.5.2.12

3.6.14.1.4 <u>Data output completion display</u>. When the RCU has completed transmission of the RCD pattern over the MCD coil, the RCU shall display the four digit SEND code associated with that pattern as specified by Drawing 9333026 when tested per 4.5.2.12

3 .6.14.2 <u>RCD code receive</u>.

3,.6.14.2.1 <u>Receive input Prompt</u>. When the RCU is in the STORE mode and the MCD coil is driven as specified by Figure 3a the RCU shall display ",RECEIVE" when tested per 4.5.2.13

3.6.14.2.2 <u>Receive input acceptance</u>. When the TRANSFER key is pressed while the RCU displays "RECEIVE", the RCU shall display the four digit SEND code associated with the-RCD pattern of Figure 3 as specified by Drawing 9333026 when tested per 4.5.2.13

3.6.15 <u>SEND mode</u>.

3 .6.15.1 <u>Initial group status display</u>. 1f a SEND code has been previously selected and correctly keyed in within the first 15 seconds after the unit power switch has been turned on, the RCU shall display "n CMD", where n is the GROUP ID (set to 1 on entering the SEND mode) and CMD is one of: NONE, TRANSFER, DEPLOY, RESET SD, or DESTRUCT when tested per 4.5.2.15

3.6.15.2 <u>Invalid SEND code entry</u>. The RCU shall display INVALID" 16 + 1.0 seconds after the unit power switch is turned on if an incorrect or incomplete SEND code or no entry is keyed in on the keyboard within the first 15 seconds after the unit power switch is turned on when tested per 4.5.2.14

3.6.16 <u>Display timeout</u>. The RCU shall blank the display in the SEND or STORE mode after 10 + 1.0 seconds of keyboard inactivity when tested per 4.5.2.9

3.6.17 <u>Group selection</u>. The RCU shall provide the capability to control up to 15 addressed groups. Control shall be exercised on each group individually or on all 15 groups simultaneously. Group selection is made while in the SEND mode. Pressing the GROUP ID key shall increment the current GROUP ID number of the RCU by one. GROUP ID's will be the numbers 1 thru 15 and ALL when tested per 4.5.2.17

3.6.18 <u>Group status display</u>. The RCU maintains in memory the current status of each group and displays that status while in the SEND mode. The status format shall be "n status", where n is the GROUP ID number 1 to 15 inclusive and status is one-of: NONE, TRANSFER, DEPLOY, RESET SD, DESTRUCT and "ALL", for the GROUP ID of ALL.

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3.6.18.1 <u>Initial status</u>. After initial power application or reassigning of the SEND or STORE codes, all groups shall begin with the initial status of NONE when tested per 4.5.2.15 and 4.5.2.17.

3.6.18.2 <u>Status update sequence</u>. The group status shall be updated as specified by the state diagram of Figure 4. when tested per 4.5.2.21, 4.5.2.23, and 4.5.7.31.4

3.6.19. <u>RCU to CI transfer</u>.

3 .6.19.1 <u>Transfer display</u>. The RCU shall momentarily display "SENDING'ʻwhen the TRANSFER key has been pressed, the RCU is in the SEND mode, and the GROUP ID is not ALL when tested per 4.5.2,16.

3.6 .19.2 <u>Transfer output</u>. When the load of Figure la is placed on the RCU MCD coil as specified in that figure, an FSD pulse sequence shall be generated at the output of the load as specified in Figure 2 for the current group and RCD code in response to a TRANSFER command when tested per 4.5.2.16.

3.6.19.3 <u>Group status update</u>. When the waveform transmission has completed, the group status display shall be updated as specified by 3.6.18.2. and tested per 4.5.2.16.

3 .6.19.4 Invalid trans<u>fer Group</u>. The RCU shall display "ALL INVALID", **when the TRANSFER key is pressed, the RCU is in the SEND** mode, **and the GROUP ID is ALL when tested per 4.5.2.18.**

3.6.20 <u>RCU command transmission</u>.

3 .6.20.1 **<u>Command display</u>. The RCU shall display "DEPLOY n", "DESTRUCT n", or "RESET SD n", when the DEPLOY, DESTRUCT, or RESET SD key respectively is pressed, - where n is the current GROUP ID number and the RCU is in the SEND mode when tested per 4.5.2.19.**

3 .6.20.2 <u>Tuning sequence</u>. The RCU shall momentarily display "TUNING" when the XMIT switch is pressed sequentially after the DEPLOY, DESTRUCT, or RESET SD key and the RCU is in the SEND mode when tested per 4.5.2.19.1.

3 .6.20.3 <u>Transmit display</u>. The RCU shall display "XMIT TUNE = **m" where m is an integer from O to 9 after the RCU has-completed the tuning sequence when tested per 4.5.2.19.2.**

3 .6.20.4 <u>RF output sequence</u>. An RF **message, as** specified by Drawing 9333026 for the FSD data of the current group, shall be generated after the RCU has completed the tuning sequence when tested per 4.5.2.19.3.

3.6.20.5 Gro<u>up-status update</u>. When **the RF transmission has completed, the group status shall be updated as specified by 3.6.18.2.**

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3.7. - **Tuning Electronic Components Assembly Performance .**
characteristics This section describes t-he -performance character-
istics of the Tuning electronic components assembly (Tuner), assembly
number 9333578.

3.7.1 Reflectometer -verification. - When tested per 4.5.5.1, the
following .conditions apply unless otherwise noted; the auto tune
select-able inductors shunted (shorted) and capacitors disabled
(disconnected) , -an RF signal of -11.0 VRMS at frequency Fo (as
specified in the 9333026 drawing) having a source impedance of 50 Ohms
applied to RFIN (A1-E14) and the XFER RELAY input (AI-E16) connected
to GROUND (A1-E18).

3.7.1.1 **Reflectometer output - 50 ohm load.** **With a 50 ohm**
resistive load between RFOUT (A2-E13) and 'GROUND, the VREFL output
(A1-E17) shall be 0.15 Vdc maximum when tested per 4.5.5.1.1.

3.7.1.2 Reflectometer output .- 75 ohm load. **With a 75 ohm**
resistive load between RFOUT and GROUND, the VREFL output shall be
between 0.75 Vdc to 1.25 Vdc when tested per 4.5.5.1.2.

3.7.1.3 Reflectemeter output - no load. **With RFOUT unterm-**
inated the VREFL output shall be 4.5 Vdc minimum when tested per
4.5.5.1.3.

3.7.2 Inductor elements. **The Tuner assembly shall have the**
capability of switching four inductors between RFIN and RFOUT. **Each**
inductor shall be individually controlled by a single data bit in the
TUNE DATA pattern as shown in Figure 5. **The four inductance values and**
associated data patterns shall be as specified in Table 1 when tested
per 4.5.5.2.

TABLE 1

Pattern	Data Pattern (bits 12345678)	Inductance at 2.5Mz + 5%
A	00001000	0.75uH + 10%
B	00000100	1.5 uH + 10%
c	00000010	3.O uH + 5 %
D	00000001	6.0 uH + 5%

3.7.3 Capacitor elementS. **The Tuner assembly shall have the**
capability of switching four capacitors between the RFOUT and GROUND.
Each capacitor shall be individually controlled by a single data bit
in the TUNE DATA pattern as shown in Figure 5. The four capacitance
values and associated data patterns shall be as specified in Table 2
when tested per 4.5.5.3.

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TABLE 2

Pattern	Data Pattern (bits 12345678)	Capacitance
A	10000000	91 pF + 10 %
B	01000000	180pF + 10 %
C	00100000	360pF + 5 %
D	00010000	720pF + 5 %

3.7.4 Power handling capability. With a 50 ohm load between RFOUT and GROUND and the data pattern associated with the 50 ohm load (A) of Table 3 applied to the TUNE DATA input per Figure 5, apply an RF signal of 12 Watts at frequency Fo having a source impedance of 50 ohms to RFIN. The RF output at the 50 ohm termination shall be greater than 10 Watts (refer Table 3). The Tuner shall output an RF power level greater than the level specified in Table 3 when each of the remaining loads of Table 3 are connected between RFOUT and GROUND, the data pattern associated with each load is applied to the TUNE DATA input per Figure 5 and the above RF source is applied to RFIN. Each of the complex loads of Table 3 are comprised of a set of inductor(s) and/or capacitor(s) between the RF output and a 50 ohm resistive termination. The power output shall be measured across the 50 ohm termination when tested per 4.5.5.4.

TABLE 3

Load	Load Impedance	Data Pattern (bits 12345678)	Power Output(min.)
A	50	00000000	10 Watts
B	50	00001000	10 Watts
C	50 - j169	00001111	10 Watts
D	50 + j152	10011011	10 Watts
E	83 + j88	11011110	10 Watts
F	316- j169	00101101	10 Watts
G	79 + j183	00011011	10 Watts

3.8 Transmitter Electronic Components Assembly Performance characteristics . This—section describes the performance characteristics of the Transmitter Electronic Components Assembly, assembly number 9333579, consisting of assembly number 9333590(A3) and assembly number 9333595(A4).

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3.8.1 <u>Harmonic filter characteristics</u>. The following describes the performance characteristics of the Harmonic Filter, when used at the MOPMS carrier frequency Fo as specified by drawing 9333026 and tested per 4.5.6.1.

a.Insertion loss: The insertion loss of the filter shall be less than 1.0 db.

b. Return loss: The return loss of the filter when loaded with a 50 ohm real load shall be less than 14db.

c. Harmonic attenuation: The attenuation of any harmonic of the fundamental frequency (Fe) up to 40.OMhz shall be greater than 35db relative to the fundamental. The attenuation of the second and third harmonic shall be greater than 60db relative to the fundamental.

3.8.2 <u>RF Power amplifier</u>. This section describes the characteristics of the RF Power Amplifier.

3.8.2.1 <u>RF power output</u>. The power output of the RF Amplifier at A3-E4 (RF OUT) when loaded with 50 ohms shall be 12 watts minimum when tested per 4.5.6.2.

3.8.2.2 <u>Current loading of amplifier</u>. The current drain into A3-E3 (VBATT) shall be less than 2.6 amps, when tested per 4.5.6.2.

3.8.3 <u>Tuning attenuator</u> pad. The RF output power shall be attenuated by 12 + 2db from the level measured in 4.5.6.2 when tested per 4.5.6.3.

3.8.4 <u>Transmitter cutoff voltage</u>. The RF transmitter shall be disabled when the voltage at A3-E3 (VBATT) is at or below the cutoff voltage threshold. The cutoff voltage threshold shall be 10.0+0.5 volts when tested per 4.5.6.4.

3.8.5 <u>Current limiter</u>. With a short applied between the drain and source of Q5 in the RF amplifier, the current drain into A3-E3 (VBATT) shall limit to less than 3.0 amps when tested per 4.5.6.5.

3.8.6 <u>Fast turn off inhibit</u>. The RF power into 50 ohms shall go to 0.0 (+0.2/-0) watts and the DC voltage at A4-E22 (STROBE BUFF) and A4-E21 (STROBE BUFF-) shall change from 0.0+0.2 volts to 5.0+0.5 volts and from 5.0+0.5 volts to 0.0+0.2 volts respectively when tested per 4.5.6.6.

3.8.7 <u>Send enable/disable.</u> With 3.6+1.6 volts applied to A3-E9 (SEND),'the DC voltage at A4-E23 (A.T.+5VDC) shall be 5.0+0.4 volts. When 0.0+0.2 volts is applied to A3-E9 (SEND) the RF power output into 50 ohms shall be 0.0 (+0.2/-0) watts and the DC voltage at A4-E23 shall be 0.0+0.5 volts when tested Per 4.5.6.7.

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3.8.8 Mark/space frequencies. With **4.8+0.2 volts applied to A4-E5 (MESSAGE DATA INPUT) the frequency of the RF output at A3-E4 (RF OUT) shall be the "mark" frequency as specified by drawing 9333026. When 0.0+0.2 volts is applied to A4-E5 the frequency of the RF output at A3-E4 shall be the "space" frequency as specified by drawing 9333026 when tested per 4.5.6.8.**

3.9 Sender Electronic Components Performance characteristics. This section describes the performance characteristics of the Sender Electronic Components Assembly (9333599). The unit performance characteristics shall be specified for a nominal voltage of 13 + 0.5V unless otherwise stated.

3.9.1 Voltage regulation. With the voltage at A2-E34 (+15V) with respect to A2-E43 (GND) set to 13 + 0.5 volts, the voltage at A2-E44 (+5VDC) with respect to A2-E43 (GND) shall be 4.8 volts minimum to 5.3 volts maximum when tested per 4.5.7.27.

3.9.2 Low voltage detection. The battery low detection lamp shall flash when the voltage at A2-E34 (+15V) with respect to A2-E43 (GND) is at or below the low voltage threshold. The *low voltage* threshold shall be from 11.0 volts maximum to 10.3 volts minimum when tested per 4.5.7.33.

3.9.3 SENDER power off current. With the voltage at A2-E45 (RAMV) set to 13 + 0.5 volts and A2-E34 **(+15v) open, the current into A2-E45 (RAMV) shall be 2.0 milliamperes maximum when tested per 4.5.7.6.**

3.9.4 Standby current . With the voltage at A2-E45 (RAMV) and A2-E34 (+15V) set to 13 + 0.5 volts and the displays blank, the current into A2-E34 (+15V) shall be 50 milliamperes maximum when tested per 4.5.7.32.

3,9.5 Data input. Keyboard data is entered into the SENDER via a matrix of switches. When a key is pressed, a signal pair that uniquely corresponds to that key is shorted together. When tested per 4.5.7.1, keyboard signal pairs shall be defined as specified below:

Key	Signal Pair To Be Shorted	
TRANSFER	A2-E49 (Row 1)	**A2-E52** **(Col 1)**
DESTRUCT/1	A2-E51 **(Row** 2)	**A2-E55** (Col 4)
AUTO/2	A2-E50 **(Row 3)**	**A2-E53** (Col 2)
DEPLOY/3	**A2-E50** (ROW **3)**	**A2-E54** (Col 3)
R'SET SD/4	**A2-E50 (Row 3)**	**A2-E55** (Col 4)
GRP ID/5	**A2-E48 (ROW 4)**	**A2-E52** (Col 1)
COPY/6	**A2-E48** **(Row 4)**	**A2-E53** (Col 2)
7	**A2-E48** **(Row 4)**	**A2-E54** (Col 3)
8	A2-E48 (Row 4)	**A2-E55** (Col 4)

3.9.6 <u>Memory retention voltage</u>. With the voltage at A2-E45 (RAMV) set to 13 + 0.5 *volts* and A2-E34 (+15V) open, the voltage at the cathode of CR2 of the AZ assembly shall be 4.5 volts minimum to 5.3 volts maximum when tested per 4.5.7.7.

3.9.7 Data <u>retention time</u>. -Data stored in the SENDER memory shall be retained for at least 5 minutes with the power disconnected from A2-E34 (+15V) and A2-E45 (RAMV).

3.9.8 <u>Power on clear</u>.

3.9.8.1 **Initializing pulse on Power up.** The SENDER shall generate an initializing pulse on powerup as specified in Figure 6 when tested per 4,5.7.8.

3.9.8.2 **Processor reset.** The processor shall reset when A2-E42 (CLEAR) is momentarily driven to 0.0 + 0.2 volts then open when tested per 4.5.7.13.

3.9.9 <u>Initial Power app lication</u>. When battery power is first applied to A2-E34 (+15V) or until a valid STORE code has been established, the SENDER shall display "INVALID", when power is applied and A2-E38 (S.C.S.) is open when tested per 4.5.7.9.

3.9.10 <u>STORE code entry **mode**</u>

3.9.10.1 **STORE code entry Prompt .** When A2-E38 (S.C.S) is at a logic *zero* (0.2 + 0.2 **volts) and then battery power is applied to A2-E43 (+15V), the SENDER shall display five dashes (-----) as the STORE code entry prompt when tested per 4.5.7.10.**

3.9.10.2 <u>STORE code entry display</u>. When the STORE code entry prompt is displayed, then as each key is entered, the SENDER shall display the new digit in the right most display position, shifting all other display digits to the left by one character position when tested per 4.5.7.11.

3.9.11   STORE mode

3.9.11.1 <u>Power on prompt</u> . When a valid STORE code has been established and A2-E38 (S.C.S) is open, the SENDER shall display "ON" when power is applied to A2-E34 (+15V) when tested per 4.5.7.10.

3..9.11.2 No previous SEND code <u>selected</u>. The SENDER shall display four dashes (----) 16 + 1.0 seconds after power is applied to A2-E34 (+15V) if a SEND code has not been previously selected and the correct STORE code has been entered within the first 15 seconds after power application at A2-E34 (+15V) when tested per 4.5.7.15.

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3.9.11.3 Previous SEND code selection. The SENDER shall display
the previously selected SEND code 16 + 1.0 seconds after power is
applied to A2-E34 (+15V) if the Correct STORE code has been entered
within the first 15 seconds after power application at A2-E34 (+15V)
when tested per 4.5.7.18.

3.9.11.4 Invalid STORE code entry. The SENDER shall
display "INVALID" 16 + 1.0 seconds after power is applied to
A2-E34 (+15V) if-an incorrect or incomplete STORE code or no
entry is keyed in within the first 15 seconds when tested
per 4.5.7.12 and 4.5.7.14.

3.9.12   SEND code selection.

3.9.12.1   SEND code selection prompt. The SENDER shall display
"AUTO" when the SENDER is in the STORE mode and the AUTO key has been
entered when tested per 4.5.7.16 and 4.5.7.17.

3.9.12.2 SEND code display. The SENDER shall display a four
digit SEND code when the SENDER is in the STORE mode and the TRANSFER
key is entered sequentially following the AUTO key when tested per
4.5.7.17,

3.9.13   SEND mode

3.9.13.1 Power on Prompt . When a valid STORE code has been
established and A2-E38 (S.C.S) is open, the SENDER shall display "ON"
when power is applied to A2-E34 (+15V).

3.9.13.2 SEND mode entry display. If the SEND code has been
correctly keyed in within the first 15 seconds after power has been
applied to A2-E34 (+15V), the SENDER shall display "n cmd", where n is
the GROUP ID (set to 1 on entering the SEND mode) and cmd is one of:
NONE , TRANSFER, DEPLOY, RESET SD, and DESTRUCT when tested per
4.5.7.22.

3.9.13.3 Invalid SEND code entry. The SENDER shall display
"INVALID" 16 + 1.0 seconds after power is applied to A2-E34 (+15V) if
an incorrect or incomplete STORE Code or no key is entered within 15
seconds when tested per 4.5.7.21.

3.9.14 Display timeout. The SENDER shall blank the
display in the SEND or STORE mode after 10 + 1.0 seconds of
keyboard inactivity when tested per 4.5.7.16.

3.9.15   Group capabilities

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3.9.15.1 <u>Group addresses</u>. The SENDER shall provide the capability to control up to 15 addressed groups when tested per 4.5.7.25.

3.9.15.2 <u>Group control</u>. Control shall be exercised on each group individually or on all 15 groups simultaneously when tested per 4.5.7.24.

3.9.15.3 <u>Group selection</u>. Group selection is made while in the SEND mode. Entering the GRP ID key shall increment the current GROUP ID number of the SENDER by one. Group ID's are the integers 1 thru 15 and "ALL" when tested per 4.5.7.24 and 4.5.7.26.

3.9.16 <u>Transfer capability</u>

3.9.16.1 <u>Transfer data output</u>

3.9.16.1.1 <u>Transfer output Prompt</u>. The SENDER shall display "COPY" when the COPY key is entered and the SENDER is in the STORE mode when tested per 4.5.7.19.

3.9.16.1.2 <u>Data sending display</u>. When the TRANSFER key is entered sequentially following the COPY key while in the STORE mode, the SENDER shall display "SENDING" when tested per 4.5.7.19.

3.9.16.1.3 Data out<u>put sequence</u>. When the load of Figure **1b** is **placed across A2-E35 (MCD1) and A2-E36 (MCD2), an RCD pulse sequence shall be generated at the output of the load as specified in Figure 2 in response to a** COPY **command when tested per 4.5.7.19.**

3.9.16.1.4 <u>Data output completion display</u>. When the SENDER has completed transmission of the RCD pattern, the SENDER shall display the four digit SEND code associated with that pattern as specified in Drawing 9333026 when tested per 4.5.7.19.

3.9.16.2 <u>Transfer data input</u>

3.9,16.2.1 <u>Receive input prompt</u>. When the load of Figure 3b is placed across A2-E35 (MCD1) and A2-E36 (MCD2) and the SENDER is in the STORE mode, the SENDER shall display "RECEIVE" when the load is driven as specified in Figure 3c when tested-per 4.5.7.20.

3.9.16.2.2 <u>Receive input acceptance</u>. When the TRANSFER key is entered while the SENDER displays "RECEIVE", the SENDER shall display the four digit SEND code associated with the RCD transfer pattern as specified by Drawing 9333026 when tested per 4.5.7.20.

3.9.17 <u>Group status display</u>

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3.9.17.1 <u>Status format</u>. The status format shall be "n stat", where n is the GROUP ID number 1 to 15 inclusive and stat is one of: NONE, TRANSFER, DEPLOY, RESET SD, and DESTRUCT when tested per 4.5.7.24 and 4.5.7.28.4.

3.9.17.2 <u>Group "ALL". status format</u>. The status format shall be. "ALL" for the GROUP ID of ALL when tested per 4.5.7.26.

3.9.17.3 <u>Initial status</u>. After initial power application or reassigning of the SEND or STORE codes, all groups shall begin with initial status of NONE when tested per 4.5.7.22 and 4.5.7.24.

3.9.17.4 <u>Status update sequence</u>. The group status shall be updated as specified by the state diagram of Figure 4 when **tested 4.5.7.31.**

3.9.18 <u>R**CU to CI transfer**</u>

3.9.18.1 <u>Transfer display</u>. The SENDER shall momentarily display "SENDING" when the TRANSFER key is entered, the SENDER is in the SEND mode, and the GROUP ID is not "ALL" when tested per 4.5.7.23.

3.9.18.2 <u>Transfer output</u>. When the load of Figure lb is placed across A2-E35 (MCD1) and A2-E36 (MCD2), an FSD pulse sequence shall be generated at the output of the load as specified in Figure 2 for the current group and RCD code *in* response to a TRANSFER command when tested per **4.5.7.23.**

3.9.18.3 <u>Group status update</u>. When the FSD pulse sequence has completed, the group status display shall be updated as specified by 3.9.17.1 and 3.9.17.4 when tested per 4.5.7.23.

3.9.18.4 <u>Invalid transfer group</u>. The SENDER shall display "ALL INVALID" when the TRANSFER key is entered, the SENDER is in the SEND mode, and the current GROUP ID is "ALL" when tested per 4.5.7.26.

3.9.19 <u>Command transmission</u>

3.9.19.1 <u>Command display</u>. The SENDER shall display "DEPLOY n"., "DESTRUCT n", or "RESET SD n" (n is the current GROUP ID), when the DEPLOY, DESTRUCT, or R'SET SD key respectively is entered, and the SENDER is in the SEND mode when tested per 4.5.7.28.

3.9.19.2 <u>Tuning sequence</u> display. The SENDER shall display "TUNING" when A2-E39 (XMIT) is momentarily driven to a logic zero (0.2 + 0.2 volts) sequentially after the DEPLOY, DESTRUCT, or R'SET SD key is entered and the SENDER is in the SEND mode when tested per 4.5.7.28.1.

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3.9.1-9.3 <u>Tuning sequence control</u>. The SENDER shall generate tuning cent-rol signals during the tuning sequence as specified by Figure 7 when tested per 4.5.7.28.1.

3.9.19.4 <u>Transmit display</u>. After the tuning sequence has completed, the SENDER shall display "XMIT TUNE = m" where m is an integer from O to 9 as specified below when tested per 4.5.7.28.2.

Lowest Voltage At A2-E58 (VREFL) As a Percentage of A2-E44 (+5VDC) During Tune Sequence	Tune Number m
1.3 + 1.3	9
4.9 + 1.7	8
9.4 + 2.3	7
13.9 + 1.7	6
19.0 + 2.9	5
23.5 + 1.1	4
26.8 + 1.7	3
34.5 + 5.4	2
52.5 + 12.1	1
82.5 + 17.4	0

3.9.19.5 <u>Command output sequence</u>. A biphase message, as specified by Drawing 9333026 for the field set data of the current group, shall be generated at A2-E46 (SEROUT) after the SENDER has completed the tuning sequence when tested per 4.5.7.28.3, 4.5.7.29, and 4.5.7.30.

3.9.19.6 <u>Group status update</u>. When the biphase transmission has completed, the group status shall be updated as specified by 3.9.17.1 and 3.9.17.4 when tested per 4.5.7.28.4, 4.5.7.29 and 4.5.7.30.

3.9.20 <u>Passive internal terminations</u>. The following signals shall have passive internal terminations when tested per 4.5.7.2

SIGNAL	VALUE	CONNECTED TO
A2-E25 (SEND)	47K + 5%	GND
A2-E28 (S.C.S.)	47K + 5%	+5VDC
A2-E32 (XMIT)	47K + 5%	+5VDC
A2-E52 (Col 1)	47K + 5%	GND
A2-E53 (Col 2)	47K + 5%	GND
A2-E54 (Col 3)	47K + 5%	GND
A2-E55 (Col 4)	47K + 5%	GND

3.1O <u>Low temperature operation</u>. The Remote Control Unit shall meet the performance characteristics specified in 3.6 at minus 35 (+0/-5) degrees F when tested as specified in 4.5.3.

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3.11 <u>High temperature operation</u>. The Remote Control Unit shall meet the performance characteristics specified in 3.6 at plus 145 **(+5/-0) degrees F when tested as specified in 4.5.4.**

3.12 <u>Stress screen</u>ing. Before potting, all circuit card assemblies shall have temperature stress screening performed prior to testing. Card assemblies are to be temperature cycled without power applied. The temperature range is -50+10 degrees **F** to 150+10 degrees F with a dwell time at temperature extremes of 15 +5 minutes. The rate of temperature change is 18 degrees F/minute minimum with 10 cycles minimum. Circuit card assemblies which have component failures at test representing more than 25% of the total board components shall have the stress screening operation repeated following replacement of defective components.

3.13 <u>Process control</u>. The contractor shall submit to the government with the first article sample, process control documents for the processes listed in the following subparagraphs. These processes shall be those used in the fabrication of the first article sample and shall not be changed after approval of the first article sample. At unscheduled intervals during the operation of the approved processes, the government inspector shall observe the processes to ascertain that production to the approved process control documents is being maintained. No deviation without approval from the procuring activity shall be allowed. XII the event that the contractor desires a change in an approved process control document, a new first article sample may, at the discretion of the government be required.

3.13.1   <u>Process control of molded Plastic parts</u>. A process control document shall be prepared for each of the molded plastic parts. These documents shall briefly describe the entire process and shall fully document the controls to be utilized for maintaining the process. **They shall specify the time, temperature, pressure ranges and cure process which shall be maintained during production of the molded** parts.

3.13.2   <u>Process control of potting</u>. A process control document shall be prepared for potting the electronic assembly. It shall fully **describe the entire process and the controls for maintaining the process. It shall specify the preparation of all materials, pot life, and curing temperature and time.**

3.14 **<u>Material control</u>. The contractor shall prepare and submit to the government a material control document. This document shall detail the procedures used to identify and control the components/subassemblies to assure that only qualified components/subassemblies from qualified suppliers are used in the manufacture or** assembly of the Remote Control Unit.

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3.15 <u>Qualified suppliers</u>. A qualified component supplier shall be one who has successfully met the requirements of this specification and **First Article inspection specified herein.**

3.16 <u>Inspection data</u>. Data shall be recorded and retained for all first article and Quality Conformance tests required by 4.4.2.TBD.

3.16.1 <u>Variable data</u>. Transmitting power output,transmitting current, standby current, power off current, "mark", frequency, "space", frequency, transmitter cutoff voltage and low-battery voltage shall be measured and recorded as variable data for the first article samples and surveillance units.

3.17 <u>Surveillance units.</u> . The contractor shall provide for surveillance quantities of electronic assemblies from production. Units shall be evenly proportioned from production. Inspection data shall be recorded and retained for all surveillance units. Require-ments, sample frequency and quantities for submission shall be as specified in the contract.

3.18 First article in<u>spection</u>. This specification contains provisions for first article inspection. Requirements for the submission of first article samples by the contractor shall be as specified in the contract:

3.19 <u>Electrostatic discharge control</u>. All areas where electronic components , assemblies or equipment are present shall comply with the requirements of the following control elements of DOD-STD-1686: protected areas, handling procedures, protective covering, installation site, training, quality assurance provisions and packaging for delivery.

3.20 <u>Workmanship.</u>

3.20.1 <u>Mechanical workmanship</u>. All parts and assemblies shall be fabricated and assembled in a thorough, workmanlike manner. They shall be free of burrs, sharp edges, cracks, dirt, grease, rust and other foreign matter. The cleaning method used shall not be injurious to any parts, nor shall the parts be contaminated by the cleaning agents. Exterior surface coatings shall be continuous; however, light scratches not exposing base material may be permitted. All required marking and stamping shall be neat and sharply defined.

3.20.2 <u>Electrical workmanship</u>. Unless otherwise specified, all soldering connections shall meet the requirements of MIL-S-45743, MIL-S-46844 and the aplicable drawing. All other electrical workmanship criteria shall meet MIL-STD-454, Req. 9 and the applicable drawing.

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4. QUALITY ASSURANCE PROVISIONS

4.1 Responsibilities for inspection and standard quality assurance Provisions. Unless otherwise specified herein or in the contract, the provisions of MIL-S-48078 shall apply and are herein made *a*part of this detail specification.

4.2 Classification of inspection. The following types of inspection shall be conducted on this item.

a. First article inspection
b. Quality conformance inspection

4.3 First article inspection.

4.301 Submission. The contractor shall submit a first article sample, as designated by the contracting officers for evaluation in accordance with the provisions of 4.3.2 and 4.3.3. The first article sample shall consist of the items and sample quantities listed in Table I.

4.3.2 Inspections to be Performed.

4.3.2.1 Components and subassemblies. See MIL-A-48078 and Table I specified herein.

4.3.2.2 Remote Control Unit. (Drawing 9332873) The control assemblies listed in Table I shall be serialized for identification and subjected to the following tests.

4.3 .2.2.1 Temperature cycle. Subject the control assembly to temperature cycle per MIL-STD-202, method 107D, condition Al, except that the temperature range shall be minus 65 degrees F to plus 160 degrees F (Non-Destructive Test).

4.3 .2.2.2 Mechanical shock. Following temperature cycle, subject the control assemblies to mechanical shock per MIL-STD-202, method 213B, condition E with a TBD peak and a TBD ms min/TBD max duration (Non-Destructive Test).

4.3 .2.2.3 Performance test. Following mechanical shock, the Remote Control Unit performance characteristics shall be verified by testing as specified in Table I.

4.3.3 Rejection. See MIL-A-48078. The first article sample shall be rejected if any part, sub-assembly or assembly fails to comply with any of the examinations or tests specified in this specification or any of the requirements of the applicable drawings.

TABLE 1. First **article inspection**

CLASSIFICATION OF DEFECTS & TESTS   MI

● MAGRAPH	TITLE Remote Control Unit		SHEET	1 2 OF	DRAW Se NEXT
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	PARAG
	Cover, **Battery Enclosure (Dwg 9332877)** **Examination for defects**	6			
	Cover, Transmitter Enclosure **(Dwg 9332882)** **Examination for defects**	6			
	Keyboard. (Dwg 9332883) **Examination for defects**	6			
	Chassis, Electrical Equipment Antenna **(Dwg** 9332884) Examination for defects	6			
	Base, Antenna Support (Dwg 9332885) Examination for defects	6			
	Value, Pressure Relief (Dwg 9332904) Examination for defects	6			
	Coil, Magnetic Coupling (Dwg 9332919-2) Examination for defects	6			
	Switch, Rotary **(Dwg** 9332924) Examination **for defects**	6			

NOTES:

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TABLE 1. First article inspection

CLASSIFICATION OF DEFECTS & TESTS   MIL-

● AUMRAPH	m u Remote Control Unit		SHEET 2 of 2	DRAWING See MEXT H.

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRA
	Electronic, **Components Assembly, Tuning** (Dwg 9333578)				
	Examination for defects	6			
	Electrical performance characteristics	6			
	Electronic, Components Assembly, Transmitter (Dwg 9333579)				
	Examination for defects	6			
	Electrical performance characteristics	6			
	Electronic, Components Assembly, Sender (Dwg 9333599)				
	Examination for defects	6			
	Electrical performance characteristics	6			
	Remote Control Unit (Dwg 9332873)				
	Mechanical	6			
	Performance characteristics				
	a. Ambient	6			
	b. Cold (-35 F)	6			
	c. Hot (+145 F)	6			

NOTES:

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4.3.4 **Requalification.** The contractor shall be-subjected to another first article for the component or assembly affected as stipulated in the contract," if any of the following occur:

a. Manufacturing techniques or process controls which affect the form, fit, or function of the assembly are revised by either the contractor or one of his subcontractors supplying parts or assemblies or materials.

b. The contractor relocates his production facilities or portions thereof.

The contractor desires to use a new subcontractor (unqualified) for materials, parts or assemblies.

d. A change occurs in the design, material, performance or assembly of the Remote Control Unit.

e. A lapse in production for a period of 90 days or as stipulated in the contract.

4.4 **Quality conformance inspection.**

4.4.1 **Inspection lot formation.** Inspection lots shall comply with the lot formation provisions of MIL-A-48078. In addition, inspection lots of electronic assemblies and sub-assemblies shall contain:

a. Crystals, quartz bearing the same lot interfix number from one manufacturer.

b. Oscillators, crystal bearing the same lot interfix number from one manufacturer.

c. Microcircuits, digital, 4096 bit (512x8) UV erasable PROM bearing the same lot interfix number from one manufacturer.

d. Microcircuits, digital, CMOS, 8 bit microprocessor bearing the same lot interfix number from one manufacturer.

e. Microcircuits, digital, CMOS, decoder logic array bearing the same lot interfix number from one manufacturer.

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f. Circuit card assemblies bearing the same lot number from
    one manufacturer
       Microprocessor, Remote Control Unit
       Inductor Tuning
       Capacitor Tuning
       Amplifier, Power, Transmitter
       Transmitter, Logic
       Display, Remote Control Unit

4.4.2 Examination.   See MIL-A-48078.

a. Sampling Plans ,   Unless otherwise specified in the
Classification of Defects and Test Tables, sampling plans and
procedures for major and minor defects shall be in accordance with
MIL-STD-105, Normal Inspection Level II. (See Classification of
Defects).

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-

PARAGRAPH	TITLE				DRAWIN
4.4.2.1	Crystal Oscillator (TTL)		SHEET 1 OF 1		9332
					NEXT
					9333

CATEGORY	RUMINATION OR TEST	NO. OF SAMPLE UNITS	AQL 100%	REQUIREMENT ● ARAGRAPH	PARAGF
Critical	**None defined**				
Major					
101	Screening not performed		100%		TABI Test Cert
102	Conformance inspection				TABI and para
103	Solderability				MIL- 208
Minor					
201	**Marking incorrect**		**0. 65%**		**Visu**
202	**Poor workmanship**		**0.65%**		**Visu**

NOTES:

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QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

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PARAGRAPH 4.4.2.2	TITLE Crystal Oscillator (TTL)		SHEET 1 OF 1		DRAWING NUMBER 9332968
					NEXT HIGHER ASSEMBLY 9333595
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%-	REQUIRMENT PARAGRAPH	PARAGRAPH REFERENCE INSPECTION METHOD
Critical	None defined				
Major					
101	Screening incorrect		100%		TABLE I: Screening Tests (9332968)/ Certification TABLE II (9332968) and MIL-O-55310, paragraph 4.7 MIL-STD-202, Method 208
102	Conformance inspection				
103	Solderability				
Minor					
201	Marking incorrect		0.65%		Visual
202	Poor workmanship		0.65%		Visual

NOTES:

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QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH 4.4.2.3	TITLE Microcircuit, CMOS Monlithic		SHEET 1 OF 1		DRAWING NUMBER See Below
					NEXT HIGHER ASSEMBLY 9333595
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
	P t N b **9333701 933702**				
Critical	None defined				
Major					
101	Screening not performed		100%		MIL-STD-883, Method 5004, Class B/Certification
102	Conformance testing		1		MIL-STD-883, Method 5005, Class B/ Certification
Minor					
201	Marking incorrect		0.65%		Visual
202	Poor workmanship		0.65%		Visual

NOTES Sampling plan shall be per applicable paragraphs of MIL-M-38510, Appendix B.

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QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH 4.4.2.4	TITLE **Microcircuit, Linear, Driver, Dual, CMOS**		SHEET 1 OF 1		DRAWING NUMBER 9333704
					NEXT HIGHER ASSEMBLY 9333595 9333585
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	**None** defined				
Major					
101	Screening not performed		100%		MIL-STD-883, Method 5004, Class B/ Certification
102	Conformance testing		<u>1</u>		MIL-STD-883, Method 5005 Class B/ Certification
Minor					
201	Marking incorrect		0.65%		Visual
202	poor workmanship		0.65%		Visual

NOTES   Sampling plan shall be per applicable paragraphs of MIL-M-38510, Appendix B.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

PARAGRAPH 4.4.2.5	TITLE Printed Wiring Board - Logic Transmitter		SHEET 1 OF 1		DRAWING NUMBER 9333596
					NEXT HIGHER ASSEMBLY 9333595
CATEGORY	EXAMINATION OR TEST	No. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major					
101	Circuits, discontinuous		100%		Tester
102	Conductor, width, minimum		0.40%		Gage
103	Conductor spacing, minimum		0.40%		Gage
104	Solderability		10-0-1		MIL-S-46844
Minor					
201	Diameter of component holes incorrect		0.65%		Gage, Pin
202	Location of component holes incorrect		0.65%		Gage
203	Poor workmanship		0.65%		Visual

NOTES:

AMSMC Form 1570, 1 Feb 85

Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH 4.4.2.6	TITLE Transmitter, Logic - Circuit Card Assembly		SHEET 1 OF 1	DRAWING NUMBER 9333595
				NEXT HIGHER ASSEMBLY 9333579
CATEGORY	RUMINATION on TEST	NO. OF SAMPLE UNITS	AQI. OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	**None** defined				
Major					
101	Circuits, damaged, missing or improperly assembled		0.40%		Visual
102	Poor soldering workmanship		0.40%		Visual/MIL-S-45743
Minor					
201	Height, Component, over max.		0.65%		Gage
202	Conformal coat, not smooth and continuous		0. 65%		Visual
203	Poor workmanship		0.65%		Visual

NOTES:

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AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH 4.4. 2.7	TITLE Core, Torroid		SHEET 1 1	DRAWING NUMBER 9333672 /MIL-C-48655
				NEXT HIGHER ASSEMBLY 9333671
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major					
101	Inductance incorrect		100%		Certification
102	Operating frequency incorrect		100%		Certification
Minor					
201	Diameter, outside incorrect		0. 65%		Gage
202	Diameter, inside incorrect		0.65%		Gage
203	Height incorrect		0.65%		Gage
204	Poor workmanship		0.65%		Visual

NOTES:

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AM   **Form 1570, 1 Feb 85**   Replaces   **DRSMHC-QA (D) Form 160, 1 Aug 83**, which may not used.

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QUALITY **CONFORMANCE INSPECTION**

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH 4.4.2.8	TITLE Microcircuit, Digital, Dual, J-K Positive Edge-Triggered Flip Flop With Preset and Clear		SHEET 1 OF 1		DRAWING NUMBER 9332964
					NEXT HIGHER ASSEMBLY 9333590
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	ACM. OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	**None** defined				
Major					
101	Screening not performed		100%		MIL-STD-883, Method 5004, Class B Certification
102	Conformance testing		1		MIL-STD-883, Method 5005, Class B/ Certification
Minor					
201	Marking incorrect		0.65%		Visual
202	poor workmanship		0.65%		Visual

NOTES Sampling plan shall be per applicable paragraphs of MIL-M-38510, Appendix B.

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AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

PARAGRAPH	TITLE				DRAWING NUMBER
4.4.2.9	Microcircuit, Digital, 5MHZ Two Phase, MOS Clock Driver		SHEET 1 OF 1		9332978
					NEXT HIGHER ASSEMBLY
					9333590
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQl. 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major					
101	Screening not performed		100%		MIL-STD-883, Method 5004, Class B Certification
102	Conformance testing		1/		MIL-STD-883, Method 5005, Class B/ Certification
Minor					
201	Marking incorrect		0. 65%		Visual
202	Poor workmanship		0.65%		Visual

NOTES 1/ Sampling plan shall be per applicable paragraphs of MIL-M-38510, Appendix B.

AMSMC   **Form 1570, 1 Feb 85**   **Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not**   **used.**

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH	TITLE					DRAWING NUMBER
4.4.2.10	Diode, Voltage Reference (1.22V), Silicon		SHEET 1_{OF} 1			9332979
						NEXT HIGHER ASSEMBLY
						9333590
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH		PARAGRAPH REFERENCE /INSPECTION METHOD
<u>Critical</u>	None defined					
<u>Major</u>						
101	Screening not performed		100%			MIL-STD-883, Method 5004, Class B Certification
102	Conformance testing		1/			MIL-STD-883, Method 5005, Class B/ Certification
<u>Minor</u>						
201	Marking incorrect		0.65%			Visual
202	Poor workmanship		0.65%			Visual

NOTES <u>1/</u> Sampling plan shall be per applicable paragraphs of MIL-M-38510, Appendix B.

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AMSMIC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be **used.**

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

PARAGRAPH 4.4.2.11	TITLE Microcircuit, Linear, Five-Volt Regulator		SHEET 1 1. OF			DRAWING NUMBER 9332980
						NEXT HIGHER ASSEMBLY 9333590
CAGEORY	EXAMINATION OR TEST	HO. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH		PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined					
Major						
101	Screening not performed		100%			MIL-STD-883, Method 5004, Class B Certification
102	Conformance testing		1/			MIL-STD-883, Method 5005, Class B/ Certification
Minor						
201	Marking incorrect		0.65%			Visual
202	Poor workmanship		0.65%			Visual

NOTES: 1/ Sampling plan shall be per applicable paragraphs of MIL-M-38510, Appendix B.

AMSMC Form 1570, 1 Feb 85   Replaces   DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used.

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QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH / TITLE		SHEET OF	DRAWING NUMBER
4.4.2.12	Microcircuit, Linear, BIMOS Operational Amplifier	1 1	9332981
			NEXT HIGHER ASSEMBLY
			9333590

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major					
101	Screening not performed		100%		MIL-STD-883, Method 5004, Class B Certification
102	Conformance testing		1/		MIL-STD-883, Method 5005, Class B/ Certification
Minor					
201	Marking incorrect		0.65%		Visual
202	Poor workmanship		0.65%		Visual

NOTES:

1/ Sampling plan shall be per applicable paragraphs of MIL-M-38510, Appendix B.

AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used.

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QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

PARAGRAPH 404.2.13	TITLE Coil, R . F		SHEET OF	1 1	DRAWING NUMBER 9332983
					NEXT HIGHER ASSEMBLY 9333590

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	● ARAGRA?N REFERENCE /INSPECTION METHOD
Critical	**None defined**				
Major					
101	Inductance incorrect		100%		Tester
102	Self resonant frequency incorrect		100%		Tester
103	DC resistance incorrect		100%		Tester
Minor					
201	Lead length incorrect		0.65%		Gage
202	Component length incorrect		0.65%		Gage
203	Coil diameter incorrect		0.65%		Gage
204	Poor workmanship		0.65%		Visual

NOTES:

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AMS? Form 1570, 1 Feb 85   Replaces   DRSMC-QA (D) Form 160, 1 Aug 83, which may **not** be used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH 4.4.2.14	TITLE Transistor, Field Effect, MOS N-Channel Enhancement, Power		SHEET 1 OF 1		DRAWING NUMBER 9332984
					NEXT HIGHER ASSEMBLY **9333590**
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major					
101	Reverse gate current incorrect				MIL-STD-750, Method 3411
102	Drain current, zero gate voltage incorrect				MIL-STD-750, Method 3413
103	Dran current, on-state incorrect				MIL-STD-750, Method 3413
104	Gate to **source threshold voltage, incorrect**				MIL-STD-750, Method. 3403
105	On-state drain to source voltage, incorrect				MIL-STD-750, Method 3405
106	Solderability				MIL-STD-202, Method 208 except aging
Minor					
201	Poor workmanship		0.65%		Visual

NOTES:

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AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

PARAGRAPH	TITLE		SHEET 1 OF 1	DRAWING NUMBER
4.4.2.15	**Printed Wiring Board - Transmitter/PA**			**9333591**
				NEXT HIGHER ASSEMBLY
				9333590

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	**None defined**				
Major					
101	**circuits, discontinuous**		**100%**		**Tester**
102	**Conductor width, minimum**		0.40%		Gage
103	Conductor spacing, minimum		0.40%		Gage
104	Solderability		1o-o-1		MIL-S-46844
Minor					
201	Diameter of component holes incorrect		0.65%		Gage, Pin
202	Location of component holes incorrect		0.65%		Gage
203	Poor workmanship		0.65%		Visual

NOTES:

AMSMC Form 1570, 1 Feb 85   Replaces **DRSMC-QA** (D) Form 160, 1 Aug 83, which May not be used

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH 4.4.2.16	TITLE Coil, Radio Frequency		SHEET 1 OF 1		DRAWING NUMBER 9333671
					NEXT HIGHER ASSEMBLY **9333590**
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT ● ARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	**None defined**				
Major					
101	Inductance incorrect		0.65%		Visual
Minor					
201	Number of turns incorrect		0.65%		Visual
202	Lead length, minimum		0.65%		Gage
203	Conformal coat, not uniform, voids		0.65%		Visual
204	Poor workmanship		0.65%		Visual

NOTES:

AMSMC Form 1570, 1 Feb 85   Replaces   DRSMC-QA   (D) Form 160, 1 Aug 83, which may not be used.

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QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

PARAGRAPH	TITLE			DRAWING NUMBER
4.4.2.17	Coil, Radio Frequency	SHEET OF	1 1	9333709
				NEXT HIGHER ASSEMBLY
				9333590

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	**None defined**				
Major					
101	Inductance incorrect		100%		Tester
Minor					
201	Number of turns incorrect		0.65%		Visual
202	Lead length incorrect		0.65%		Gage
203	Conformal coat, not uniform, voids		0.65%		Visual
204	Poor workmanship		0.65%		Visual

NOTES:

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AMXMC   Form 1570, 1 Feb 85   Replaces   DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH 4.4.2.18	TITLE **Capacitor, Fixed Cermaic**		SHEET OF	I	1	DRAWING NUMBER **9333715**
						NEXT HIGHER ASSEMBLY 9333590
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL *OR* 100%		REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	**None defined**					
Major						
101 102	**Capacitance incorrect** Solderability		**100%** s-4			**Tester** MIL-C-55681, para 4.7.9
Minor						
201	Poor workmanship		0.65%			Visual

NOTES:

AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D)   **Form 160, 1 Aug 83, which may not be used.**

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. **QUALITY CONFORMANCE INSPECTION**

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025 (AR)

PARAGRAPH	TITLE		SHEET 1 OF 1		DRAWING NUMBER
4.4.2.19	Amplifier, Power, Transmitter - Circuit Card Assembly				9333590
					NEXT HIGHER ASSEMBLY
					9333579
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major					
101	Standoff, loose or bent		0.40%		Visual
102	Components, damaged, missing, or improperly assembled		0.40%		Visual
103	Poor soldering workmanship		0.40%		Visual/MIL-S-45743
Minor					
201	Height, component, over max.		0.65%		Gage
202	Conformal coat, not smooth and continuous		0.65%		Visual
203	Poor workmanship		0.65%		Visual

NOTES:

AMSMC form 1570, 1 Feb 85   Replaces   DRSMC-QA (D) Form 160, 1 Aug 83, which may not used

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QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-c-64025(AR)

● PARAGRAPH 4.4.2.20	TITLE Transmitter, Electrical Component Assy		SHEET 1 OF 1		DRAWING NUMBER 9333579
					NEXT HIGHER ASSEMBLY 9332873
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major					
101	Harmonic filter requirements		100%	3.8.1	4.5.6.1
102	RF power output		100%	3.8.2.	4.5.6.2
103	Current loading		100%	3.8.2.	4.5.6.2
104	Tuning attenuator pad		100%	3.8.3	4.5.6.3
105	Transmitter cutoff voltage		100%	3.8.4	4.5.6.4
106	Current limiter		100%	3.8.5	4.5.6.5
107	Fast turn off inhibit		100%	3.8.6	4.5.6.6
108	Sender enable/disable		100%	3.8.7	4.5.6.7
109	Mark/space frequencies		100%	3.8.8	4.5.6.8
Minor	None defined				

NOTES:

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AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which *may* not be used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH 4.4.2.21	TITLE Microcircuit, Linear, 3-Terminal Positive 5 Volt Voltage Regulator	SHEET 1 OF 1	DRAWING NUMBER 9333613
			NEXT HIGHER ASSEMBLY 9333746
CATEGORY	EXAMINATION on TEST	NO. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major					
101	Screening not performed		100%		MIL-STD-883, Method 5004, Class B/ Certification
102	Conformance testing		1/		MIL-STD-883, Method 5005, Class B/ Certification
Minor					
201	Marking incorrect		0. 65%		Visual
202	Poor workmanship		0.65%		Visual

NOTES:

Sampling plan shall be per applicable paragraphs of MIL-M-3851O, Appendix B.

AMS Form 1570, 1 Feb 85   Replaces   DRSMC-QA (D) Form 160, 1 Aug 83, which may not used.

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QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH 4.4.2.22	TITLE Microcircuit, Hybrid		SHEET 1 OF 2	DRAWING NUMBER 9333708
				NEXT HIGHER ASSEMBLY 9333746
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	**None defined**				
Major					
101	**High temperature storage**		100%		MIL-STD-883, **Method 1008, Test Condition C/Certification**
102	**Temperature cycling**		100%		MIL-STD-883, **Method 1010,Test Conditions C/Certification**
103	**Constant acceleration**		100%		**MIL-STD-883, Method 2001,** Test condition **E, Y1 Orientation Only/Certification**
104	Burn-in test		100%		MIL-STD-883, **Method 1015, 160 Hrs. @ 125 C Min/Certification**
105	Seal: **fine and** gross **leak**		100%		MIL-STD-883, **Method 1014, Test condition A or B followed by C**

NOTES:

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QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

PARAGRAPH	TITLE				DRAWING NUMBER
4.4.2.22	Microcircuit, Hybrid	SHEET	2 OF 2		9333708
					NEXT HIGHER ASSEMBLY
					9333746

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Major					
106	Final electrical test, static		100%		Test per 9355160 Table II ambient and temperature extremes\ certification
107	Final electrical, test, switching		100%		Test per 9355160 Table II at 125 C only/certification
"108	Solderability				
Minor					
201	Marking incorrect		0.65%		Visual
202	Poor workmanship		0.65%		Visual

NOTES:

AMSMC Form 1570, 1 Feb 85   **Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used.**

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MI L-C-64025 (AR)

● PARAGRAPH 4.4.2.23	TITLE Microcircuit, CMOS Monolithic		SHEET	1 OF 1	DRAWING NUMBER See Below
					NEXT HIGHER ASSEMBLY 9333746
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
	Part Number 9333000 9333003 9333021				
Critical	None defined				
Major					
101	Screening not performed		100%		MIL-STD-883, Method 5004, Class B/ Certification
102	Conformance testing		1/		MIL-STD-883, Method 5005, Class B\ Certification
Minor					
201	Marking incorrect		0.65%		Visual
202	Poor workmanship		0.65%		Visual

NOTES:

1/ Sampling plan shall be per applicable paragraphs of MIL-M-38510, Appendix B.

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QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH 4.4.2.24	m u Microcircuit, Digitial		SHEET 1 OF 2		DRAWING **NUMBER** 9333001
					NUMBER HIGHER ASSEMBLY 9333746
CATEGORY	**EXAMINATIN OR TEST**	NO. OF SAMPLE UNITS	AQL 100%	REQUIREMENTS PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
<u>Critical</u>	**None defined**				
<u>Major</u>					
101	**High temperature** storage		100%		MIL-STD-883, Method 1008, Test Condition C/Certification
102	Temperature cycling		100%		MIL-STD-883, Method 1010, Test Condition C/Certification
103	Constant acceleration		100%		MIL-STD-883, Method 2001, Test Condition E,Y1 Orientation Only/Certification
104	Burn-In Test		100%		MIL-STD-883, Method 1015, 160 Hrs. @ 125 C Min./Certification
105	Seal: Fine and Gross Leak		100%		MIL-STD-883, Method 1014, Test Condition A or B followed by c/ Certification

NOTES:

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QUALITY **CONFORMANCE INSPECTION**

CLASSIFICATION **OF DEFECTS & TESTS**

MIL-C-64025(AR)

PARAGRAPH 4.4.2.24	TITLE Microcircuit, Digitial				DRAWING NUMBER 9333001
		SHEET 2 OF 2			NEXT HIGHER NUMBER 9333746
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Major					
106	Final electrical test, static		100%		Test per 9355159 Table II ambient and temperature extremes/certification
107	Final electrical test, switching		100%		Test per 9355160 Table 111 at +25 C only/certification
108	Solderability		1o-o-1		MIL-STD-202, Method 208
Minor					
201	Marking incorrect		0.65%		Visual
202	Poor workmanship		0.65%		Visual

NOTES:

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MJL-C-64025(AR)

PARAGRAPH 4.4.2.25	TITLE Diode, Light emitting, hybrid, flashing, Red	SHEET 1 OF 1	DRAWING NUMBER 9333008
			NEXT HIGHER ASSEMBLY 9333746

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major					
101	Luminous intensity incorrect		100%		Tester
102	Peak forward current incorrect		100%		Tester
103	Pulse repetition rate @ +25 C, incorrect		100%		Tester
Minor					
201	Lead spacing incorrect		0.65%		Gage
202	Poor workmanship		0.65%		Visual

NOTES:

Form 1570, 1 Feb 85   Replaces   DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used

QUALITY CONFORMANCE **INSPECTION**

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH 4.4.2.26	TITLE Display, Led, Alphanumerical Array with Logic		SHEET 1 OF 1			DRAWING NUMBER 9333011
						NEXT- HIGHER ASSEMBLY
						9333746
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL. OR 100%	REQUIREMENT PARAGRAPH		PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined					
Major						
101	Loading data		100%			Table I (9333011)/ tester
102	Continuous intensity		100%			Table V (9333011)/ tester
103	Current consumption		100%			Table VI (9333011)/
Minor						
201	Poor workmanship		0.65%			Visual

NOTES:

AMSMC Form 1570. J Feb 85   Replaces DRSMC-OA (D) Form 160. 1 Aug 83. which may not be used.

QUALITY **CONFORMANCE INSPECTION**

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH	TITLE		SHEET OF	1 1		DRAWING NUMBER
4.4.2.27	**Transistor Array, Field Effect**					9333022
						NEXT HIGHER ASSEMBLY
						9333746
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH		PARAGRAPH **REFERENCE** /INSPECTION METHOD
Critical	None defined					
Major						
101	Gate threshold voltage incorrect					MIL-STD-750, Method 3403
102	Drain-source on voltage incorrect					MIL-STD-750 , Method 3405
103	Drain-source breakdown incorrect					MIL-STD-750, Method 3407
104	On-state drain current incorrect					MIL-STD-750, Method 3413
105	Solderability					MIL-STD-202, Method 208 Except aging
Minor						
201	Poor workmanship		0.65%			Visual

NOTES:

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

PARAGRAPH	TITLE				DRAWING NUMBER
4.4.2.28	Printed Wiring Board	SHEET	1 OF 1		**9333747**
					NEXT HIGHER ASSEMBLY
					9333746

CATEGORY	EXAMINATON OR TEST	NO. OF SAMPLE UNITS	AQL *100%*	REQUIREMENT PARAGRAPH	**PARAGRAPH REFERENCE** **/INSPECTION METHOD**
Critical	**None** defined				
Major					
101	Circuits, discontinuous		100%		Tester
102	Conductor, width, minimum		0.40%		Gage
103	Conductor, spacinq, minimum		0.40%		Gage
104	Solderability		**10-0-1**		MIL-S-46844
Minor					
2 0 1	**Diameter of** component holes		**0.65%**		Gage, Pin
202	Location of component holes		**0.65%**		Gage
203	Poor workmanship		**0.65%**		Visual

NOTES:

AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used

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QUALITY **CONFORMANCE INSPECTION**

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH 4.4.2.29	TITLE Microcircuit, Linear, Bipolar Monolithic Micropower Voltage Detector		SHEET 1 OF 1		DRAWING NUMBER 9333615
					NEXT HIGHER ASSEMBLY 9333746
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major					
101	Screening not performed		100%		MIL-STD-883, Method 5004, Class B
102	Conformance testing		1/		MIL-STD-883, Method 5005, Class B
Minor					
201	Marking incorrect		0.65%		Visual
202	Poor workmanship		0.65%		Visual

1/ **Sampling plan shall be per applicable paragraphs of** MIL-M-38510, Appendix B.

AMSMC   **Form 1570, 1 Feb 85**   Replaces   **DRSMC-QA (D) Form 160, 1 Aug 83, which may not used.**

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QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

PARAGRAPH 4.4.2.30	TITLE Display, Remote Control Unit - Circuit Card Assembly		SHEET 1 OF 1	DRAWING NUMBER 9333746
				NEXT HIGHER ASSEMBLY 9333599
CATEGORY	EXAMINATION OR TEST	MO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major					
101	Components, damaged, missing or improperly assembled		0.40%		Visual
102	Poor soldering workmanship		0.40%		Visual/MIL-S-45743
Minor					
201	Height, component, over max.		0.65%		Gage
202	Conformal coat, not smooth and continuous		0. 65%		Visual
203	Poor workmanship		0.65%		Visual

NOTES:

AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used.

QUALITY **CONFORMANCE INSPECTION**

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

PARAGRAPH	TITLE			DRAWING NUMBER
4.4.2.31	printed Wiring Board	SHEET	1 OF 1	9332961
				NEXT HIGHER ASSMEBLY
				9332962

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major					
101	Circuits, discontinuous		100%		Tester
102	Conductor width, minimum		0.40%		Gage
103	Conductor spacing, minimum		0.40%		Gage
104	Solderability		1o-o-1		MIL-S-46844
Minor					
201	Diameter of component holes incorrect		0.65%		Gage,pin
202	Location of component holes incorrect		0.65%		Gage
203	Poor workmanship		0. 65%		Visual

NOTES:

AMSMC   Form 1570, 1 Feb 85   Replaces   DRSMC-QA (D) Form 160, 1 Aug 83, which may not   used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH 4.4.2.32	TITLE Microcircuit, CMOS Monolithic Amplifier		SHEET 1 OF 1	DRAWING NUMBER See Below
				NEXT HIGHER ASSEMBLY 9332962
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
	Part Number 9332988 9332989 9332990 9332991 9333682 9333683 9333684 9333685				
Critical	**None defined**				
Major					
101	Screening not performed		100%		MIL-STD-883, Method 5004, Class B Certification
102	Conformance testing		1/		MIL-STD-883, Method. 5005, Class B\ Certification
Minor					
201	Marking incorrect		0.65%		Visual
202	Poor workmanship		0.65%		Visual

NOTES 1/ Sampling plan shall be per applicable paragraphs of M1L-M-38510, Appendix B.

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AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH 4.4.2.33	TITLE Microcircuit, CMOS Monolithic		SHEET 1 OF 1	DRAWING NUMBER See Below
				NEXT HIGHER ASSEMBLY 9332962/9333746

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL- 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
	Part Number 9332996 9333002				
Critical	None defined				
Major					
101	Screening not performed		100%		MIL-STD-883, Method 5004, Class B/ Certification
102	Conformance testing		1/		MIL-STD-883, Method 5005, Class B/ Certification
Minor					
201	Marking incorrect		0.65%		Visual
202	Poor workmanship		0.65%		Visual

NOTES: 1/ Sampling plan shall be per applicable paragraphs of MIL-M-38510, Appendix B.

AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used.

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QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

PARAGRAPH	TITLE			DRAWING NUMBER
4.4.2.34	Microcircuit, Digital Amplifier	SHEET	1 OF 2	9332994
				NEXT HIGHER ASSEMBLY
				9332962

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	**None defined**				
Major					
101	**High temperature** storage		100%		MIL-STD-883, Method 1008, Test Condition C/Certification
102	Temperature cycling		100%		MIL-STD-883, Method 1010, Test condition C/Certification
103	Constant acceleration		100%		MIL-STD-883, Method 2001, Test Condition E,Y1 Orientation Only/Certification
104	Burn-in Test		100%		MIL-STD-883, Method 1015, 160 hrs. @ 1.25 C Min./Certification
105	Seal- Fine and Gross Leak		100%		MIL-STD-883, Method 1014, Test Condition A or B followed by C/ Certification

NOTES:

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AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) Form 160, 1 Aug 83

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH	TITLE			DRAWING NUMBER
4.4.2.34	Microcircuit, Digital Amplifier	SHEET 2 OF 2		9332994
				NEXT HIGHER ASSEMBLY
				9332962

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major					
106	**Final electrical test, static**		100%		**Test per 9355158 Table II Ambient and Temperature extremes\ Certification**
107	**Final electrical test, switching**		100%		**Test per 9335158 Table III at +25 C only/Certification**
108	**Solderability**		1o-o-1		**MIL-STD-202, Method 208**
Minor					
201	**Marking incorrect**		0. 65%		**Visual**
202	**poor workmanship**		0.65%		**Visual**

NOTES:

AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used.

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QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

PARAGRAPH 4.4.2.35	TITLE Crystal, Quartz		SHEET 1 OF 1		DRAWING NUMBER 9332997
					NEXT HIGHER ASSEMBLY 9332962
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL. OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /iNSPECTION METHOD
Critical	None defined				
Major					
101	Fine and gross leak		100%		MIL-STD-883, Method 1014, Test Condition A and C
102	Frequency and equivalent resistance incorrect		100%		MIL-C-3098
103	Capacitance, shunt (Group B) incorrect				MIL-C-3098
104	Solderability		100%		MIL-STD-202, Method 208
Minor					
201	Poor workmanship		0.65%		Visual

NOTES:

AMSMC Form 1570, 1 Feb 85

Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used.

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QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH 4.4.2.36	TITLE **Microprocessor, Remote Control Unit- Circuit card Assembly**		SHEET 1 OF 1		DRAWING NUMBER **9332962**
					NEXT HIGHER ASSEMBLY **9333599**
CATEGORY	RUMINATION OR TEST	HO. OF SAMPLE UNITS	AQL. 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major					
101	Spacer, loose or bent		0.40%		Visual
102	Components, damaged, missing or improperly		0.40%		Visual
103	Solderability		0.40%		Visual/MIL-S-45743
Minor					
201	Height, component, over max.		0. 65%		Gage
202	Conformal coat, smooth, continuous		0.65%		Visual
203	Poor workmanship		0.65%		Visual

NOTES:

AMSMC Form 1570, 1 Feb 85   Replaces   DRSMC-QA (D) Form 160, 1 Aug 83, which may not   used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH	TITLE				DRAWING NUMBER
4.4.2.37	Sender Electrical Component Assembly		SHEET	1 OF 2	9333599
					NEXT HIGHER ASSEMBLY
					9332873

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL. OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical					
1	FSD transfer test		100%	3.6.18.1 3.9.18.3	4.5.7.23
Major					
101	Data input test		100%	3.9.5	4.5.7.1
102	Internal termination test		100%	3.9.20	4.5.7.2
103	Power off current test		100%	3.9.3	4.5.7.6
104	Memory retention voltage		100%	3.9.6	4.5.7.7
105	Power on clear test		100%	3.9.8.1	4.5.7.8
106	Store code entry prompt		100%	3.9.10.1	4.5.7.10
107	Store code select test		100%	3.9.10.2	4.5.7.11
108	Keyboard timeout test		100%	3.9.8.1	4.5.7.12
			100%	3.9.11.4	4.5.7.12
109	Processor reset test		100%	3.9.8.2	4.5.7.13
110	Invalid store code entry test		100%	3.9.11.4	4.5.7.14
111	Initial store mode entry test		100%	3.9.11.2	4.5.7.15
112	Display timeout test		100%	3.9.12.1 3.9.14	4.5.7.16
113	Send code selection		100%	3.9.12.2	4.5.7.17
114	Store mode entry test		100%	3.9.11.3	4.5.7.18
115	RCD code transfer		100%	3.9.16.1.1 3.9.16.1.2 3.9.16.1.3 3.9.16.1.4	4.5.7.17

NOTES:

AMSMC Form 1570, 1 Feb 85   Replaces **DRSMC-QA**   (D) Form 160, 1 Aug 83, which may not be used.

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QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH	TITLE			DRAWING NUMBER
4.4.2.37	Sender Electrical Component Assembly		2 3	9333599
			SHEET OF	NEXT HIGHER ASSEMBLY
				9332873

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL 100%	REQUIREMENTS PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Major					
116	RCD code receive test		100%	3.9.16.2.1 3.9.16.2.2	4.5.7.20
118	Send mode entry test		100%	3.9.13.2 3.9.17.3	4.5.7.22
119	Group selection test		100% 100% 100% 100%	3.9.15.2 3.9.15.3 3.9.17.1 3.9.17.3	4.5.7.24
120	Group addressing test		100%	3.9.15.1	4.5.7.25
121	Invalid fSD transfer test		100%	3.9.15.3 3.9.17.2 3.9.18.4	4.5.7.26
122	Voltage regulation		100%	3.9.1	4.5.7.27
123	Command transmission		100%	3.9.19.1	4.5.7.28
124	Tune sequence		100%	3.9.19.2 3.9.12.3	4.5.7.28.1
125	Transmit display		100%	3.9.14.4	4.5.7.28.2
126	Command output sequence		100%	3.9.19.5	4.5.7.28.3
127	Group status update		100%	3.9.17.1 3.9.19.6	4.5.7.28.4
128	Reset SD test		100%	3.9.19.5	4.5.7.29
129	Destruct test		100%	3.9.19.5 3.9.19.6	4.5.7.30

NOTES:

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QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

PARAPRAPH 4.4.2.37	TITLE Sender Electrical Component Assembly		SHEET 3 OF 3		DRAWING NUMBER 9333599
					NEXT HIGHER ASSEMBLY 9332873
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Major					
130	Status state update test		100%	3.9.17.4	4.5.7.31
	Status setup		100%		4.5.7.31.1
	Reset SD state test		100%		4.5.7.31.2
	Deploy state test		100%		4.5.7.31.3
	Destruct state test		100%		4.5.7.31.5
	Transfer state test		100%		4.5.7.31.4
131	Standby current		100%	3.9.4	4.5.7.32
132	Low battery voltage test		100%	3.9.2	4.5.2.33
133	Data retention test		100%	3.9.7	4.5.7.34
Minor					
201	Initial power application test		0.65%	3.9.9	4*5.7.9

NOTES:

AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) Form 160, 1 AUG 83, which may not be used.

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QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

●AMGRA?H m u		SHEET I OF 1		DRAWING NUMBER
4.4.2.38	Pin, Keying			9332916
				NEXT HIGHER ASSEMBLY
				9332915
CATEGORY	EXAMINATION OR TEST	No. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major					
101	Location, flat incorrect		o. 40%		Gage
102	Dia., keying incorrect		0.40%		Gage
103	Dia., (-B-) incorrect		00 40%		Gage
Minor					
201	Length, (-B-) incorrect		0.65%		Gage
202	Overall length incorrect		0.65%		Gage
203	Flange thickness incorrect		0.65%		Gage
204	Poor workmanship		0.65%		Visual

NOTES:

AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used.

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QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

PARAGRAPH 4.4.2.39	TITLE **Contact, battery**		SHEET 1 OF 1	DRAWING NUMBER **9332917**
				NEXT HIGHER ASSEMBLY **9332915**
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major	None defined				
Minor					
201	Contact dia, incorrect		0.65%		Gage
202	Dia., major outside incorrect		0.65%		Gage
203	Material improper		100%		Certification
204	Poor workmanship		0.65%		Visual

NOTES:

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QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH	TITLE		SHEET 1 OF 1	DRAWING NUMBER
4.4.2.40	Plate, Electrical			9332915
				NEXT HIGHER ASSEMBLY
				9332914-2

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	PARAGAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major					
101	Dia., contact pin holes (2) (-l), incorrect		0.40%		Gage
102	Dia., keying pin hole (-1) , incorrect		o. 40%		Gage
103	Location, contact pin holes (-1), incorrect		o. 40%		Gage
104	Location of battery pins, incorrect		0.40%		Gage
Minor					
201	Poor workmanship		0.65%		Visual

NOTES:

AMSMC Form 1570, 1 **Feb 85**   Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH	TITLE		SHEET	1 OF 1		DRAWING NUMBER
4.4.2.41	Cable Assembly, Power Electrical					9332914
						NEXT HIGHER ASSEMBLY
						9332873
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT ● ARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD	
Critical	None defined					
Major						
101	Solder workmanship poor		0.40%		Visual	
102	Overall length incorrect		0.40%		Gage	
Minor						
201	Poor workmanship		0.65%		Visual	

NOTES:

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AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS MIL-C-64025(AR)

PARAGRAPH 4.4.2.42	TITLE Relay, Magnetic Reed (Latching)		SHEET 1 OF 1		DRAWING NUMBER 9333010
					NEXT HIGHER ASSEMBLY 9333580/9333585
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL. OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major					
101	Operational test incorrect		100%		Tester
102	Coil resistance incorrect		100%		MIL-STD-202, Method 303
103	Insulation resistance incorrect		1.0		MIL-R-5757,Para 4.8.6
104	RF Contact resistance incorrect		1.0		Tester
105	Contact standoff voltage incorrect		100%		Tester
106	Solderability				MIL-STD-202, Method 208
Minor					
201	Pin location incorrect		0. 65%		Gage
202	Poor workmanship		0.65%		Visual

NOTES:

AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used.

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QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

PARAGRAPH	TITLE			DRAWING NUMBER
4.4.2.43	Microcircuit, Linear, Driver, Dual CMOS	SHEET 1 OF 1		9333705
				NEXT HIGHER ASSEMBLY
				9333580/9333585

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major					
101	Screening not performed		100%		MIL-STD-883, Method 5004, Class B/ Certification
102	Conformance testing		1/		MIL-STD-883, Method 5005, Class B/ Certification
Minor					
201	Marking incorrect		0. 65%		Visual
202	Poor workmanship		0.65%		Visual

NOTES:

    1/ Sampling plan shall be per applicable paragraphs of MIL-M-3851O, Appendix B.

AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH	TITLE			DRAWING NUMBER
4.4.2.44	printed Wiring Board	SHEET	1 OF 1	9333581
				NEXT HIGHER ASSEMBLY

CATEGORY	EXAMINATION OR TEST	No. OF SAMPLE UNITS	AQL. 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECITON METHOD
Critical	None defined				
Major					
101	Circuits, discontinuous		100%		Tester
102	Conductor width, minimum		0.40%		Gage
103	Conductor spacing, minimum		0.40%		Gage
104	Solderability		10-0-1		MIL-S-46844
Minor					
201	Diameter of component holes incorrect				Gage,pin
202	Location of component holes incorrect		0.65%		Gage
203	Poor workmanship		0.65%		Visual

NOTES:

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NEXT HIGHER ASSEMBLY: 9 3 3 3 5 8 0

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

AaAGMPN 4.4.2.45	TITLE Microcircuit, Digital		SHEET 1 OF 1		DRAWING NUMBER 9333700
					NEXT HIGHER ASSEMBLY 9333580
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	**None defined**				
Major					
101	Screening not performed		100%		MIL-STD-883, Method 5004, Class B/ Certification
102	Conformance testing		1/		MIL-STD-883, Method 5005, Class B/ Certification
Minor					
201	Marking incorrect		0.65%		Visual
202	Poor workmanship		0.65%		Visual

NOTES: 1/ Sampling plan shall be per applicable paragraphs of M1L-M-38510, Appendix B.

AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

PARAGRAPH	TITLE			DRAWING NUMBER
4.4.2.46	Coil, Radio Frequency		SHEET 1 OF 1	9333717
				NEXT HIGHER ASSEMBLY
				9333580

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major					
101	Inductance incorrect		0.40%		Tester
Minor					
201	Number of turns incorrect		0.65%		Visual
202	Lead length incorrect		0.65%		Gage
203	Conformal coat, not uniform, voids		0.65%		Visual
204	Poor workmanship		0.65%		Visual

NOTES:

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QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

DRAWING NUMBER 9333718

NEXT HIGHER ASSEMBLY 9333580

SHEET 1 OF 1

...circuit, Linear

EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
defined				
...ening not performed		100%		MIL-STD-883, Method 5004, Class B/ Certification
...ormance testing		1/		MIL-STD-883, Method 5005, Class B/ Certification
...ing incorrect		0.65%		Visual
...workmanship		0.65%		Visual

...g plan shall be per applicable paragraphs of MIL-M-38510, Appendix B.

Feb 85

Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

●AMmA?tI 4.4.2.48	TITLE Inductor Tuning - Circuit Assembly		SHEET 1 OF 1	DRAWING NUMBER 9333580
				NEXT HIGHER ASSEMBLY 9333578
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH
				PARAGRAPH REFERENCE /INSPECTION METHOD

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	**None defined**				
Major					
101	**Terminals, loose or bent**		0.40%		**Visual**
102	**Components, damaged, missing or improperly assembled**		0.40%		Visual
103	Poor soldering workmanship		0.40%		Visual/MIL-S-45743
Minor					
201	Conformal coat, not smooth continuous		0.65%		Visual
202	Poor workmanship		0.65%		Visual

NOTES:

AM﹡ Form 1570, 1 Feb 85   Replaces   DRSMC-QA (D) Form 160, 1 Aug 83, which may not   used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

● ARAGRA?H 4.4.2.49	m u Printed Wiring Board, Capacitance Board		SHEET 1 of 1		DRAWING NUMBER 9333586
					NEXT HIGHER ASSEMBLY 9333585
CATEGORY	EXAMINATION on TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major					
101	Circuits, discontinuous		100%		Tester
102	Conductor width, minimum		0.40%		Gage
103	Conductor spacing, minimum		0.40%		Gage
104	Solderability		1o-o-1		MIL-S-46844
Minor					
201	Diameter of component holes incorrect		0.65%		Gage,pin
202	Location of component holes incorrect		0.65%		Gage
203	Poor workmanship		0.65%		Visual

NOTES:

QUALITY CONFORMANCE INSPECTION ,

CLASSIFICATION OF DEFEECTS &TESTS   MIL-C-64025(AR)

PARAGRAPH	TITLE				DRAWING NUMBER
4.4.2.50	Capacitor timing - **Circuit Card Assembly**		SHEET 1 OF 1		**9333585**
					NEXT HIGHER ASSEMBLY 9333578
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major					
101	Components, damaged, missing or improperly assembled		0.40%		Visual
102	Poor soldering workmanship		0.40%		Visual/MIL-S-45743
Minor					
201	Height, component, over max.		0.65%		Gage
202	Conformal coat, not smooth and continuous		0. 65%		Visual
203	Poor workmanship		0.65%		Visual

NOTES:

AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) **Form** 160, 1 Aug 83, which may not be **used.**

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

PARAGRAPH	TITLE		SHEET 1_{OF} 1	DRAWING NUMBER
4.4.2.51	Tuning, Electronic Component			9333578
				NEXT HIGHER ASSEMBLY
				9332884

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major					
101	Reflectometer verification test		100%	3.7.1	4.5.5.1
102	Reflectometer ouput		100%	3.7.1.1	4.5.5.1.1
	50 OHM load			3.7.1.2	4.5.5.1.2
	75 OHM load			3.7.1.:	4.5.5.1.3
	No load				
103	Inductor element test		100%	3.7.2	4.5.5.2
104	Capacitor element		100%	3.7.3	4.5.5.3
105	Power handling capability		100%	3.7.4	4.5.5.4
Minor	None defined				

NOTES:

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

PARAGRAPH	TITLE		SHEET	1 OF 1	DRAWING NUMBER
4.4.2.52	**Base, Antenna Support**				9332885

NEXT HIGHER ASSEMBLY

9332884

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major					
101	Location, mounting holes incorrect		0. 40%		Gage
102	Flatness, mounting-surface		0.40%		Gage
Minor					
201	Width, o-ring groove incorrect		0.65%		Gage
202	Depth, o-ring groove incorrect		0.65%		Gage
203	Poor workmanship		0. 65%		Visual

NOTES:

AMSMC Form 1570, 1 Feb 85

Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS MIL-C-64025(AR)

PARAGRAPH 4.4.2.53	TITLE Support, Antenna-Upper		SHEET OF 1 1		DRAWING NUMBER 9332891
					NEXT HIGHER ASSEMBLY **9332884**
CATEGORY	EXAMINATION OR TEST	*NO. OF* SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	**None defined**				
Major					
101	.375-24 UNF-2B thread (-2) , incorrect		0.40%		Thread Gage
102	.250-28 UNF-2A thread (-2) , incorrect.		0.40%		Thread Ring Gage
103	Knurl dia., over max. (-2)		0.40%		Gage
104	Length, knurl dia. (-2) , incorrect		0.40%		Gage
105	Counterbore depth (-1) , incorrect		0.40%		Gage
106	Dia., chassis mounting (-1) (Ref. 584) incorrect		0.40%		Gage
107	Depth, o-ring groove incorrect		0.40%		Gage
108	Location, flat surface incorrect		0.40%		Gage
109	.250-28 UNF-2A thread (-1), incorrect		0.40%		Thread Gage
Minor					
201	Width, o-ring groove, incorrect		0.65%		Gage
202	Diameter, o-ring groove, incorrect		0.65%		Gage
203	Location, antenna lock groove (typ) incorrect		0.65%		Gage
204	Width, antenna lock groove (typ) incorrect		0.65%		Gage
205	Dia., antenna lock grooves , incorrect		0.65%		Gage
206	Diameter, flange outside, incorrect		0.65%		Gage
207	Poor workmanship		0.65%		Visual

NOTES:

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AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which May not be used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

PARAGRAPH	TITLE				DRAWING NUMBER
4.4.2.54	Support, Antenna-Lower	SHEET 1 OF 1			9332892
					NEXT HIGHER ASSEMBLY
					9332884
CATEGORY	EXAMINATION OR TEST	No. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	**None defined**				
Major					
101	**Location, flat surface**		o. 40%		**Gage**
Minor					
201	**Diameter,** inside incorrect		0.65%		Gage
202	Diameter, outside incorrect		0.65%		Gage
203	Length, incorrect		0.65%		Gage
204	Poor workmanship		0.65%		Visual

NOTES:

AMSMC Form 1570. J Feb 85   Replaces DRSMC-QA   (D) Form 160, 1 Aug 83, which may not be used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH 4.4.2.55	TITLE Terminal, Pin		SHEET 1 OF 1	DRAWING NUMBER 9355155
				NEXT HIGHER ASSEMBLY 9332936

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	● ARAGRAPM REFERENCE /INSPECTION METHOD
Critical	**None defined**				
Major					
101	.042 dia. incorrect		o. 40%		Gage
102	.041 dia. incorrect		0.40%		Gage
103	Length, contact incorrect		0.40%		Gage
Minor					
201	Diameter , flange incorrect		0.65%		Gage
202	Poor workmanship		0.65%		Visual

NOTES:

AMSMC Form   70 1 Feb 8   Replaces DRS C QA (D) Fo m 60 1 Aug 83 wh c may not be used

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS &TESTS

MIL-C-64025(AR)

PARAGRAPH 4.4.2.56	TITLE Pin Plate Assembly Coil		SHEET 1 OF 1		DRAWING NUMBER 9332936
					NEXT HIGHER ASSEMBLY 9332919
CATEGORY	EXAMINATION OR TEST	No. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major					
101	**Material improper**		0.40%	3.2	**Certification**
102	**Swage pins location incorrect**		0.40%	3.2	**Gage**
103	**Components, damaged or bent**		0.40% ,	3.2	**Visual**
Minor					
201	**Poor workmanship**		0.65%	3.2	Visual.

NOTES:

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AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not used.

QUALITY   CONFORMANCE   INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

PARAGRAPH	TITLE			DRAWING NUMBER
4.4.2.57	Core, Ferrite	SHEET 1 OF 1		9332920
				NEXT HIGHER ASSEMBLY
				9332919-2

CATEGORY	EXAMINATION OR TEST	Ho. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major					
101	Magnetic properties, incorrect		100%	B/PNote1	Certification
102	Terminal stud hole dia., incorrect		0.40%		Gage
103	Cavity depth, incorrect.		0.40%		Gage
Minor					
201	Cavity dia., incorrect		0.65%		Gage
202	Cavity center dia., incorrect		0.65%		Gage
203	Width, clearance slots, over min.		0.65%		Gage
204	Height, overall incorrect		0.65%		Gage
205	Outside dia., incorrect		0.65%		Gage
206	Poor workmanship		0. 65%		Visual

NOTES:

AMSMC Form 1570, 1 Feb 85

Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used.

QUALITY   CONFORMANCE   INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   **MIL-C-64025(AR)**

PARAGRAPH 4.4.2.58	TITLE Pin Plate Assembly, Coil - MCD		SHEET	1 OF 1	DRAWING NUMBER 9332936
					NEXT HIGHER ASSEMBLY 9332919-2
CATEGORY	EXAMINATION OR TEST	No. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	**None defined**				
Major 101 102 .103	 **Pin hole location incorrect** **Thru hole dia. incorrect** **Perpendicularity of pins incorrect**		 0.40% **0.40%** **0.40%**		 **Gage** **Gage** **Gage**
Minor 201 202 203 204	 **Pin hole** dia. (before pin installation) incorrect Outside dia. incorrect Material thickness incorrect Poor workmanship		 0.65% 0.65% 0. 65% 0.65%		 Gage Gage Gage Visual

NOTES:

AMSMC   **Form 1570. 1 Feb 85**   Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

PARAGRAPH	TITLE		SHEET 1 OF 1		DRAWING NUMBER 9332919-2
4.4.2.59	Coil, Magnetic Coupling				NEXT HIGHER ASSEMBLY 9332873

CATEGORY	EXAMINATION OR TEST	MO. OF SAMPLE UNITS	AQL. OR 100%	REQUIREMENT ● ARAGRAPH	PARAGRAPH REFERENCE /INPECTION METHOD
Critical	None defined				
Major					
101	Inductance between terminals, incorrect		100%		Test
102	Polarity, incorrect		100%		Test
103	Solder workmanship, poor		0.40%		Visual\MIL-STD-454
104	Outside dia. incorrect		0.40%		Gage
105	Potting material on core, over max.		0.40%		Visual
Minor					
201	Location, polarity dot, incorrect		0.65%		Visual
202	.925 Dia., incorrect		0.65%		Gage
203	Width of pin potting compound incorrect		0.65%		Gage
204	Exposed wires, none permitted		0.65%		Visual
205	Poor workmanship		0.65%		Visual

NOTES:

AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS &TESTS   MIL-C-64025(AR)

PARAGRAPH	TITLE			DRAWING NUMBER
4.4.2.60	**Cover,** Battery Enclosure	SHEET	1 OF 1	9332877
				NEXT HIGHER ASSEMBLY
				9332873

CATEGORY	EXAMINATION OR TEST	No. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
<u>Critical</u>	**None** defined				
Major					
101	Loc of captive screw holes, incorrect		0.40%		Gage
102	Flatness of back face, incorrect		0.40%		Gage
103	Complete assembly and installations, incorrect		0.40%		Visual
<u>Minor</u>					
201	**O-ring cavity width, incorrect**		**0.65%**		**Gage**
202	**O-ring cavity depth, incorrect**		**0.65%**		**Gage**
203	**Location, enclosure pad incorrect**		**0.65%**		**Gage**
204	**Poor workmanship**		**0.65%**		**Visual**

NOTES:

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Form 1570. 1 **Feb 85**   Replaces   **DRSMC-QA (D) Form 160, 1** Aug 83, which **may** **not USED.**

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH	TITLE		SHEET	1 OF 1	DRAWING NUMBER
4.4.2.61	Cover, Transmitter Enclosure				9332882
					NEXT HIGHER ASSEMBLY
					9332873

CATEGORY	EXAMINATION OR TEST	No. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENTS ● ARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
critical	**None defined**				
Major					
101	**Location, mounting holes, incorrect**		**0.40%**		**Gage**
102	**Flatness, mounting surface**		**0.40%**		**Gage**
Minor					
201	**P.D. .138-32 UNC -2B**		0.65%		Thd, Gage
202	Width, o-ring groove		**0.65%**		**Gage**
203	**Depth, o-ring groove, incorrect**		**0.65%**		**Gage**
204	**Poor workmanship**		**0.65%**		**Visual**

NOTES:

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QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH 4.4.2.62	TITLE Keyboard		SHEET 1 OF 1	DRAWING NUMBER 9332883
				NEXT HIGHER ASSEMBLY 9332873

CATEGORY	EXAMINATION OR TEST	No. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENTS ● ARAGRAPH	● ARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major					
101	Momentary action, switch		100%		Tester
102	Location, mounting holes		0.40%		Gage
103	.138-32 thread		o. 40%		Thd Gage
104	Width, gasket groove		0.40%		Gage
105	Depth, gasket groove		0.40%		Gage
106	Flatness, mounting surface		0.40%		Gage
Minor					
2 0 1	Key lighting (LED)		0.65%		Visual
202	Length, cable, minimum		0.65%		Gage
203	Panel identification correct		0.65%		Visual
204	Switch actuation force, incorrect		0.65%		Gage
205	Material, improper, len, display display window		0.65%		Certification
206	Protective finish uniform incomplete		0.65%		Visual
207	Poor workmanship		0.65%		Visual

NOTES:

AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D)) Form 160, 1 Aug 83, which may not bE used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH 4.4.2.63	TITLE Chassis, Electrical Equipment Antenna		SHEET 1 OF 1	DRAWING NUMBER 9332884
				NEXT HIGHER ASSEMBLY 9332873
CATEGORY	EXAMINATION OR TEST	No. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major	None defined				
Minor					
201	Missing or loose hardware/parts		0.65%		Visual
202	Marking, incorrect, illegible or missing		0.65%		Visual
203	Poor workmanship		0.65%		Visual

NOTES:

MSMC Form 1570 1 Feb 85   Replaces DRSMC-QA (D) Form 160 1 Aug 83 which may not be used

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MTL.-C-64025(AR)

PARAGRAPH	TITLE				DRAWING NUMBER
4.4.2.64	Enclosure, Component Mounting	SHEET 1 OF 1			9332899
					NEXT HIGHER ASSEMBLY
					9332873
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major					
101	In work		100%	B/Note	1 Certification
Minor					
201	In work		0.65%		Gage
202	Poor workmanship		0.65%		Visual

NOTES:

AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used.

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QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

PARAGRAPH 4.4.2.65	TITLE Valve, Pressure Relief			SHEET I OF 1	DRAWING NUMBER 9332904
					NEXT HIGHER ASSEMBLY 9332873
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	● ARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major					
101	Cracking pressure, incorrect		100%		Certification
102	Thread, major diameter incorrect		0.40%		Gage
Minor					
201	Absence of o-ring and washer		0.65%		Visual
202	Poor workmanship		0.65%		Visual

NOTES:

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AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

PARAGRAPH	TITLE			DRAWING NUMBER
4.4.2.66	Switch, Rotary	SHEET	1 OF 1	9332924
				NEXT HIGHER ASSEMBLY
				9332873

CATEGORY	EXAMINATION OR TEST	MO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMEMT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major					
101	Contact rating, incorrect		100%		Certification
102	Number Of positions, incorrect		100%		Certification
Minor					
201	Shaft diameter, incorrect		0.65%		Gage
202	Thickness, flat incorrect		0.65%		Gage
203	1/4-28 UNF-2B, incorrect		0.65%		Thread gage
204	Length, shaft and threads, incorrect		0.65%		Gage
205	Missing hardware		0.65%		Visual
206	Poor workmanship		0.65%		Visual

NOTES:

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QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

PARAGRAPH	TITLE			DRAWING NUMBER
4.4.2.67	Cover, Electrical Switch	SHEET	1 OF 1	9332926
				NEXT HIGHER ASSEMBLY
				9332873

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%-	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major	None defined				
Minor					
201	Width, stop surface incorrect		0.65%		Gage
202	Location, stop surface incorrect		0.65%		Gage
203	Diameter mounting hole incorrect		0.65%		Gage
204	Diameter spring hole, incorrect		0.65%		Gage
205	Length to bend, incorrect		0.65%		Gage
206	4-40 UNC-2B thread, incorrect		0.65%		Gage
207	Location thread hole, incorrect		0.65%		Gage
208	Height, bend incorrect		0.65%		Gage
209	Poor workmanship		0.65%		Visual

NOTES:

AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS &TESTS

MIL-C-64025 (AR)

PARAGRAPH TITLE			DRAWING NUMBER
4.4.2.68	Support, Switch Cover	SHEET 1 OF 1	9332927
			NEXT HIGHER ASSEMBLY
			9332873

CATEGORY	EXAMINATION OR TEST	No. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	● ARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major	None defined				
Minor					
201	Width, spring slot, incorrect		0.65%		Gage
202	Diameter, spring slot, incorrect		0.65%		Gage
203	Diameter, thru hole, incorrect		0.65%		Gage
204	Threads, MS20209F4-15L insert, incorrect		0.65%		Gage
205	Height, cover diameter, incorrect		0.65%		Gage
206	Diameter, body incorrect		0.65%		Gage
207	Length, overall, incorrect		0.65%		Gage
208	Thickness, flange, incorrect		0.65%		Gage
209	Location, spring slot, incorrect		0.65%		Gage
210	Poor workmanship		0.65%		Visual

NOTES:

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AMSMC **Form** 1570. 1 Feb 85   Replaces DRSMC-QA (D) Form 160. 1 Aug 83. which may not used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH 4.4.2.69	TITLE Post, Binding, Electrical		SHEET 1 OF 1		DRAWING NUMBER 9332930
					NEXT HIGHER ASSEMBLY 9332873
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major					
101	Conductor retention		100%		MIL-P-55149, Para. 4.6.7
102	Contact resistance		100%		MIL-P-55149, Para. 4.6.5
103	Solderability		100%		MIL-STD-202, Method 208
Minor					
201	Poor workmanship		0.65%		Visual

NOTES:

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QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH	*TITLE*		SHEET	I OF 2	DRAWING NUMBER
4.4.2.70	Electronic Assembly (Performance Characteristics) (Ambient)				9332873
					NEXT HIGHER ASSEMBLY
					9332870

CATEGORY	EXAMINATION OR TEST	No. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	● ARAGRAPH REFERENCE /INSPECTION METHOD
Critical					
1	FSD) transfer test		100%	3.6.19	4.5.2.1.16
Major					
101	Power off current		100%	3.6.1	4.5.2.1
102	Store code entry mode		100%	3.6.11	4.5.2.5
.103	Power on prompt		100%	3.6.12.1	4.5.2.6
104	Keyboard timeout test		100%	3.6.12.2	4.5.2.6
105	Invalid store code test		100%	3.6.12.2	4.5.2.7
106	Store mode entry test		100%	3.6.12.3	4.5.2.0
107	Display timeout		100%	3.6.13	4.5.2.9
108	Send code selection		100%	3.6.13	4.5.2.10
109	Store mode entry		100%	3.6.13.1	4.5.2.11
110	RCD code transfer test		100%	6.1.14.1	4.5.2.12
111	RCD code receive		100%	3.6.1.14.2	4.5.2.13
112	Invalid send code test		100%	3.6.15.2	4.5.2.14
113	Send mode entry test		100%	3.6.15.1	4.5.2.15
114	Group selection test		100%	3.6.17	4.5.2.17
115	Invalid FSD transfer test		100%	3.6.19.4	4.5.2.18
116	RF command transmission		100%	3.6.20.1	4.5.2.19
	Tune display		100%	3.6.20.2	4.5. 2.19.1
	Xmit display		100%	3.6.20.3	4.5.2.19.2
	RF output sequence		100%	3.6.20.4	4.5.2.19.3
	Group status		100%	3.6.20	4.5.2.19.4
117	Command group test		100%	3.6.20	4.5.2.20

NOTES:

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QUALITY **CONFORMANCE INSPECTION**

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH	TITLE		SHEET 2 OF 2	DRAWING NUMBER
4.4.2.70	Electronic Assembly (Performance Characteristics) (Ambient)			9332873
				NEXT HIGHER ASSEMBLY
				9332870

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Major					
118	Reset SD test		100%	**3.6.20**	**4.5.2.21**
119	Destruct test		100%	3.6.20	4.5.2.22
120	Status state update test		100%	3.6.18.2	4.5.2.23
	Status setup		100%	3.6.18.2	4.5.2.23.1
	Reset SD state test		100%	3.6.18.2	4.5.2.23.2
	Deploy state test		100%	3.6.18.2	4.5.2.23.3
	Destruct state test		100%	3.6.18.2	4.5.2. 23.4
	Transfer state test		100%	3.6.18.2	4.5.2.23.5
121	Standby current		100%	3.6.2	4.5.2.2
122	Low battery voltage test		100%	3.6.8	4.5.2.28
123	Transmitting current		100%	3.6.5	4.5.2.25
124	Transmitting power		100%	3.6.6	4.5.2.26
125	Tuning capability		100%	3.6.7	4.5.2.27
126	Transmitter cutoff		100%	3.6.8	4.5.2.28
127	Data retention test		100%	3.6.9	4.5.2.29
Minor					
201	Initial power application test		0.65%	3.6.10	4.5.2.4
202	Keyboard lights		0.65%	3.6.3	4.5.2.3
203	Poor workmanship		0.65%		Visual

NOTES:

AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH	TITLE				DRAWING NUMBER
4.4.2.71	Transistor, PNP (JAN2N869A)		SHEET	1 OF 1	MIL-S-19500/283
					NEXT HIGHER ASSEMBLY
					9333746

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major					
101	Wire material incorrect	32	Note 1	3.2	Visual
102	Wire bond	32	Note 1	3.2	Pull Tester (Note 2)
103	MIL-S-19500/283 compliance			3.2	Certification
104	Solderability (3" leads)		0.40%	3.5.1	MIL-STD-202, Method 208
105	Leakage current ice		0.40%	3.2	MIL-STD-750, Method 3041, Cond. B
106	Internal visual	Note 3	LTPD 10%	3.2	MIL-STD-750, Method 2072, Para 3.2 only
Minor					
2 0 1	Poor workmanship		0. 65%	3.20	Visual

NOTES: (1) Reject for three (3) or more defects.   (2) Pull all wire.   (3) Sampling per
MIL-M-38510, Appendix B.

AMSMC   Form 1570, 1 Feb 85   Rep   es DRSMC-QA (D) Form 160. 1 Aug 83, which may not be used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH 4.4.2.72	TITLE Transistor, NPN (JAN2N222A)		SHEET I OF 1		DRAWING NUMBER MIL-S-19500/255
					NEXT HIGHER ASSEMBLY 9333595/9333590
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL. OR 100%	REQUIREMENT ●ARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major 101	Wire material incorrect	32	Note 1	3.2	Visual
102	Wire bond	32	Note 1	3.2	Pull Tester (Note 2)
103	MIL-S-19500/255 compliance			3.2	Certification
104	Solderability (3 leads)		0.40%	3.5.1	MIL-STD-202, Method 208
105	Leakage current ice		0.40%	3.2	MIL-STD-750, Method 3041, Cond. B
106	Internal visual	Note 3	LTPD 10%	3.2	MIL-STD-750, Method 2072, Para 3.2 only
Minor 2 0 1	Poor workmanship		0.65%	3.20	Visual

NOTES: (1) Reject for three (3) or more defects.   (2) Pull all wire.   (3) Sampling per MIL-M-38510, Appendix B.

Replaces DRSMC-OA (D) Form 160, 1 Aug 83. which may not be used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

● MAGRA?H 4.4.2.73	TITLE Transistor, PNP (JAN2N2905A)		SHEET 1 OF 1		DRAWING NUMBER MIL-S-19500/905
					NEXT HIGHER ASSEMBLY 9333590
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	● ARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major 101 102 103 104 105 106	Wire material incorrect Wire bond MIL-S-19500\290 compliance Solderability (3 leads) Leakage current ice Internal visual	32 32 Note 3	Note 1 Note 1 0.40% 0.40% LTPD 10%	3.2 3.2 3.2 3.5.1 3.2 3.2	Visual Pull Tester (Note 2) Certification MIL-STD-202, Method 208 MIL-STD-750, Method 3041, Cond. B MIL-STD-750, Method 2072, Para 3.2 only
Minor 2 0 1	Poor workmanship		0.65%	3.20	Visual

NOTES: (1) Reject for three (3) OK more defects. (2) Pull all wire. (3) Sampling per MIL-M-38510, Appendix B.

AMSMC   Form 1570, 1 Feb 85   Replax   DRSMC-QA (D) Form 160, 1 Aug 83, which may no   used.

QUALITY **CONFORMANCE INSPECTION**

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

PARAGRAPH 4.4.2.74	TITLE Transistor, PNP (JAN2N2907A)		SHEET	1 OF 1	DRAWING NUMBER MIL-S-19500/291
					NEXT HIGHER ASSEMBLY 9333590
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	**None** defined				
Major					
101	Wire material incorrect	32	Note 1	3.2	Visual
102	Wire bond	32	Note 1	3.2	Pull Tester (Note 2)
103	MIL-S-19500/291 compliance			3.2	Certification
104	Solderability (3 leads)		0.40%	3.5.1	MIL-STD-202, Method 208
105	Leakage current ice		0.40%	3.2	MIL-STD-750, Method 3041, Cond. B
106	Internal visual	Note	LTPD 10%	3.2	MIL-STD-750, Method 2072, Para 3.2 only
Minor					
2 0 1	Poor workmanship		0. 65%	3.20	Visual

NOTES: (1) Reject for three (3) **or more defects.** **(2) Pull all wire.** **(3) Sampling per** MIL-M-38510 **, Appendix B.**

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AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) Form 160, 1 **Aug 83**, which **may not** be used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS MIL-C-64025(AR)

PARAGRAPH 4.4.2.75	TITLE Transistor, NPN (JAN2N2369A)		SHEET 1 OF 1		DRAWING NUMBER MIL-S-19500/317
					NEXT HIGHER ASSEMBLY 9333746
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major 101	Wire material incorrect	32	Note 1	3.2	Visual
102	Wire bond	32	Note 1	3.2	Pull Tester (Note 2)
103	MIL-S-19500/317 compliance			3.2	Certification
104	Solderability (3 leads)		0.40%	3.5.1	MIL-STD-202, Method 208
105	Leakage current ice		0.40%	3.2	MIL-STD-750, Method 3041, Cond. B
106	Internal visual	Note 3	LTPD 10%	3.2	MIL-STD-750, Method 2072, Para 3.2 only
Minor 2 0 1	Poor workmanship		0. 65%	3.20	Visual

NOTES: (1) Reject or three (3) or more defects. (2) Pull all wire. (3) Sampling per MIL-M-38510, Appendix B.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH 4.4.2.76	TITLE Transistor, PNP (JAN2N3740), Silicon, Power Type		1 SHEET	1 OF	DRAWING NUMBER MIL-S-19500/441
					NEXT HIGHER ASSEMBLY 9333590
CATEGORY	EXAMINATION OR TEST	No. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major					
101	Wire material incorrect	32	Note 1	3.2	Visual
102	Wire bond	32	Note 1	3.2	Pull Tester (Note 2)
103	MIL-S-19500/441 compliance			3.2	Certification
104	Solderability (3 leads)		0.40%	3.5.1	MIL-STD-202, Method 208
105	Leakage current ice		0.40%	3.2	MIL-STD-750, Method 3041, Cond. B
106	Internal visual	Note 3	LTPD 10%	3.2	MIL-STD-750, Method 2072, Para 3.2 only
Minor					
201	Poor workmanship		0.65%	3.20	Visual

NOTES: (1) Reject for three (3) or more defects. (2) Pull all wire. (3) Sampling per MIL-M-38510, Appendix B.

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AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH 4.4.2.77	TITLE Diode, Silicon, Switching Type (JAN1N4148)		SHEET 1 OF 1	DRAWING NUMBER MIL-S19500/116
				NEXT HIGHER ASSEMBLY 9333585/9333580
CATEGORY	EXAMINATION OR TEST	MO. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH
				PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	**None defined**				
Major 101	**Forward voltage drop**		0.40%	3.2	**MIL-STD-750, Method 4011**
102	**Reverse leakage current**		0.40%	3.2	**MIL-STD-750, Method 4016**
103	**MIL-S-19500\l16 compliance**			3.2	**Certification**
104	**Solderability (all leads)**		o. 40%	3.5.1	**MIL-STD-202, Method 208**
105	**JAN marking missing**			3.2	**Visual**
Minor 2 0 1	**Poor workmanship**		0. 65%	3.20	**Visual**

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NOTES:

AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF **DEFECTS & TESTS**

MIL-C-64025(AR)

PARAGRAPH 4.4.2.78	TITLE Diode, Silicon, Switching Type (JAN1N5712)		SHEET 1 OF 1		DRAWING NUMBER MIL-S19500/445

NEXT HIGHER ASSEMBLY
9333746/9333560

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	● ARAGRAPH REFERENCE /INSPECTION METHOD
Critical	**None defined**				
Major 101	**Forward voltage drop**		0.40%	3.2	**MIL-STD-750,** **Method** 4011
102	Reverse leakage current		0.40%	3.2	**MIL-STD-750 ,** Method 4016
103	MIL-S-19500/445 compliance			3.2	Certification
104	Solderability (all leads)		0.40%	3.5.1	MIL-STD-202 , Method 208
105	JAN marking **missing**			3.2	Visual
Minor 2 0 1	Poor **workmanship**		0.65%	3.20	**Visual**

NOTES:

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

PARAGRAPH 4.4.2.79	TITLE Diode, Silicon, Switching Type (JAN1N5712)		SHEET	1 OF 1		DRAWING NUMBER MIL-S-19500/445
						NEXT HIGHER ASSEMBLY 9333590
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL 100%		REQUIREMENT PARAGRAPH	● ARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined					
Major 101	Forward voltage drop		0.40% "		3.2	MIL-STD-750, Method 4011
102	Reverse leakage current		0.40%		3.2	MIL-STD-750, Method 4016
103	MIL-S-19500/356 compliance				3.2.	Certification
104	Solderability (all leads)		0.40%		3.5.1	MIL-STD-202, Method 208
105	JAN marking missing				3.2	Visual
Minor 201	Poor workmanship		0. 65%		3.20	Visual

NOTES:

AM Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) Form 160. 1 Aug 83. which *may* not used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

PARAGRAPH 4.4.2.80	TITLE Diode, Silicon, Power Rectifier Type (JAN1N5614)	SHEET 1 OF 1		DRAWING NUMBER MIL-S-19500/427
				NEXT HIGHER ASSEMBLY 9332962

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major 101	Forward voltage drop		0.40%	3.2	MIL-STD-750 , Method 4011
102	Reverse leakage current		0.40%	3.2	MIL-STD-750 , Method 4016
103	MIL-S-19500/427 compliance			3.2	Certification
104	Solderability (all leads)		0.40%	3.5.1	MIL-STD-202, Method 208
105	JAN marking missing			3.2	Visual
Minor 201	Poor workmanship		0. 65%	3.20	Visual

NOTES:

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QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH 4.4.2.81	TITLE. Diode, Silicon, Low Voltage Regulator (JAN1N5523B)		SHEET I OF 1		DRAWING NUMBER MIL-S-19500/437
					NEXT HIGHER ASSEMBLY 9332962
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	● ARAGRAPH REFERENCE /INSPECTION METHOD
Critical	None defined				
Major 101	Forward voltage drop		0.40%	3.2	MIL-STD-750, Method 4011
102	Reverse leakage current		0.40%	3.2	MIL-STD-750 , Method 4016
103	MIL-S-19500/437 compliance			3.2	Certification
"104	Solderability (all leads)		o. 40%	3.5.1	MIL-STD-202, Method 208
105	JAN marking missing			3.2	Visual
Minor 2 0 1	Poor workmanship		0.65%	3.20	Visual

NOTES:

AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) Form 160, 1 **Aug 83, which may not be** used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

PARAGRAPH	m u			DRAWING NUMBER
4.4.2.82	Semiconductor Device, Diode (JANlN5711)	SHEET I OF 1		MIL-S-19500/444
				NEXT HIGHER ASSEMBLY
				9333580

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
Critical	**None** defined				
Major					
101	Forward voltage drop		o. 40%	3.2	MIL-STD-750 , Method 4011
102	Reverse leakage current		0.40%	3.2	MIL-STD-750 , Method 4016
103	MIL-S-19500/444 compliance			3.2	Certification
104	Solderability (all leads)		0.40%	3.5.1	MIL-STD-202, Method 208
105	**JAN marking missing**			**3.2**	**Visual**
Minor					
201	**Poor workmanship**		0.65%	**3.20**	**Visual**

NOTES:

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QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

PARAGRAPH 4.4.2.83	TITLE Capacitor, Fixed, Ceramic, Style CKR06	SHEET I OF 1	DRAWING NUMBER MIL-C-39014/2
			NEXT HIGHER ASSEMBLY 9333590

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	Ace; 100%	REQUIREMENTS PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
	Part Number Part Value (UF)				
	M39014-02-1407 1.0				
	M39014-02-1218 .01 + lo%, 200V				
Critical	None defined				
Major					
101	Capacitance incorrect		0.40%	3.2	MIL-STD-202, Method 305
102	Leakage current		0.40%	3.2	MIL-STD-202, Method 302
103	MIL-C-39014\2 compliance			3.2	Certification
104	Solderability (all leads)		0.40%	3.5.1	MIL-STD-202, Method 208
105	Dissipation factor			3.2	MIL-STD-202 , Method 306
Minor					
2 0 1	Identification and marking incorrect		0. 65%	3.2	Visual
202	Poor workmanship		0.65%	3.20	Visual

NOTES:

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AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH	TITLE		SHEET	I OF 1	DRAWING NUMBER
4.4.2.84	Capacitor, Fixed, Ceramic, Style CKR06				MIL-C-39014/22
					NEXT HIGHER ASSEMBLY 9333560/9333746 9 96

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
	Part Number Part Value (UF)				
	M39014-22-111 .001 + 10%, 100V				
	M39014-22-195 .1				
	M39014-22-177 .01, 100V				
Critical	None defined				
Major					
101	Capacitance incorrect		0.40%	3.2	MIL-STD-202, Method 305
102	Leakage current		0.40%	3.2	MIL-STD-202 , Method 302
103	MIL-C-39014/22 compliance			3.2	Certification
104	Solderability (all leads)		0.40%	3.5.1	MIL-STD-202, Method 208
105	Dissipation factor			3.2	MIL-STD-202, Method 306
Mines					
2 0 1	Identification and marking incorrect		0.65%	3.2	Visual
202	Poor workmanship		0.65%	3.20	Visual

NOTES:

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QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

PARAGRAPH 4.4.2.85	TITLE Capacitor, Fixed, Ceramic, Style CKR05		SHEET OF 1 1 1		DRAWING NUMBER MIL-C-39014/1
					NEXT HIGHER ASSEMBLY 9333590/9333585 9333580/9333595
CATEGORY	EXAMINATION OR TEST	NO. OF *SAMPLE* UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
	Part Number Part Value (U F) M39014-01-1228 330 PF, 200V M39014-01-1473 .1 + 10%, 50V M39014-01-1219 100 PF M39014-01-1222 150 PF M39014-01-1237 .001				
Critical	None defined				
Major 101	Capacitance incorrect		0.40%	3.2	MIL-STD-202, Method 305
102	Leakage current		0.40%	3.2	MIL-STD-202, Method 302
103	MIL-C-39014/1 compliance			3.2	Certification
104	Solderability (all leads)		0.40%	3.5.1	MIL-STD-202, Method 208
105	Dissipation factor			3.2	MIL-STD-202, Method 306
Minor 2 0 1	Identification and marking incorrect		0. 65%	3.2	Visual
202	Poor workmanship		0.65%	3.20	Visual

NOTES:

AMSMC Form 1570, 1 Feb 85

Replaces DRSMC-QA (d) Form 160, 1 Aug 83, which may not be used.

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QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR),

● *AnAGuA?* TITLE				DRAWING NUMBER
4.4.2.86	Capacitor, **Chip**	SHEET	1 OF 1	MIL-C-55681/5
				NEXT HIGHER ASSEMBLY
				9333590

CATEGORY	EXAMINATION on TEST	NO. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
	Part Number Part Value (UF)				
	CDR21BP362AJTM 3600 PF				
	CDR21BP512AJTM 5100 PF				
	CDR21BG121DJTM 120 PF				
	CDR21BG361CJTM 360 PF, 200 V				
	CDR21BG681AJTM 680 PF				
	CDR21BP152AJTM 1500 PF				
	CDR21BP511BJTM 510 PF, 100V				
Critical	None defined				
Major					
101	Capacitance incorrect		0.40%	3.2	MIL-STD-202, Method 305
102	Leakage current		0.40%	3.2	MIL-STD-202 , Method 302
103	MIL-C-55681/5 compliance			3.2	Certification
104	Solderability (all leads)		0. 40%	3.5.1	MIL-STD-202, Method 208
105	Dissipation factor			3.2	MIL-STD-202, Method 306
Minor					
2 0 1	Identification and marking incorrect		0.65%	3.2	Visual
202	Poor workmanship		0.65%	3.20	Visual

NOTES:

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AMSMC **Form 1570, 1 Feb 85**   **Replaces** DRSMC-QA (D) Form 160, 1 **Aug 83, which** *may* not be **used.**

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-6402~ (AR)

PARAGRAPH 4.4.2.87	TITLE Capacitor, **Fixed, MICA, Dielectric**	SHEET	1 OF 1	DRAWING **NUMBER** MIL-C-39001/5
				NEXT HIGHER ASSEMBLY 9333585

CATEGORY	EXAMINATION OR TEST	Ho. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
	Part Number Part Value (UF)				
	CMR05F361JODM 360 PF				
	CMR05F181JODM 180 PF				
	CMRO5F91OJODM 91 PF				
	CMR05E820FPDM 82 PF + 1%, 500V				
Critical	None defined				
Major 101	Capacitance incorrect		0.40%	3.2	MIL-STD-202, Method 305
102	Leakage current		0:40%	3.2	MIL-STD-202, Method 302
103	MIL-C-39001\5 compliance			3.2	Certification
104	Solderability (all leads)		0.40%	3.5.1	MIL-STD-202, Method 208
105	Dissipation factor			3.2	MIL-STD-202, Method 306
Minor 2 0 1	Identification and marking incorrect		0. 65%	3.2	Visual
202	Poor workmanship		0.65%	3.20	Visual

NOTES:

AMSMC Form 1570, 1 **Feb 85**

Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH	TITLE			DRAWING NUMBER
4.4.2.88	Capacitor, Fixed, Electrolytic	SHEET	1 OF 1	MIL-C-39003/1
				NEXT HIGHER ASSEMBLY 9333560/9333040 9333746/9333590

CATEGORY	EXAMINATION OR TEST	No. OF SAMPLE LIMITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
	<u>Part Number</u> <u>Part Value (UF)</u>				
	M39003-01-2257 33 + 10%, 10V				
	M39003-01-2274				
	M39003-01-2254 4.7 + 10%, 10V				
	M39003-01-2261 100 + 10%, 10V				
	M39003-01-2356 1.0 + 10%				
Critical	None defined				
Major					
	Capacitance incorrect		0.40%	3.2	MIL-STD-202, Method 305
102	Leakage current		0.40%	3.2	MIL-STD-202 , Method 302
103	**MIL-C-39003/I** compliance			3.2	Certification
104	Solderability (all leads)		0.40%	3.5.1	MIL-STD-202, Method 208
105	Dissipation factor			3.2	MIL-STD-202, Method 306
Minor					
2 0 1	Identification and marking incorrect		0.65%	3.2	Visual
202	Poor workmanship		0.65%	3.20	Visual

NOTES:

AMSMC **Form** 1570. 1 **Feb 85**   Replaces DRSMC-QA (D) Form 160, 1 **Aug** 83, which may not be used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

PARAGRAPH 4.4.2.89	TITLE Capacitor, Fixed, Electrolytic		SHEET 1 OF 1		DRAWING NUMBER MIL-C-39006/9
					NEXT HIGHER ASSEMBLY 9333590
CATEGORY	EXAMINATION OR TEST	NO, OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
	P t N b Part Value (UF) M39006-09-8481 270 UF, 15V				
Critical	None defined				
Major 101	Capacitance incorrect		0.40%	3.2	MIL-STD-202, Method 305
102	Leakage current		0.40%	3.2	MIL-STD-202 , Method 302
103	MIL-C-39006/9 compliance			3.2	Certification
104	Solderability (all leads)		0.40%	3.5.1	MIL-STD-202, Method 208
105	Dissipation factor			3.2	MIL-STD-202, Method 306
Minor 2 0 1	Identification and marking incorrect		0. 65%	3.2	Visual
202	Poor workmanship		0.65%	3.20	Visual

NOTES:

AMSA Form 1570. 1 Feb 85   Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

PARAGRAPH 4.4.2.90	TITLE Capacitor, **Variable, Ceramic, Styles CV35, CV36**		SHEET 1 OF 1		DDRAWING NUMBER MIL-c-81/6
					NEXT HIGHER ASSEMBLY 9333595
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
	Part Number **Part Value** CV35G400 **7 - 40 PF**				
Critical	**None** defined				
Major 101	Capacitance range incorrect		0.40%	3.2	MIL-STD-202, Method 302
102	Height of thread stud and body incorrect		o. 40%	3.2	Gage
103	MIL-C-81\6 compliance			3.2	Certification
104	Solderability (all leads)		0.40%	3.5.1	MIL-STD-202, Method 208
Minor **2 0 1**	**Identification and marking incorrect**		0. 65%	3.2	Visual
202	Poor workmanship		0.65%	3.20	Visual

NOTES:

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AMSMC Form 1570, 1 Feb 85

Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS .

MIL-C-64025(AR)

PARAGRAPH 4.4.2.91	TITLE Resistor, Fixed, Composition, Styles RCR20	SHEET 1 OF 1	DDRAWING NUMBER MIL-R-39008/2
			NEXT HIGHER ASSEMBLY 9333590

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL 100%	REQUIREMEMT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
	Part Number **Part Value**				
	RCR20G2R7JS 2 - 7, . 5W				
	RCR20G121JS 121, 2W				
Critical	None defined				
Major					
101	Resistance incorrect		0.40%	3.2	MIL-R-39008\1
102	Solderability (all leads)		0.40%	3.5.1	MIL-STD-202, Method 208
103	Conformance to MIL-R-39008/2			3.2	Certification
Minor					
2 0 1	Identification and marking incorrect		0.65%	3.2	Visual
202	Poor workmanship		0.65%	3.20	Visual

NOTES:

AMSMC   Form 1570, 1 **Feb 85**   Replaces   **DRSMC-OA (D) Form 160. 1 Aug 83. which may not used.**

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QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH	TITLE				DRAWING NUMBER
4.4.2.92	Resistor, Fixed, Composition, Styles RCR42		SHEET 1 OF 1		MIL-R-39008/5
					NEXT HIGHER ASSEMBLY
					9333590

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
	Part Number **Part Value** RCR42G820JS 82, 2W				
Critical	**None** defined				
Major 101 **102** 103	Resistance incorrect Solderability (all leads) Conformance to MIL-R-39008\5		**0.40%** **0.40%**	3.2 3.5.1 3.2	MIL-R-39008/l MIL-STD-202, Method 208 Certification
Minor vmI- **202**	Identification and marking incorrect Poor workmanship		0. 65% 0.65%	3.2 3.20	Visual Visual

NOTES:

AMSMC Form 1570, 1 Feb 85

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

PARAGRAPH 4.4.2.93	m u Resistor, Fixed, Composition, Styles RCR32		SHEET 1 OF 1		ORAWING NUMBER MIL-R-39008/3
					NEXT HIGHER ASSEMBLY 9333590
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
	Part Number **Part Value** RCR32G151JS 150, lW RCR32G91OJS 91, IW				
Critical	None defined				
* 101 102	Resistance incorrect Solderability (all leads)		o. 40% 0.40%	3.2 3.5.1	MIL-R-39008/l MIL-STD-202, Method 208
103	Conformance to MIL-R-39008/5			3.2	Certification
Minor 201 202	Identification and marking incorrect Poor workmanship		O. 65% 0.65%	3.2 3.20	Visual Visual

NOTES:

AMSMC Form 1570, 1 Feb 85

Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which MAY not be used.

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CLASSIFICATION OF DEFECTS & TESTS

MIL-C-64025(AR)

PARAGRAPH 4.4.2.94	TITLE Resistor, Fixed, Wire Wound		SHEET	1 OF 1	DRAWING MUMBER MIL-R-39007\8
					NEXT HIGHER ASSEMBLY 9333590
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
	Part Number Part Value RWR80SR249FM .249 + 1%, 2W				
Critical	None defined				
Major 101 102	Resistance incorrect Solderability(all leads)		0.40% 0.40%	3.2 3.5.1	L-R-39008/1 MIL-STD-202, Method 208
103	Conformance to MIL-R-39007/8			3.2	Certification
Minor 2 0 1 202	Identification and marking incorrect Poor workmanship		0.65% 0.65%	3.2 3.20	Visual Visual

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NOTES:

AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

● MAGRA?U 4.4.2.95	TITLE Resistor, Fixed, Film (Insulated)		SHEET 1 OF 1		DRAWING NUMBER MIL-R-39017/1
					NEXT HIGHER ASSEMBLY 9333746/9333560
CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
	Part Number **Part Value** RLRO7C1OO3FM 100K + 1% RLR07C51ROGM 51 + 2% RLR07C1152FM 11.5K + 1% RLR07C1303FM 130K + 1% RLR07C1802GM 18K + 2% RLR07C2612FM 26.1K + 1% RLR07C6191FM 6.19K + 1%				
Critical	None defined				
Major 101 102	Resistance incorrect Solderability (all leads)		0.40% 0.40%	3.2 3.5.1	MIL-R-39008/1 MIL-STD-202, Method 208
103	Conformance to MIL-R-39017/1			3.2	Certification
Minor 201 202	Identification and marking incorrect Poor workmanship		0.65% 0.65%	3.2 3.20	Visual Visual

NOTES:

AMSMC Form 1570, 1 Feb 85   Replaes DRSMC-QA (D) Form 160, 1 Aug 83, which maY not be used.

<u>ALITY CONFORMANCE INSPECTION</u>

CLASSIFICATION OF DEFECTS ESTS

MIL-C-64025(AR)

PARAGRAPH	m u			SHEET		DRAWING NUMBER
4.4.2.96	Resistor, Fixed, Film (Insulated)			1 OF 2		MIL-R-39017/1
						NEXT HIGHER ASSEMBLY
		NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH		9333590/9333580
CATEGORY	EXAMINATION OR TEST					3 746/9333560
						PARAGRAPH REFERENCE /INSPECTION METHOD
	Part Number Part Value					
	RCR07G472JS 4.7K					
	RCR07G473JS 47K					
	RCR07G331JS 330					
	RCRO7G1O3JS 10K					
	RCR07G513JS 51K					
	RCR07G272JS 2.7K					
	RCRO7G1O2JS 1K					
	RCR07G300JS 30					
	RCR07G202JS 2K					
	RCRO7G1O1JS 100					
	RCR07G163JS 16K					
	RCR07G820JS 82					
	RCRO7G1O4JS 100K					
	RCR07G334JS 330K					
	RCR07G226JS 22M					
	RCR07G223JS 22K					
	RCRO7G1O6JS 10M					
	RCRO7G1OOJS 100					
Critics 1	None defined					

NOTES:

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AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) Form 160, 1 Aug 83, which may not be used.

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-c-64025(AR)

PARAGRAPH 4.4.2.96	m u Resistor, Fixed, Film (Insulated)		SHEET 2 OF 2		DRAWING NUMBER MIL-R-39017/1

NEXT HIGHER ASSEMBLY
9333590/9333580
9333746/9333560

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL 100%	REQUIREMEMT PARAGRAPH	● ARAGRAPH REFERENCE /INSPECTION METHOD
Major	Resistance incorrect		0.40%	3.2	MIL-R-39008/1
102	Solderability (all leads)		0.40%	3.5.1	MIL-STD-202, Method 208
103	Conformance to MIL-R-39017/1			3.2	Certification
Minor 2 0 1	Identification and marking incorrect		0. 65%	3.2	Visual
202	Poor workmanship		0.65%	3.20	Visual

NOTES:

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QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-c-64025(AR)

PARAGRAPH	TITLE		SHEET	1OF 1	DRAWING NUMBER
4.4.2.97	Resistor, Fixed, Film				MIL-R-83401\2
					NEXT HIGHER ASSEMBLY
					9332962

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
	<u>Part Number</u> <u>Part Value</u>				
	M83401-02-M4702JB 470K .1W				
Critical	None defined				
Major					
101	Resistance incorrect		0.40%	3.2	MIL-R-39008\l
102	Solderability. (all leads)		0.40%	3.5.1	MIL-STD-202, Method 208
103	Conformance to MIL-R-83401/2			3.2	Certification
104	Resistance-temperature characteristics		32-O-1	3.2	MIL-STD-202, Method 304
Minor					
2 0 1	Identification and marking incorrect		0.65%	3.2	Visual
202	Poor workmanship		0.65%	3.20	Visual

NOTES:

QUALITY CONFORMANCE INSPECTION `

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025 (AR}

PARAGRAPH 4.4.2.98	TITLE Microcircuit, Digital, CMOS		SHEET 1 OF 1		DRAWING NUMBER MIL-R-38510/173
					NEXT HIGHER ASSEMBLY
CATEGORY	EXAMINATION OR TEST	No. oF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	9332962
					PARAGRAPH REFERENCE /INSPECTION METHOD
	Part Number Part Value M38510-17305BEB				
Critical	None defined				
Major 101	Screening not performed		00 40%	3.2	MIL-STD-883, Method 5004, Class B Certification
102	Conformance to MIL-R-38510/173			3.2	Certification
Minor 2 0 1	Identification and marking incorrect		0.65%	3.2	Visual
202	Poor workmanship		0.65%	3.20	Visual

NOTES:

At   **Form 1570, 1** Feb 85   Replaces DRSMC-QA (D) Form 160, 1 Aug 83, whi ch may not   **used.**

QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF, DEFECTS & TESTS   MIL-C-64025(AR)

PARAGARAPH 4.4.2.99	m u Microcircuit, Digital, CMOS		SHEET 1 OF 1	DRAWING NUMBER MIL-R-38510/12
				NEXT HIGHER ASSEMBLY 9333595
CATEGORY	EXAMINATION OR TEST	HO. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	● ARAGRAPH REFERENCE /INSPECTION METHOD

CATEGORY	EXAMINATION OR TEST	HO. OF SAMPLE UNITS	AQL 100%	REQUIREMENT PARAGRAPH	● ARAGRAPH REFERENCE /INSPECTION METHOD
	<u>Part Number</u> <u>Part Value</u> M38510-01203BEB				
Critical	None **defined**				
Major 101	**Screening not performed**		0.40%	3.2	MIL-STD-883, Method 5004, Class B Certification
102	**Conformance to MIL-R-38510/12**			3.2	Certification
Minor 2 0 1 202	**Identification and marking incorrect** **Poor workmanship**		0.65% 0.65%	3.2 3.20	Visual Visual

NOTES:

AMSMC Form 1570, 1 Feb 85   Replaces DRSMC-QA (D) Form 160. 1 Aug 83. which mav not be USED!.

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QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS   MIL-C-64025(AR)

PARAGRAPH 4.4.2.100	TITLE Microcircuit, Digital, CMOS		SHEET 1 OF 1		DRAWING NUMBER MIL-R-38510/300
					MEXT HIGHER ASSEMBLY 9333595
CATEGORY	LAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMENT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
	Part Number Part Value M38510-30001BCB				
Critical	None defined				
Major 101	Screening not performed		o. 40%	3.2	MIL-STD-883, Method 5004, Class B Certification
102	Conformance to MIL-R-38510\300			3.2	Certification
Minor 2 0 1	Identification and marking incorrect		0. 65%	3.2	Visual
202	Poor workmanship		0.65%	3.20	Visual

NOTICE:

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QUALITY CONFORMANCE INSPECTION

CLASSIFICATION OF DEFECTS & TESTS

MIL-G-64025 (AR)

PARAGRAPH	TITLE		SHEET	1OF 1	DRAWING NUMBER
4.4.2.10:	Relay, Electromagnetic				MIL-R-39016/9
					NEXT MIGHER ASSEMBLY
					9333590/9333580

CATEGORY	EXAMINATION OR TEST	NO. OF SAMPLE UNITS	AQL OR 100%	REQUIREMEMT PARAGRAPH	PARAGRAPH REFERENCE /INSPECTION METHOD
	Part Number Part Value				
	M39016-9-022L				
Critical	None defined				
Major					
101	Screening not performed		o. 40%	3.2	MIL-STD-883, Method 5004, Class B Certification
102	Conformance to MIL-R-39016\9			3.2	Certification
Minor					
2 0 1	Identification and marking incorrect		0.65%	3.2	Visual
202	Poor workmanship		0.65%	3.20	Visual

NOTES:

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4.4.3 **Testing.** Testing is described in the first article and quality conformation inspection "Classification of Defects and Tests" form.

4.4.4 **Inspection equipment.** The inspection equipment required to perform the examination and tests prescribed herein is. described in the "paragraph/inspection method" column in the Classification of Defects and Tests forms. The contractor shall submit for approval inspection equipment designs in accordance with the terms of the contract.

4.5 **Test methods and Procedures.** Test methods used for performance testing parameters described in 4.5.2 shall be approved prior to use for product acceptance.

4.5.1 **Dimensional control of molded or Plastic Parts.** In place of the normal sampling and inspections associated with the Classification of 'Defects, and after a curing time for the parts has been approved (See Note 1), a sample of three (3) parts (as molded) from each cavity shall be fully inspected dimensionally (all dimensions on drawing) to qualify a new or reworked cavity for use in production. The molded parts shall carry the individual cavity identification. As a control of each cavity during production, the above quantity of parts from each cavity shall be inspected for at least the defects listed in [TBD (4.4.2.1 through 4.4.2.66)] after continuous production of each 5,000 parts or at the end of each week, whichever occurs first. If any defective parts are found during qualification of the cavity, the cavity producing the defective part(s) will not be used in production. If any defective parts are found when inspection is performed for the control of the cavity, the cavity producing the defective part(s) shall be removed from production. Further, that portion of production since the last control check shall be inspected for each separate type of defect according to MIL-STD-105, using an AQL of 0.40 percent for each major defect and an AQL of 0.65 percent for each minor defect. All cavities removed from production because of some fault, may, after reworking, be returned to production providing they pass the qualification test above. The contractor may request a change of inspection frequency providing he presents objective evidence to the Contracting Officer to substantiate the request. Contractor designs of gages and test equipment required to perform the inspections listed herein shall be submitted in accordance with 4.4.4 and 6.2 herein for approval prior to manufacture of equipment. The noted sub-paragraphs identify those items and minimum inspection subject to the requirements of this paragraph.

NOTE 1: In establishing a curing time, dimensionally check ten (10) parts from each cavity at periodic intervals (e.g. every 30, 60, etc. minutes) until dimensional stability is attained. The curing time will be from the time the part comes out of the mold until dimensional stability is attained. The inspection data used in determining the curing time shall be submitted in accordance with 6.3. If there is a change in material, or in the cycle time, or if a cavity is reworked, or a new cavity is used, a new curing time shall be established and approved.

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NOTE 2: Those features of a part which are subsequently machined or otherwise worked upon to meet its drawing requirements shall be inspected **in accordance with the classification of defects.**

4.5.2 **Remote Control Unit Performance tests. The following section describes the performance tests for the Remote Control Unit** (RCU), assembly number 9332873. Unless otherwise specified, all testing shall be performed at room ambient conditions. All tests in this section should be executed in the order listed. Other orders are **possible with approval from ARDEC,**

Power source setup: Set the output of a DC power supply to 0+0.lV. Turn the unit power switch off, then connect the negative terminal to P1-BLK and the positive terminal to PI-RED. Set the output voltage to 13+0.5V

4.5.2.1 <u>Power off current test</u>. Measure the current into PI-RED and verify compliance with the requirements specified in 3.6.1.

4.5.2.2 <u>Standby current test</u>. Measure the current into PI-RED and verify compliance with the requirements specified in 3.6.2.

4.5.2.3 Ke<u>yboard lights</u>. **Turn the unit power switch on. Verify** that all the keyboard keys are backlit in compliance with the requirements specified in 3.6.3.

4.5.2.4 Ini<u>tial power application test</u>. **Turn the unit power switch on. Verify that the RCU displays "INVALID" in compliance with the requirements specified in 3.6.10. If the RCU isplays "ON", iteratively disconnect it from the power supply, starting with a minimum of 4 hours and increasing the time for each iteration, until the unit passes or the minimum time exceeds 72 hours. Restart testing at this point.**

4.5.2.5 <u>STORE</u> **code** <u>select prompt</u>. **Turn the unit power switch off. Execute the following sequence: Turn the STORE code select switch on; turn the unit per switch on; then, turn the STORE code select switch off. Verify** that the RCU displays five dashes (-----), Press keys 1 thru 8 sequentially. Verify the display response as each key is pressed with the requirements of 3.6.11. Press keys 1 thru 5 sequentially and verify that the RCU displays "12345". Turn the unit power switch off.

4.5.2.6 <u>Power on prompt test</u>. Turn the unit power switch on. Verify that the RCU displays. "ON" in compliance with the requirements specified in 3.6.12.1.

4.5.2.7 **<u>Invalid store code entry test</u>. Turn the unit power switch on. Key in "12344" (an incorrect STORE code) within** the next 15 **seconds. Verify that the RCU displays "INVALID" in compliance with the requirements of 3.6.12.2. Turn the unit** power switch Off. Turn the unit power on, measure the time-lapse from the moment the unit is turned on until the RCU displays "INVALID" and verify compliance with the requirements specified in 3.6.12.2.

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4.5.2.8 <u>STORE mode entry test - no Previous SEND code</u>. Turn the unit power switch on. Key in the correct STORE code ("12345") within the next 15 seconds. Verify that the RCU displays four dashes (----) in compliance with requirements of 3-6.12.3.

4.5.2..9 <u>Display timeout test</u>. Press the AUTO key. Verify that the RCU displays "AUTO" in compliance with the requirements of 3.6.13. Measure the time-lapse-from the moment the AUTO key is pressed until the RCU display blanks and verify compliance with the requirements of 3.6.16. -Note: this requirement need not be tested further; however, this effect may be observed while executing other tests in the STORE or SEND modes and does not invalidate those tests.

4.5.2.10 <u>SEND code selection test</u>. Press the AUTO key. Verify that the RCU displays "AUTO"'. Press the TRANSFER key. Verify the display response with the requirements of 3.6.13. Note the four digit SEND code. Turn the unit power switch off.

4.5.2.11 <u>STORE mode entry test-previous send code</u>. Turn the unit power switch on. Key in "12345" within the next 15 seconds. Verify that the RCU displays the SEND code from 4.5.2.10 in compliance with the requirements of 3.6.13.1

4.5.2.12 RCD <u>code transfer test</u>. Apply Transfer Load I to the RCU as specified in Figure la. Press the COPY key. Verify that the RCU displays "CQPY" in compliance with the requirements of 3.6.14.1.1. Press the-TRANSFER key and verify that the RCU displays "SENDING" in compliance with the requirements of 3.6.14.1.2. Verify the waveform response at the load with the requirements of 3.6.14.1.3. When the waveform transmission has completed, verify that the RCU displays the four digit SEND code of 4.5.2.10 in compliance with the requirements of 3.6.14.1.4, Note the RCD code.

4.5.2.13 RCD <u>code receive test</u>. Remove Transfer Load I. Drive the RCU MCD coil as specified in Figure 3a with a known RcD code different than that of 4.5.2.12. Verify that the RCD displays "RECEIVE'" in compliance with the requirements of 3.6.14.2.1. Press the TRANSFER.key and verify that the RCU displays a four digit SEND code in compliance with the requirements of 3.6.14.2.2. Note the four digit SEND code. Turn the unit power switch off.

4.5.2.14 <u>Invalid SEND code entry test</u>. Turn the unit power switch on. Key in an incorrect SEND code within the next 15 seconds. Verify that the RCU displays "INVALID" in compliance with the requirements of 3.6.15.2. Turn the unit power switch off.

4.5.2.15 <u>SEND mode entry test</u>. Turn the unit power switch on and key in the SEND code from 4.5.2.13 within the next 15 seconds. Verify that the RCU displays "1 NONE"' in compliance with the requirements of 3.6.15.1 and 3.6.18.1.

4.5.2.16 <u>FSD transfer test</u>. Apply Transfer Load I to the RCU as specified in Figure la. Press the TRANSFER key and verify the waveform response at the load with the requirements of 3.6.19.2 and that the RCU displays "SENDING" in compliance with the requirements of 3.6.19.1. Verify that the FSD data conforms to the RCD

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code of 4.5.2.13 as specified by Drawing 9333026 for the current group. After the FSD **pulse sequence has been sent,** verify that the RCU displays "1 TRANSFER" in compliance with the requirements of 3.6.18 and 3,6.19.3.

4.5.2.17 **G r o u p selection test. For each group thru group** 15, perform the following: Press the GROUP ID key and verify that the RCU displays "n **NONE" in compliance with the requirements of 3,6.17, 3.6.18,** and 3.6.18.1, where n is the current GROUP ID number; redo 4.5.2.16 substituting the current GROUP ID number for group 1 in that test.

4.5.2.18 Invalid FSD transfer test. Press the GROUP-ID key and verify the display response of "ALL" as per requirement 3.6.17. Press the TRANSFER key and verify that the RCU displays "ALL INVALID'" in compliance with the requirements of 3.6.19.4.

4.5.2.19 RF command transmission. Connect a 50+5% ohm resistive load from the ANTENNA to the RCU case. Press the GROUP ID key and verify that the status of group 1 is displayed. Press the DEPLOY key and verify that the RCU displays "DEPLOY 1" in compliance with the requirements of 3.6.20.1. Press the XMIT switch and verify the following.

4.5,2.19.1 Tune **display. Verify that the RCU displays "TUNING" in compliance with the requirements of 3.6.20.2.**

4.5.2.19.2 Transmit display. After the tuning sequence has completed, verify that the RCU displays "XMIT TUNE = m" in compliance with the requirements of 3 .6.20,3 **and that the tune number m is an integer from 5 to** 9.

4.5.2.19.3 **R F output sequence. Verify the RF waveform data with the requirements of 3.6.20.4.**

4.5.2.19.4 Group status update. When transmission has completed, verify that **the RCU displays "1 DEPLOY" in compliance with the requirements of** 3.6.18 and 3.6.20.5. "

4.5.2.20 Command group test. Repeat 4.5.2.19 for groups 2 thru 15.

4.5.2.21 **Reset SD test. Repeat 4.5.2.19 for group "ALL" using the RESET SD command key. Verify that all 15 group status displays conform to the requirements of 3.6.18 and 3.6.18.2.**

4.5.2.22 Destruct test. Repeat 4.5.2.19 for group 1 using the DESTRUCT command key.

4.5.2.23 **Status state update test. Turn the unit power switch off. Enter the STORE mode as per 4.5.2.11. Select a new SEND code as per 4.5.2.10. Turn the unit power switch on and key in the correct SEND code within the next 15 seconds. Verify the following tests in accordance with 3.6.18.2**

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4.5.2.23.1 <u>Status setuP</u>. Press the TRANSFER key. Wait for the
**TRANSFER command to complete (a command has completed when the group
status is displayed - the RCU is then ready to receive and execute a
new command). The display should read "1 TRANSFER". Press the GROUP ID
key followed by the TRANSFER key and wait for the.TRANSFER command to
complete. The display should read "2 TRANSFER". Press the GROUP ID
key followed by the TRANSFER key again and wait for the TRANSFER
command to complete. The display should read "3 TRANSFER". Press the
GROUP ID key 14 times. Press the DEPLOY key and then the.XMIT switch.
Wait for the DEPLOY command to complete. The display should read "1
DEPLOY". Press the GROUP ID key followed by the DEPLOY key and then
the XMIT switch again. Wait for the DEPLOY command to complete. The
display should read "2 DEPLOY". Press the GROUP ID key 15 times. Press
the DESTRUCT key and then the.XMIT switch. Wait for the DESTRUCT
command to complete. The display should read "1
DESTRUCT".**

4.5.2.23.2 **RESET<u> SD state test</u>. Press the GROUP ID key 15
times. Press the RESET SD key and then the XMIT switch. Wait for the
RESET SD command to complete. Press the GROUP ID key. For groups 1
thru 15, note the group status and then press the GROUP ID key.
Verify that group 2's status now reads "2 RESET SD" and all other
groups' statuses have not changed from prior to the RESET SD command
execution.**

4.5.2.23.3 **DEPLOY <u>state test</u>. Press the DEPLOY key and then the
XMIT switch. Wait for the DEPLOY command to complete. Press the GROUP
ID key. For groups 1 thru 15, note the group status and then press
the GROUP ID key. Verify that group 3's status now reads "3 DEPLOY"
and all other groups' statuses have not changed from prior to the .
DEPLOY command execution. Press the GROUP ID key 4 times.. Press the
TRANSFER key. The display should read "4 TRANSFER".**

4.5.2.23.4 **TRA<u>NSFER status test</u>. Press the GROUP ID key and then
the TRANSFER key. Verify that the group 1's status still reads "1
DESTRUCT". Press the GROUP ID key and then the TRANSFER key. Verify
that the-group 2's status still reads "2 RESET SD". Press the GROUP ID
key and then the TRANSFER key. Verify that the group 3's status still
reads "3 DEPLOY".**

4.5.2.23.5 **D<u>ESTRUCT state test</u>. Press the GROUP ID key 13
times. Press the DESTRUCT key and then the XMIT switch. Wait for the
DESTRUCT command to complete. Press the GROUP ID key. For groups 1
thru 15, note the group status and then press the GROUP ID key. Verify
that group 2's status now reads "2 DESTRUCT", group 3's status reads
"3 DESTRUCT" and all other groups statuses-have not changed from
prior to the DESTRUCT command execution.**

4.5.2-.24 <u>Low batterv voltage test</u>. **Set the supply voltage at
Pi-RED to 11.05 + 0.05 volts and verify that the battery low indicator
is "off". Lower the supply voltage to 10.25 + 0.05 volts and verify
that the battery low indicator flashes as specified in 3.6.4. Set the
supply voltage to 13 + 0.5 volts.**

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4,5.2.25 Transmitting current test. Connect a **50** + **5%** ohm resistive load from the ANTENNA to the RCU case. press the DESTRUCT key, then press the XMIT switch.' Measure the current into Pi-RED and verify compliance with the requirements of 3.6.5.

4.5.2.26 Transmitting Power test. **With the supply set to 13 +** 0.1 volts, press the DESTRUCT key then press the **XMIT key. Measure the power into the resistive load and verify compliance with the requirements of 3.6.6.**

4.5.2.27 Tuning (load matching) capability test. With each of the complex loads of 3.6.7, perform the following: connect the load from the ANTENNA to the RCU case; press the DESTRUCT key, then press the XMIT switch; measure the power into the SO ohm real component of the load and verify compliance with the requirements of 3.6.7.

4.5.2.28 Transmitter cutoff test. Reduce the supply voltage at Pi-RED to 10.55 + 0.05 volts. Press the DESTRUCT key and then press the XMIT key. Verify transmission responses with the requirements of 3.6.8. Reduce the supply voltage to 9.45 + 0.05 volts. Press the DESTRUCT key and then press the XMIT key. Verify transmission response with the requirements of 3.6.8. Set the supply voltatge to 13 + 0.5 volts.

4.5.2.29 Data retention test. "Turn the unit power switch off. Turn the unit power switch on and key in "12345" in the next 15 seconds. Press the COPY key then press the TRANSFER key. Note the RCD code, Turn the unit power switch off. Disconnect the positive SUpPly terminal from Pi-RED. Wait 315 + 15 seconds. Reconnect the positive supply terminal to Pi-RED. Turn the unit power switch on and key in the correct STORE code in the next **15 seconds. Repeat the RCD transfer test of 4.5.2.12. Verify that the RCD code is the** same **as noted just before disconnecting the batteries. Turn the unit power switch off then on.** Key **in the correct SEND code in the next 15 seconds. Step thru each group using the GROUP ID key. Verify that each group status has retained the status just before disconnecting the battery in compliance with the requirement of 3.6.9.**

4.5.3 High temperature test. Conduct the RCU performance tests described in the paragraphs 4.5.2 - 4.5.2.29 with the unit under test temperature stabilized at 145 (+5/-0) degrees F in compliance with requirement 3.10.

4.5.4 Low temperature test. Conduct the tests listed in 4.5.3 with the unit under test temperature stabilized at -35 (+0/-5) degrees F in compliance with requirement 3.11.

4.5.5 Tuning Electronic Components Assembly Performance test. This section describes the performance tests for the Tuning Electronic Equipment Components Assembly (Tuner), assembly number 9333578. Unless otherwise specified, all testing shall be sequentially performed in the order listed at room ambient conditions. Unless otherwise specified, all test setup shall be retained throughout subsequent tests.

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Power source. Set the output of a DC power supply to 5.0 + 0.1 volts. With the power supply off connect the positive terminal to +5V INPUT (A1-E23) and connect the negative terminal to GROUND (Al-E18). Set the output of another DC power supply to 13.5+0.1 volts. With the power supply off, connect the positive terminal to VBATT (A1-E15) and connect the negative terminal to GROUND (A1-E18).

4.5.5.1 <u>Reflectometer verification tests</u>. Test setup per 3.7.1 and then turn both power supplies on. Apply an all zeros data pattern **(00000000)** to the TUNE DATA **(A1-E22), CLK (A1-E19), STROBE** BUFF **(Al-E21) and** STROBE BUFF- (A1-E20) inputs per Figure 5. Adjust **the** output of a 50 ohm RF 'signalsource to a frequency Fo (as specified in. the 9333026 drawing) and an amplitude of 5.5 + 0.2 VRMS when measured into a SO ohm load. Note: For the subparagraphs that follow, the RF source shall be turned off while changing load **resistors.**

4.5.5.1.1 <u>Reflectometer output test (50 ohms)</u>. Connect a 50 + 5% ohm **1** watt load resistor between RFOUT (A2-13) and GROUND (A1-E18), connect **the** XFER RELAY input (A1-E16) to GROUND (A1-E18) and apply the " **RF** signal of paragraph 4.5.5.1 to RFIN (between A1-14 and A1-E13). Verify the VREFL output (A1-E17) is in compliance with the requirements of 3.7.1.1.

4.5.5.1.2 <u>Reflectometer output test (75 ohms)</u>. Remove the 50 ohm load resistor between RFOUT and GROUND and replace with a 75 + 2% ohm 1 watt resistor. Verify the VREFL output is in compliance with **the** requirements of 3.7.1 .2.

4.5.5.1.3 <u>Reflectometer output, test (no load)</u>, Remove **the** 75 ohm load resistor between RFOUT and GROUND. Verify the VREFL output is in compliance with the requirements of 3.7.1.3.

4.5.5.2 <u>Inductor element test</u>. Apply data pattern A of Table 1 (para. 3.7.2.) to the TUNE DATA, CLOCK, STROBE BUFF and STROBE BUFF-inputs per Figure 5. Verify the inductance between RFIN (A1-E14) and RFOUT is in compliance with the requirements of paragraph 3.7.2, Table 1, Pattern A. Apply each of the remaining data patterns of Table 1 and verify the inductance between RFIN and RFOUT is *in* compliance with Table 1. .

4.5.5.3 <u>Capacitor elements test</u>. Apply data pattern A of Table 2 (para. 3.7.3) to the TUNE DATA, CLOCK, STROBE BUFF and STROBE BUFF-inputs per Figure 5. Verify the capacitance between RFOUT and Ground (A1-E13) is in compliance with paragraph 3.7.3, Table 2, Pattern A. Apply each of the remaining patterns of Table 2 and verify the capacitance between RFOUT and Ground is in compliance with Table 2.

4.5.5.4 <u>Power handling capability</u>. Adjust the output of a 50 ohm RF signal source to a frequency Fo and an amplitude of 24.5 + 0.5 VRMS into a 50 **ohm** load. Connect a 50 + 5% ohm 20 watt load (Table 3, Load A) between RFOUT and GROUND. Apply data pattern A of Table 3 (para. 3.7.4) to the TUNE DATA, CLOCK, STROBE BUFF and STROBE BUFF-inputs per Figure 5. Apply the previously adjusted RF source to RFIN and verify that the power output is in compliance with paragraph 3.7.4, Table 3, Load A. Connect each of the remaining loads of Table 3

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between RFOUT and GROUND and apply the appropriate data pattern for
each load, then apply the RF source to RFIN. Verify the power output
measured across the 50 ohm resistive part of the load is in compliance
with paragraph 3.7.4, Table 3.

4.5.6   Transmitter Electronic Components Assembly Performance
test. The following section describes the performance test of the
Transmitter Electronic Components Assembly, assembly number 9333579.
Unless otherwise specified, all testing shall be performed at room
ambient conditions and with a 50 + 5% ohm 20 watt load resistor
connected between A3-E4 (RF OUT) and A3-E1 (RTN).

4.5.6.1 Harmonic filter. The harmonic filter must be tested
with C7 and C9 removed from the 9333590 assembly. Apply a 50 ohm
generator sweeping between Fo and 40.0 MHz to A3-E16. Measure the
harmonics of frequency Fo at the 50 ohm termination between A3-E4 and
A3-E1 . Verify that the amplitude of the second, third and other
harmonics of frequency Fo are attenuated as specified in 3.8.1.c, The
insertion loss of the filter at Fo shall be measured by subtracting
the power (in dB) into the 50 ohm termination at A3-E4 (RFOUT) from
the power applied to the input of the filter. The insertion loss shall
be as specified in 3,8.1.a. The return loss of the filter is measured
by terminating the output of the filter with the 50 ohm resistive load
and using an RF bridge at the input of the filter to measure the
unbalance of the input impedance from a 50 ohm resistive input. The
return loss shall be as specified in 3.8.1.b.

4.5.6.2 RF Power amplifie test. Apply +13.5 + 0.1VDC to A3-E3
(vBATT), 3.6+1.6 vOlts tO A3-E9 (SEND), and 0.0+0,2 vOlts tO A4- E16
(TUNE) and A4-E20 (sTROBE IN). Verify that the RF power into the 50
ohm load resistor is in compliance with the requirements of 3.8.2.1.
While the RF amplifier is enabled, verify that the current drain into
A3-E3 (VBATT) is in compliance with the requirements of 3.8.2.2.

4.5.6.3 Tuning attenuator Pad test. APPly +13.5 + 0.1VDC to A3-
E3 (vBATT), 4.8+0.2 volts to A4-E16 (TUNE), 3.6+1.6 volts to A3-E9
(SEND), and 0.0+0.2 volts to A4-E20 (STROBE IN). Verify that the RF
power into the 50 ohm load resistor is in compliance with the
requirements of 3.8.3.

4.5.6.4 Transmitter cutoff voltage test. Apply 10.55+0.05 xDC
to A3-E3 (vBATT) , 3.6+1.6 volts to A3-E9 (SEND), and 0.0+0.2 volts to
A4-E16 (TUNE) and A4-E20 (sTrObe IN). Verify that the voltage at A4-
E22 (A.7.+5vDC) is 5.0+0.4 VOlts. Reduce the voltage at A3-E3 to
9.45+0.05 VDC and verify the voltage at A4-E22 is 0.0+0.5 volts is in
compliance with the requirements of 3.8.4.

4.5.6.5 Current limiter test. Short the drain to the source of
Q5 on the 9333590 assembly, apply +13.5+0.1 VDC to A3-E3 (VBATT),
3.6+1.6 Volts to A3-E9 (SEND), and 0.0+0.2 volts to A4-E16 (TUNE) and
A4-E20 (STROBE IN). Verify that the current drain into A3-E3 (VBATT)
is in compliance with the requirements of 3.8.5. Note, the short
applied shall be limited to 30 seconds in any two minute period when
the transmitter is enabled.

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4.5.6.6 <u>Fast turn off inhibit test.</u> Apply +13.5 + 0.1VDC to A3-E3 (vBATT), 3.6+1.6 volts to A3-E9 (SEND), and 0.0+0.1 volts to A4-E16 (TUNE) and A4-E20 (STROBE IN). Change the voltage at A4-E20 (STROBE IN) from 0.0+0.2 to 4.8+0.2 volts and verify that the power into the 50 ohm load, A4-E22 (STROBE BuFF) and A4-E21 (sTROBE BUFF-) Outputs are in compliance with the requirements of 3.8.60

4.5.6.7 <u>Send enable/disable test</u>. Apply +13.5 + 0.1VDC to A3-E3 (VBATT), 3.6+1.6 volts to A3-E9 (SEND) and 0.0+0.2 volts to A4-E16 (TUNE) and A4-E20 (STROBE IN). Verify that the voltage at A4-E23 (A.T.+5VDC) is in compliance with the requirements of 3.8.7. Change the voltage at A3-E9 (SEND) to 0.0+0.2 volts and verify that the power into the 50 ohm load and voltage at A4-E23 (A.T. +5VDC) are in compliance with the requirements of 3.8.7.

4.5.6.8 <u>Mark/space</u> <u>frequencies</u> <u>test.</u> Apply +13.5 + 0.1VDC to A3-E3 (vBATT), 3.6+1.6 volts to A3-E9 (SEND), and 0.0+0.2 volts to A4-E16 (TUNE) and A4-E20 (STROBE IN). Apply 4.8+0.2 vOlts tO A4-E5 (MESSAgE DATA INPUT), and verify that the RF output at A3-E4 is in compliance with the requirements of 3.8.8. Apply 0.0+0.2 vOlts tO A4-E5 (MESSaGE DATA INPUT) and verify that the RF output at A3-E4 is in compliance with the requirements of 3.8.8.

4..5.7 <u>Sender Electronic Component Assembly performance tests</u>. The following section describes the performance tests for the Sender Electronic Components Assembly (9333599), otherwise specified, all testing shall be performed at room ambient conditions and in the order listed. Other orders are possible with approval from ARDEC.

4.5.7.1 <u>Data input test</u>. For this section, key entry referred to in tests shall be defined as specified in section 3.9.5.

4.5.7.2 <u>Internal termination test</u>. Measure the DC resistance from A2-E52 (Col 1), A2-E53 (Col 2), A2-E54 (Col 3), A2-E55 (Col 4), and A2-E40 (SEND) to A2-E44 (+5VDC) and then measure the DC resistance from A2-E38 (S.C.S.) and A2-E39 (XMIT) to A2-E43 (GND) and verify compliance with the requirements of 3.9.20.

4.5.7.3 <u>Power source</u>. Set the output of a DC power supply to O + 0.1 volts. Connect the negative terminal to A2-E43 (GND) and the positive terminal to A2-E45 (RAMV). Set the output voltage to 13 + 0.5 volts.

4.5.7.4 <u>Loads.</u> Connect Transfer Load II of Figure lb across .A2-E35 (MCD1 and A2-E36 (MCD2).

4.5.7.5 <u>Initial input conditions</u>. The initial input conditions shall be as listed below.

INPUT TERMINAL	SIGNAL NAME	CONNECT TO
A2-E49	Row 1	Open
A2-E51	Row 2	Open
A2-E50	Row 3	Open
A2-E48	Row 4	Open
A2-E52	Col 1	Open

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A2-E53	Col 2	Open
A2-E54	Col 3	Open
A2-E55	Col 4	Open
A2-E38	S.c.s.	Open
A2-E39	XMIT	Open
A2-E42	CLEAR	0+0.2V
A2-E58	VREFL	0+0.2V

4.5.7.6 <u>Power off current test</u>. **Measure the current into A2-E45 (RAMV) and** verify Compliance with the requirements of 3.9.3.

4.5.7.7 **Memory retention voltages Measure the voltage at the cathode of CR2 of the AZ assembly and verify compliance with the requirements of 3.9.6.**

4.5.7.8 <u>Power on clear</u>. Open A2-E42 (CLEAR) then apply 13+0.5 volts to A2-E34 (+15V). Verify that **the** waveform response at A2-E29 (CLR) is in compliance with the requirements of 3.9.8.1.

4.5.7.9 <u>Initial **power** a p**plication** test</u>. **Verify that the SENDER displays "INVALID" in compliance with the requirements of 3.9.9. If** the RCU displays '-'ON", short the cathode of CR2 of the A2 assembly to A2-E43 (GND) and restart testing at this point.

4.5.7.10 <u>STORE code entry Prompt</u>. Open the supply connection to A2-E34 (+15V). Apply 0+0.2 volts to A2-E42- (CLEAR). Execute the following sequence: Apply 0+0.2 volts to A2-E38 (S.C.S.), Open A2-E42 (CLEAR), apply 13 + 0.5 volts to A2-E34 (+15v), wait at least 1 second, open A2-E38 (S.C.S.). Verify that the SENDER displays five dashes (---) in compliance with 3.9.10.1.

4.5.7.11 <u>STORE code select test</u>. Enter keys 1 thru 8 sequentially. **Verify the display response with** the requirements of **3.9.10.2. Enter keys 1 thru 5 sequentially. Verify that the SENDER displays "12345".**

4.5.7.12 <u>Keyboard timeout test</u>. Open A2-E34 (+15V). Apply 0+0.2 Volts to A2-E42 (CLEAR) for at least 1 millisecond then open. Apply 13+0.5 volts to A2-E34 (+15V). Verify that the SENDER displays "ON" in compliance with the requirements of 3.9.8.1. Measure the time-lapse from the moment power is applied to A2-E34 (+15V) until the SENDER displays "INVALID" and verify compliance with the requirements of 3.9.11 .4."

4.5.7.13 <u>Processor reset test</u>. Apply 0.0+_0.2 volts to A2-E42 (CLEAR) for at least 1 millisecond, then open. Verify that the display reads "ON" in compliance with the requirements. of 3.9.8.2. OPen the supply-connection to A2-E34 (+15v).

4.5.7.14 Invalid STORE code entry test. Apply 0+0.2 volts to A2-E42 (CLEAR) for at least 1 millisecond then open. Apply 13+0.5 volts to A2-E34 (+15V). Enter "12344" **(an incorrect STORE code) within the next 15 seconds after application of power to A2-E34** (+15V). Verify **that the SENDER displays "INVALID" in compliance with the requirements of 3.9.11.4. Open the supply connection to A2-E34 (+15V).**

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4.5.7.15 **Initial STORE mode** entry test. Apply 0+0.2 volts to A2-E42 (CLEAR) for **at least 1 millisecond then** open. Apply 13+0.5 volts to A2-E34 (+15V). Enter "12345" within the next 15 seconds. Verify-that the SENDER displays four dashes (----) in compliance with the requirements of 3.9.11.2.

4.5.7.16 Display timeout. Enter-the AUTO key. Verify that the SENDER displays "AUTO". in compliance with the requirements of 3.9.12.1. Measure the time-lapse from the moment the AUTO key is entered until the SENDER displays blanks and verify compliance with the requirements of 3.9.14.

4.5.7.17 SEND code selection. Enter the AUTO key. Verify that the SENDER displays "AUTO" in compliance with the requirements of 3.9.12.1. Enter the "TRANSFER key. Verify the display response with the requirements of 3.9.12.2. Note the four digit SEND code. Open the supply connection to A2-E34 (+15V).

4.5.7.18 STORE mode entry test. Apply 0+0.2 volts to A2-E42 (CLEAR) for at least 1 millisecond then open. Apply 13+0.5 volts to A2-E34 (+15V). Enter "12345" within the next 15 seconds. Verify that the SENDER displays the SEND code noted in 4.5.7.17 is in compliance with the requirements of 3.9.11.3.

4.5.7.19 RCD code transfer test. Enter the COPY key. Verify that the SENDER displays "COPY"' in compliance with 3.9.16.1.1. Enter the TRANSFER key and verify that the SENDER displays "SENDING" in compliance with the requirements of 3.9.16.1.2. Verify the RCD pulse sequence response at the output of Transfer Load 11 with the requirements of 3.9.16.1.3. When the RCD pulse sequence has completed, verify that the SENDER displays the four digit SEND code noted in 4.5.7.17 in compliance with the requirements of 3.9.16.1.4. Note the RCD code.

4.5.7.20 RCD code receive test. Remove Transfer Load II from the SENDER. Drive the SENDER as specified in Figure 3b with a known RCD code different than that of 4.5.7.19. Verify that the SENDER displays "RECEIVE" in compliance with the requirements of 3.9.16.2.1. Enter the.TRANSFER key and verify that the SENDER displays a four digit SEND code in compliance with the requirements of 3.9.16.2.2. Note the four digit SEND code. Open the supply connection to A2-E34 (+15V).

4.5.7.21 Invalid SEND code entry test. Apply 0+0.2 volts to A2-E42 (CLEAR) for at least 1 millisecond then open. Apply 13+0.5 volts to A2-E34 (+15V). Enter an incorrect SEND code (i.e., different than the SEND code noted in 4.5.7.20) within the next 15 seconds. Verify that the SENDER displays "INVALID" in compliance with the requirements of 3.9.13.3. Open the supply connection to A2-E34 (+15V).

4.5.7.22 SEND mode entry test. Apply 0+0.2 volts to A2-E42 (CLEAR) for at least 1 millisecond then *open.* Apply 13+0,5 volts to A2-E34 (+15V). Enter the SEND code noted in 4.5.7.14 within the next **15 seconds.** Verify that the SENDER displays "1 NONE" in compliance with the requirements of 3.9.13.2 and 3.9.17.3.

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4.5.7.23 <u>FSD transfer test</u>. **Apply Transfer Load II to the SENDER as specified in Figure 1b. Enter the TRANSFER key and verify the FSD pulse sequence with the requirements of 3.9.18.2 and that the SENDER displays "SENDING" in compliance with the requirements of 3.9.18.1. Verify-that the FSD data conforms to the** RCD code of 4.5.7.20 as specified by Drawing 9333026 for the Current group. After the FSD pulse sequence has been sent, verify that the SENDER displays "n TRANSFER", where n is the current GROUP ID, in compliance with the requirements of 3.9.18.3.

4.5.7.24 <u>Group select-ion test</u>. Enter the GRP ID key anti verify that the SENDER displays "n NONE", where n is the next GROUP ID number , in compliance with the requirements of 3.9.15.2, 3.9.15.3, 3.9.17.1, and 3.9.17.3.

4.5.7.25 <u>Group addressing test</u>. Repeat 4.5.7.23 and 4.5.7.24 for each of the remaining groups thru group 15. Verify compliance with the requirements of 3.9.15.1.

4.5.7.26 <u>Invalid FSD transfer test.</u> Enter the GRP ID key and verify the display response of "ALL" as per requirements 3.9.15-3 and 3.9.17.2. Enter the TRANSFER key and verify that the SENDER displays "ALL INVALID" in compliance with the requirements of 3.9.18.4.

4.5.7.27 <u>Voltage regulation</u>. Measure the voltage at A2-E44 (+5VDC) and verify compliance with the requirements of 3.9.1.

4.5.7.28 <u>**Command transmission**</u>. **For each entry in the following table,**

Command Test Table

g	n 2		m
2	20	4.9%	9, 8, or 7
3	38	9.4%	7
4	56	13.9%	7, 6, or 5
5	75	19.0%	5
6	93	23 .5%	5, 4, or 3
7	111	26.8%	4, 3, or 2
8	129	34.5%	2
9	147	52.5%	1
10	165	100.0%	0
11	183	100.0%	0
12	202	100.0%	0
13	220	100.0%	0
14	239	100.0%	0
15	256	100.0%	0

Note: **v is a percentage +_ 100 millivolts of the regulation** voltage measured in 4.5.7.27.

do the following sequence: Enter the GRD ID key; verify that the display reads "g TRANSFER" where g is the current GROUP ID; enter the DEPLOY key and verify that the display reads "DEPLOY g" in compliance

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with 3.9.19.1; apply 0.0+_0.2 volts momentarily to A2-E39 (XMIT) then open; apply a pulse on A2-E58 (VREFL) from 5+_0.2 **volts to v volts for 4+_1.0 microseconds beginning on the nth falling edge of A2-E62 (STROBE) during the tune sequence (see the table above for v and n). Verify the following.**

4.5.7.28.1 <u>Tune sequence</u>. **Verify that the SENDER displays "TUNING" in compliance with the requirements of 3.9.19.2. Verify that control-signals at A2-E61 (TUNE), A2-E62 (sTRoBE), A2-E40 (SEND), A2-E59 (TUNE DATA), and A2-E60 (CLOCK) are in compliance with the requirements of 3.9.19.3.**

4.5.7.28.2 Transmit <u>display</u>. **After the tuning sequence observed in 4.5.7.28.1 has completed, verify that the SENDER displays "XMIT TUNE = m" where m is the value shown in the table above, as specified by the requirements of 3.9.19.4.**

4.5.7.28.3 Command output <u>sequence</u>. **Verify the biphase data at A2-E46 (SEROUT) for the current group with the requirements of 3.9.19.5.**

4.5.7,28.4 <u>Group status update.</u> **When transmission has completed, verify that the SENDER displays "g DEPLOY" in compliance with the requirements of 3.9.17.1 and 3.9.19.6.**

4.5.7.29 <u>RESET SD test</u>. **Enter the GRP ID key. The display should read "ALL". Enter the R SET SD key and then momentarily apply 0.0+_0.2 volts to A2-E39 (XMIT) then open. Verify the biphase data at A2-E46 (SEROUT) for the current group "ALL" with the requirements of .3.9.19.5. Enter the GRP ID key. For each group 1 thru 15: confirm that the group status now reads "n RESET SD" in compliance with the requirements of 3.9.19.6, where n is the current GROUP ID; then, enter the GRP ID key.**

4.5.7.30 <u>DESTRUCT test</u>. **Enter the GRP ID key, The display should read "1 RESET SD". Enter the DESTRUCT key and then momentarily apply 0.0+_0.2 volts to A2-E39 (XMIT) then open. Verify the biphase data at A2-E46 (SEROUT) for group 1 with the requirements of 3.9.19.5. Wait for the DESTRUCT command to complete. Verify that the display reads "1 DESTRUCT" in compliance with the requirements Of 3.9.19.6.**

4.5.7.31 <u>status state up-date test.</u> **Open the supplyconnection to A2-E34 (+15V). Enter the STORE mode as per 4.5.7.18. Select a new SEND code as per 4.5.7.17. Apply 0+0.2 volts to A2-E42 (CLEAR) for at least 1 millisecond then open. Apply 13+0.5 volts to A2-E34 (+15V). Enter the newly selected SEND code from above within the next 15 seconds. Verify the following tests in accordance with 3.9.17.4**

4.5.7.31.1 <u>Status setup</u>. **Enter the TRANSFER key. Wait for the TRANSFER command to complete (a command has completed when the group status is displayed - the RCU is then ready to receive and execute a new command). The display should read "1 TRANSFER". Enter the GRp ID key followed by the TRANSFER key and wait for the.TRANSFER command to complete. The display should read "2 TRANSFER". Enter the GRP ID key**

1 4 8

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followed by the TRANSFER key again and wait for the TRANSFER command
**to complete. The display should read ".3 TRANSFER". Enter the GRP ID
key 14 times. Enter the DEPLOY key and then momentarily apply
.0.+_0.2 volts to A2-E39 (XMIT) then open. Wait for the DEPLOY command
to complete. The display should read "1 DEPLOY". Enter the GROUP ID
key followed by the DEPLOY key and then momentarily apply 0.0+_0.2
volts to A2-E39 (XMIT) then open. Wait for the DEPLOY command to
complete. The display should read** "2 DEPLOY". Enter **the** GRP ID key 15
times. Press the DESTRUCT key and then momentarily apply 0.0+_0.2
volts to A2-E39 (XMIT) then open. Wait for the DESTRUCT command to
complete. The display should read "1 DESTRUCT".

4.5.7.31.2 R<u>ESET SD state test</u>. Enter **the** GRP ID key 15 times.
Enter the R'SET **SD key and then momentarily apply 0.0+_0.2 volts to
A2-E39 (XMIT) then open. Wait for the** RESET SD Command to complete.
Enter the GRP ID key. For each group 1 thru 15: note the group status
**and then enter the GRP ID key. Verify that group 2's status now reads
"2 RESET SD" and all other group statuses have not changed from prior**
to **the** RESET SD command execution.

4.5.7 .31.3 <u>DEPLOY state test</u>. Enter the DEPLOY key and then
momentarily apply 0.0+_0.2 volts to A2-E39 (XMIT) then open* Wait for
the DEPLOY command to complete. Enter the GRP ID key. For each group 1
thru 15: note the group status and then enter the GROUP ID key.
Verify that group 3's status now reads "3 DEPLOY" and all other group
statuses have not changed from prior to the DEPLOY command executions
Enter the GRP ID key 4 times. Enter the TRANSFER key. The display
should read "4 TRANSFER".

4.5.7.31.4 T<u>RANSFER status test</u>. Enter the GRP ID **key and then
the TRANSFER key. Wait for the TRANSFER command to complete. Verify
that group 1's status still reads "1 DESTRUCT" as per 3.6.18.2. Enter
the GRP ID key and then the TRANSFER key. Wait** for the TRANSFER
command to complete. Verify that **group 2's status still reads "2
RESET SD". Enter the GRP ID key and then the TRANSFER** key. Wait" for
the TRANSFER command to complete. Verify that group 3's status still
reads "3 DEPLOY".

4.5.7.31.5 <u>DESTRUCT state test</u>. Enter the GRP ID key 13 times.
Enter **the** DESTRUCT key and then momentarily apply 0.0+_0.2 volts to
A2-E39 (XMIT) then open. Wait for the DESTRUCT command **to complete.
Enter the GRP ID key. For each group 1 thru 15: note the group status
and then enter the GRP ID key. Verify that group 2's status now reads
"2 DESTRUCT", group 3's status reads "3 DESTRUCT", and all other group
statuses have not changed from prior to the DESTRUCT command
execution.**

4.5.7.32 <u>Standby current test</u>. **Wait until the display is blank
after keyboard timeout. Measure the current into A2-E34 (+15V) and
verify compliance with the requirements of 3.9.4.**

4.5.7.33 <u>Low battery voltage test</u>. **Set the supply voltage at
A2-E34 (+15V) to 11.05+0.05 volts and verify that the battery low
indicator is "off". Lower the supply voltage to 10.25+0.05 volts** and

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verify that the battery low indicator flashes as specified in 3.9.2. Set the supply voltage to 13+0.5 volts.

4.5.7.34 Data retention test. Open the supply connection to A2-E34 (+15V). Apply 0+0.2 volts to A2-E42 (CLEAR) for at least 1 millisecond, then open. Apply 13+0.5 volts to A2-E34 (+15v) and enter "12345" in the next 15 seconds. **Enter the COPY key followed by the TRANSFER key. Note the RCD code. Open the supply connection to A2-E34 (+15V) and A2-E45 (RAMv). Wait 315+15 seconds. Apply 13+0.5 volts to A2-E45 (RAMV). Apply 1+0.2 VOlts to A2-E42 (CLEAR) for at least 1 millisecond, then open, Apply 13+0.5 volts to A2-E34 (+15V) then enter "12345" in the next 15 seconds. Enter the COPY key followed by the TRANSFER key. Verify that the RCD) code is the same as noted prior to disconnecting the supply. Open A2-E34 (+15v). Apply 0+0.2 volts to A2-E42 (CLEAR) for at least 1 millisecond, then open. Apply** 13+0.5 volts to A2-E34 (+15V) then enter the SEND code **from 4.5.7.31 within the next 15 seconds. Step thru each group status and verify that each group has retained the status prior to disconnecting the supply.**

5. PACKAGING

5.1 Preservation and packaging

5.1.1 **Level A.** **Preservation and packaging shall be in accordance with drawing 9362585.**

5.2 Packing

5.2.1 **Level A.** **Packing shall be in accordance with drawing 9362584.**

5.3 Marking

5.3.1 **Level A.** **Marking shall be in accordance with drawing 9362584 and 9362585.**

5.4 Consolidation

5.4.1 **Level A.** **Consolidation shall be in accordance with drawing 8808362.**

5.5 Unitization

5.5.1. **Level A.** **Unitization shall be in accordance with MIL-sTD-1169.**

6. NOTES

6.1 Ordering data. See MIL-A-48078.

6.2 Submission of inspection equipment designs for approval. **(See MIL-A-48078) Submit equipment designs as required to: Commander, U.S. Army Armament Research, Development and Engineering Center (ARDEC), Attn: AMSMC-QAT-I(D), Dover, N.J. 07801-5001.**

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6.3 <u>Distribution of ammunition data cards, inspection and test results</u>. Distribution of ammunition data cards, inspection and test results shall include Commander: ARDEC, Dover, N.J. 07801-5001, Attn: AMSMC-QAT-M(D) .

6.4 <u>Drawings</u>. Drawings listed in Section 2 of this specification under the heading U.S. Army Armament Research, Development and Engineering Center (ARDEC) may also include drawings prepared by and identified as, U.S. Army Armament research and Development Command (ARRADCOM), Edgewood Arsonal, Frankford Arsenal, Rock Island Arsonal, Picatinny Arsenal or Army Armament Research and Development Center drawings. Technical data originally prepared by these activities is now under the cognizance of ARDEC.

6.8 <u>Subject term (key word) listing</u>.

Attenuator
Control, Remote
Data Transfer
Radio Frequency
Reflectometer
Stress Screening
Transmitter
Tuner

Custodian: Preparing   activity:
  Army-AR   Army-AR

(project 1290-A237)

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Figure 1

RCU Transfer Loads

RCU

MCD 1 ●

*

MCD2

Ml

$2K \pm 5\%$

●   M2

Transfer Load I

(a)

SENDER

MCD 1   ● *   Ml

$2K \pm 5\%$

MCD2

●   M2
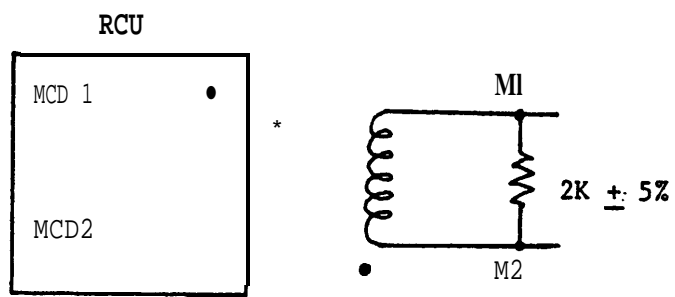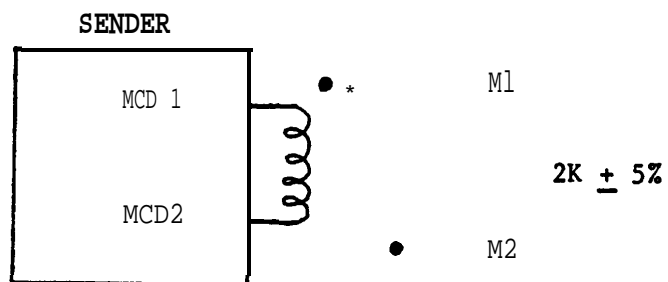
Transfer Load II

(b)

* **Notes:** All coils 9332919-2 Spaced by 0.05 ± **0.01 inch gap.**

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Figure 2

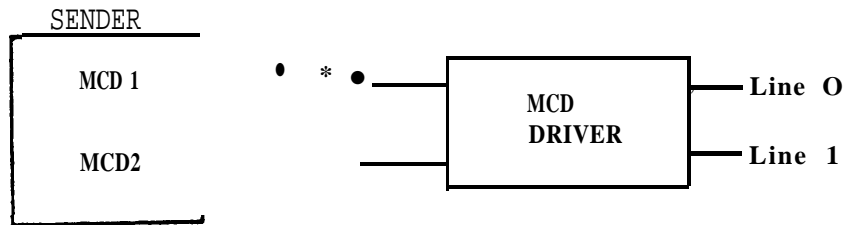### RCU to RCU and RCU to MCU data transfer timing and voltages

m   n   m   n   m   n   m

zeros | pattern | zeros | **pattern** | zeros | pattern | zeros

bit | bit | bit | bits | **bit** | **bit** | **bit** | **bit** | bits | **bit**

1 | 2 | 3 | 4 to **m-1** | m | 1 | 2 | 3 | 4 to n-1 | n

+Vo --

MCD1-MCD2

-Vo --

Tpw

Tpw

Trep

Trep

LoGiC 0

LoGiC 1
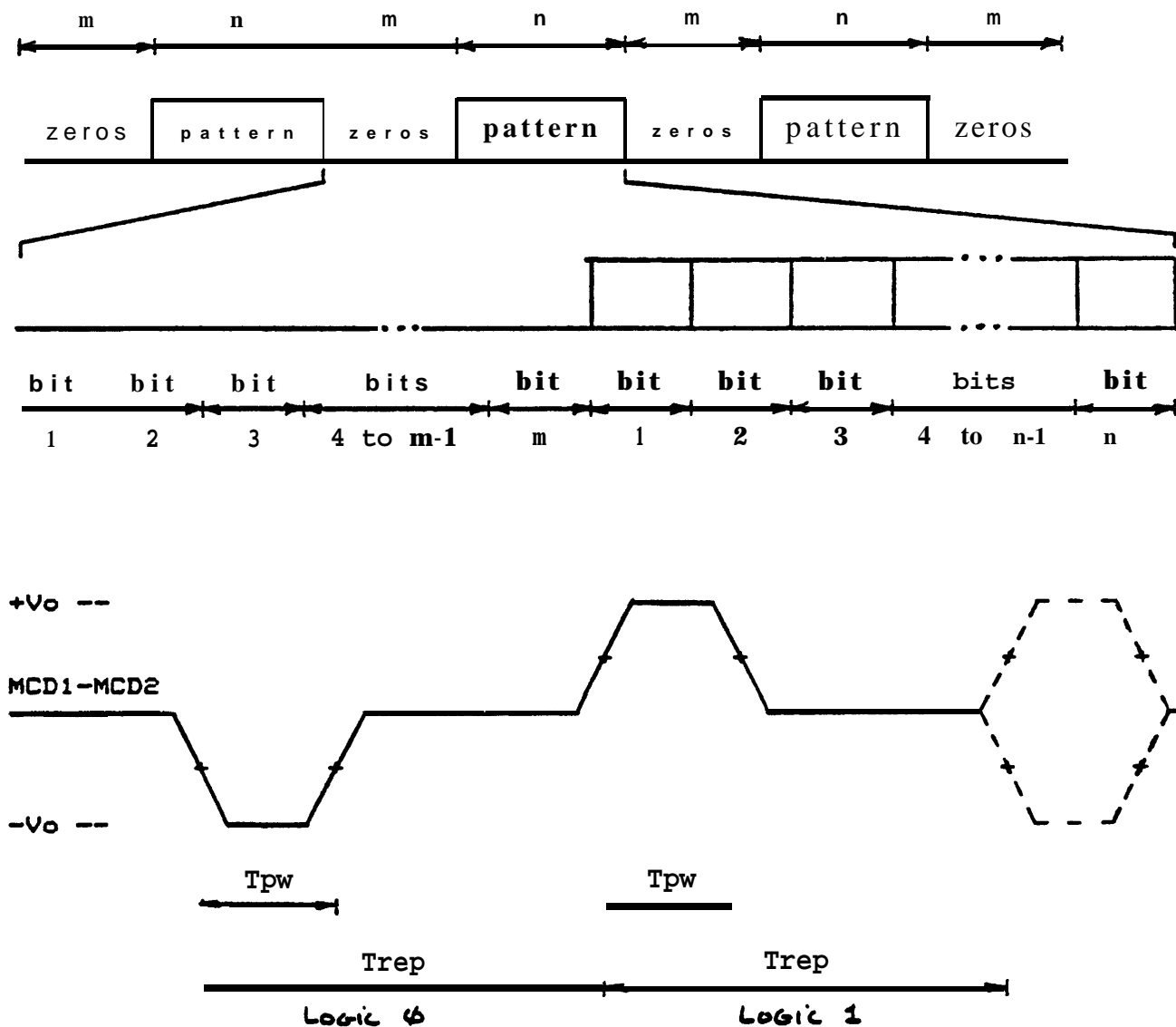
Notes:

1. Transfer coils ● eoerated by 0.05 ± 0.01 inch gap

2. Tpw = 4±0.1 micro seconds
   Trep = 1±0.1 mini seconds
   Vo - 5.0 to 10.0 volts

3. A detailed description of RCD and FSD patterns including the value of m and n is given in Drawing 9333026.

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Figure **3**

<u>Transfer Drivers</u>

RCU ,

MCI) 1   *

MCD2

MCD
DRIVER

Line O

Line 1

(a)

SENDER

MCD 1   • * •

MCD2

MCD
DRIVER

Line O

Line 1
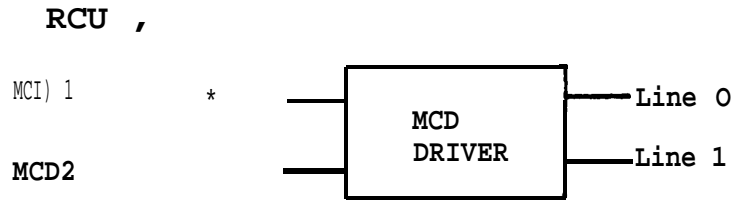
(b)

<u>Transfer Driver Performance Characteristic</u>

Line 0

Line 1

MCD
DRIVER

*   Ml

2K ± 5%

M2

Line o

Line 1

(Ml - M2)   + V_O

$-V_0$

$T_{p\ w}$ T_{pw}

^{1}**REP**

I 54
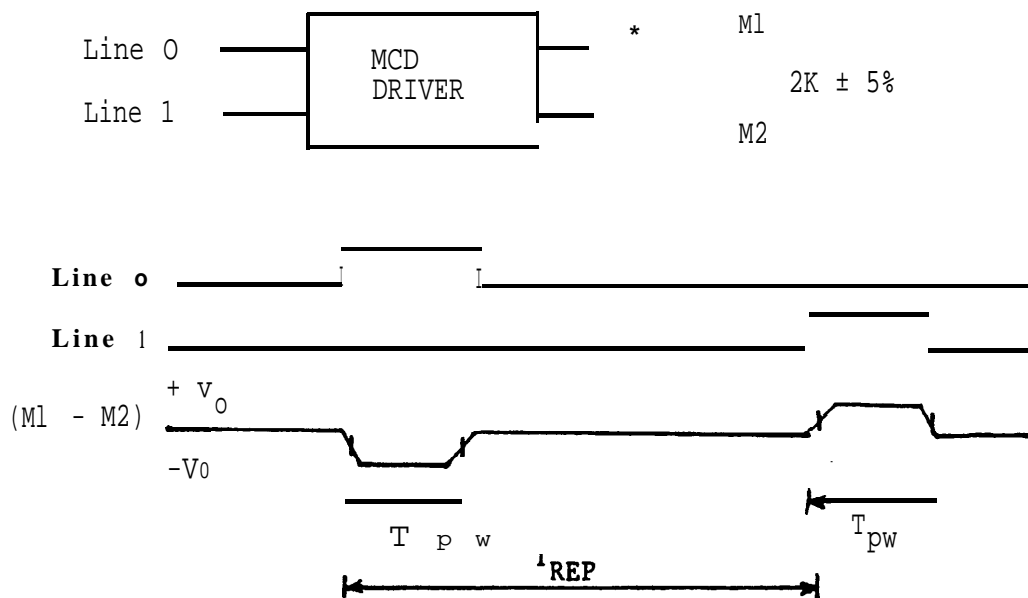
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Figure 3 (Continue)

<u>Transfer Drivers</u>

Notes: * All coils 9332919-2 spaced by 0.05 ± 0.01 inch gap.
See Figure 2 for data 12 voltage and pattern definition

FIGURE 4

GROUP STATUS UPDATE STATE DIARAM

START

NONE

TRANSFER

TRANSFER

DEPLOY

DEPLOY

RESET SD

DESTRUCT

RESET SD

DESTRUCT

DESTRUCT
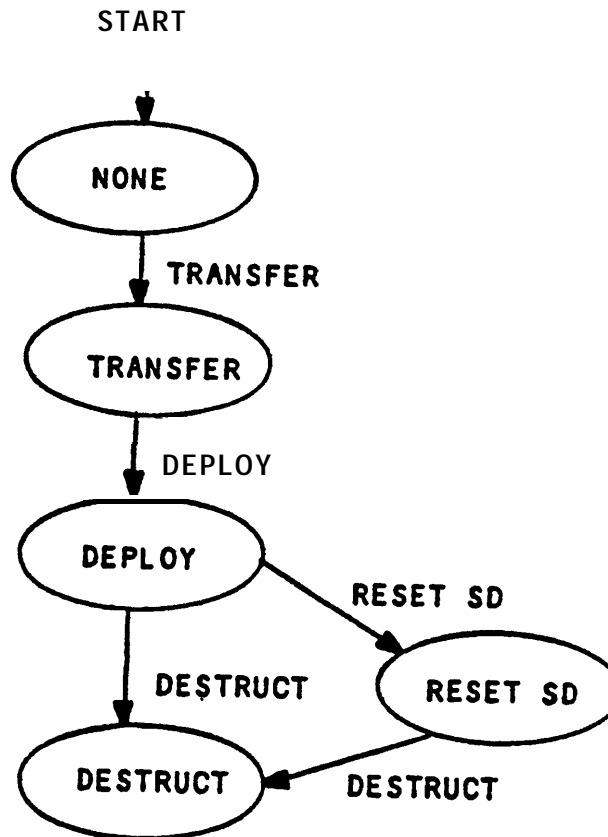
NOTES:

1. **Completed commands are represented by arcs between bubbles.**

2. **Status states are represented by bubbles.**

3. **State changes (from bubble to bubble) occur only across the arcs shown. No state change occurs for commands whose arcs are not shown as leaving a state bubble.**
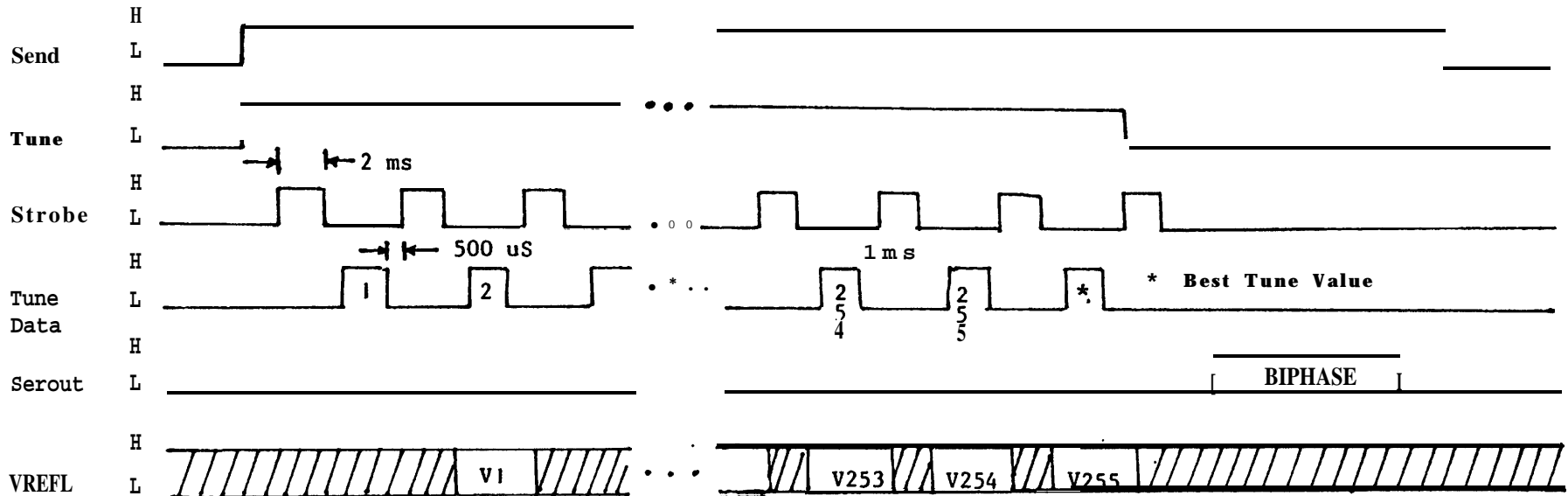
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Figure 5

| Sample data pattern | 0 | 0 | 0 | 0 | 1 | 0 | 0 | 0 |
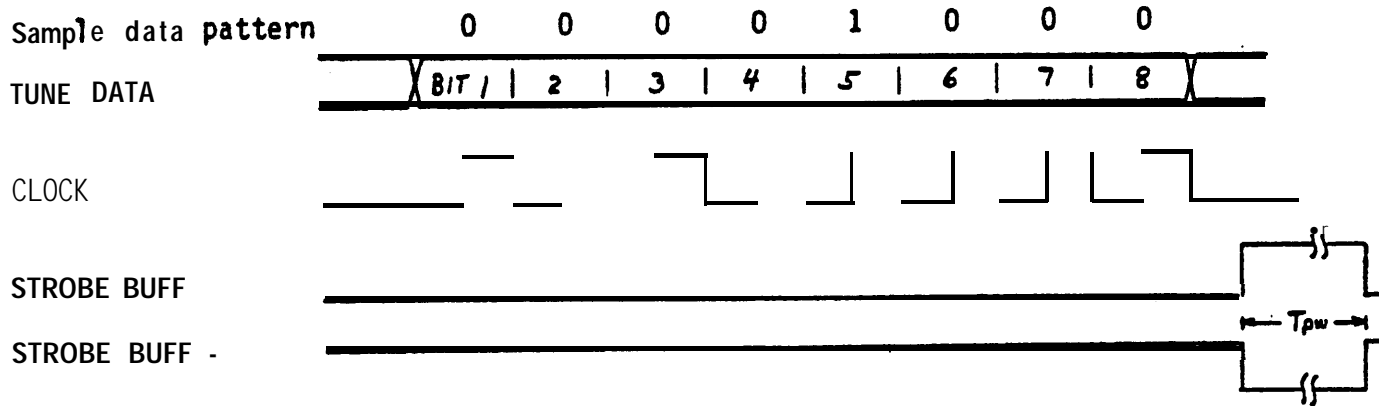
Note: 1. Signal level; High = **4.5 ± 0.5V, Low = 0.5 ± 0.5V**

2. Clock period, $T_{Per} = 8 \pm 2$ microseconds

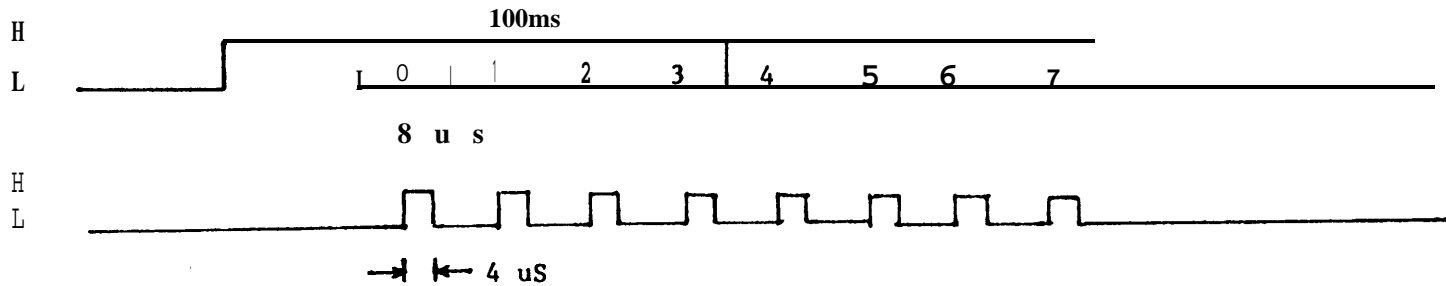**3.** Strobe pulsewidth, **T_{pw} = 1.0 milliseconds**

Figure 6

<u>Power on clear</u>
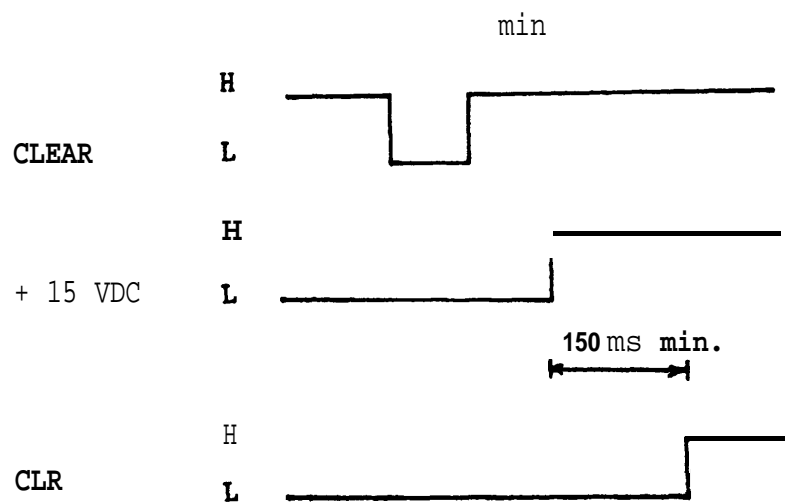
MIL-C-64025 (AR)
Tune Sequence Timing

Send

Tune
2 ms

Strobe
500 uS   1 m s

Tune Data
1   2   2 5 4   2 5 5   *.   * **Best Tune Value**

Serout   **BIPHASE**

VREFL   V I   V253   V254   V255

Tune Timing Detail

100ms

0   1   2   3   4   5   6   7

8 u s

4 uS

Notes: L = 0.0 ± 0.2 volts H = 4.8 to 5.3 volts

Figure 7

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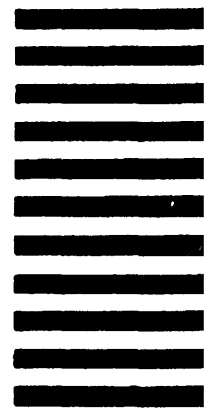
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4. TYPE OF ORGANIZATION *(Mark one)*

☐ VENDOR

☐ USER

☐ MANUFACTURER

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